

# Machine Learning and Its Applications in IC Physical Design

David Z. Pan

University of Texas at Austin

<http://users.ece.utexas.edu/~dpan/>

Yibo Lin

Peking University

<http://yibolin.com/>



**TEXAS**  
The University of Texas at Austin



# Outline

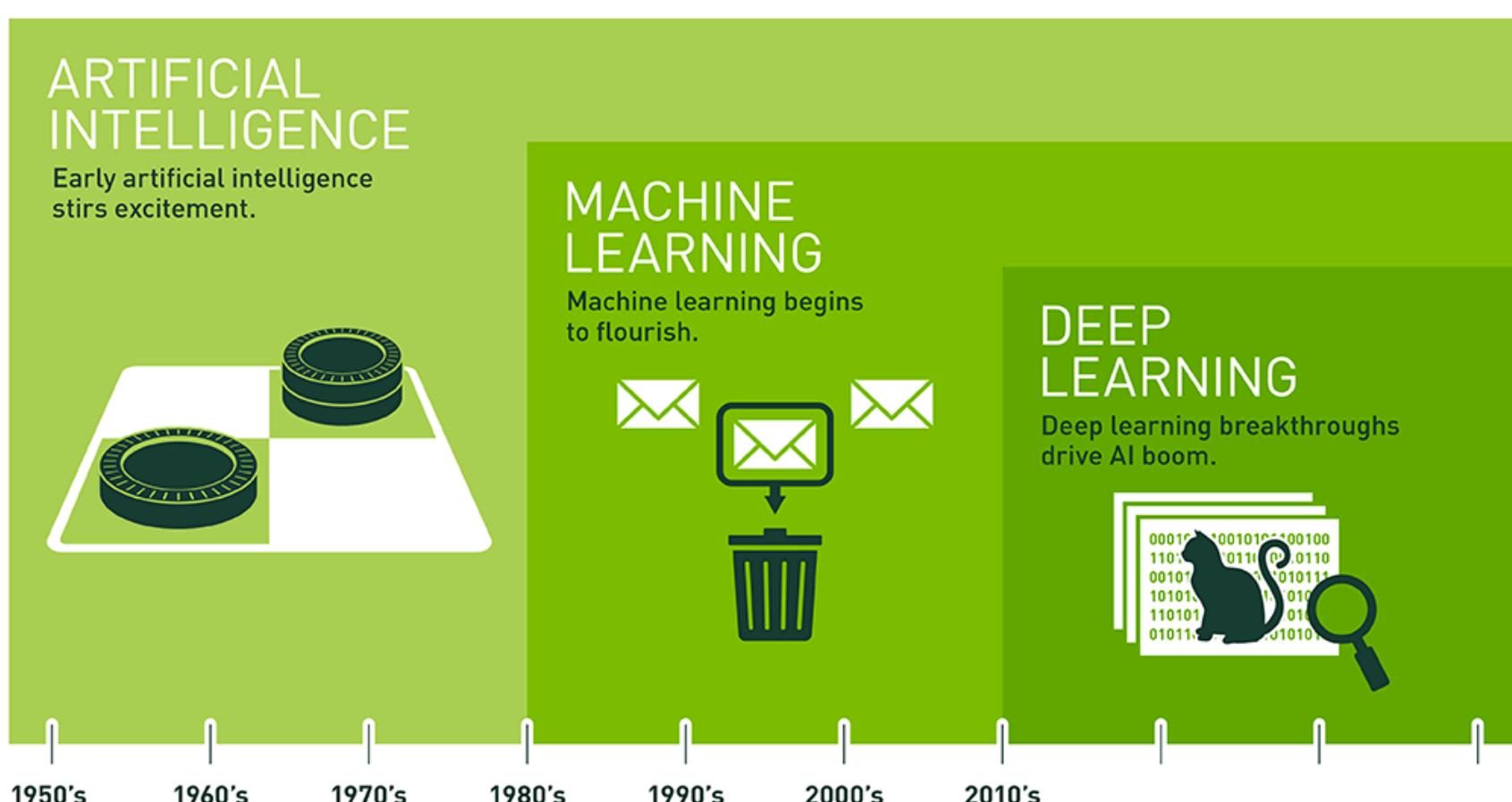
## Part I: Introduction to Machine Learning

- What is Machine Learning
- Taxonomy of Machine Learning
- Machine Learning Techniques

## Part II: Machine Learning for Physical Design

- Motivations
- Opportunities
- Challenges and Future Directions

# A Bit History



Since an early flush of optimism in the 1950s, smaller subsets of artificial intelligence – first machine learning, then deep learning, a subset of machine learning – have created ever larger disruptions.

[Courtesy Nvidia<sup>3</sup>](#)

# Enormous Opportunities for Machine Learning



# Enormous Opportunities for Machine Learning



Auto

你是什么垃圾？

AI智能识别，不惧灵魂拷问

我分享传播也是公益  
成为第 39930 个“3小时公益”参与者

玻璃杯 属于  
可回收物  
“回收后加工可再利用”

» 打开手机淘宝 扫一扫查询垃圾分类 «

搜索 你是什么垃圾

扫一扫 会员码

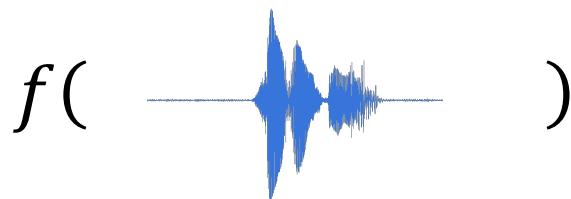
Trash Classification

This image shows a screenshot of a mobile application interface. The top half has a grid background. The main content area is a blue box containing a photograph of a clear plastic cup with a yellow handle. Below the photo, the text reads "玻璃杯 属于 可回收物 “回收后加工可再利用”". At the bottom of the blue box, there is a call-to-action: "» 打开手机淘宝 扫一扫查询垃圾分类 «". Below this, there are two orange buttons: one for "搜索 你是什么垃圾" and another for "扫一扫 会员码". The overall theme is recycling and waste classification.

Entertainment

# Machine Learning $\approx$ Looking for a Function

Speech recognition



= “*How are you*”

Image recognition



= “*Cat*”

Playing Go



= “5 – 5”  
(next move)

Dialogue system

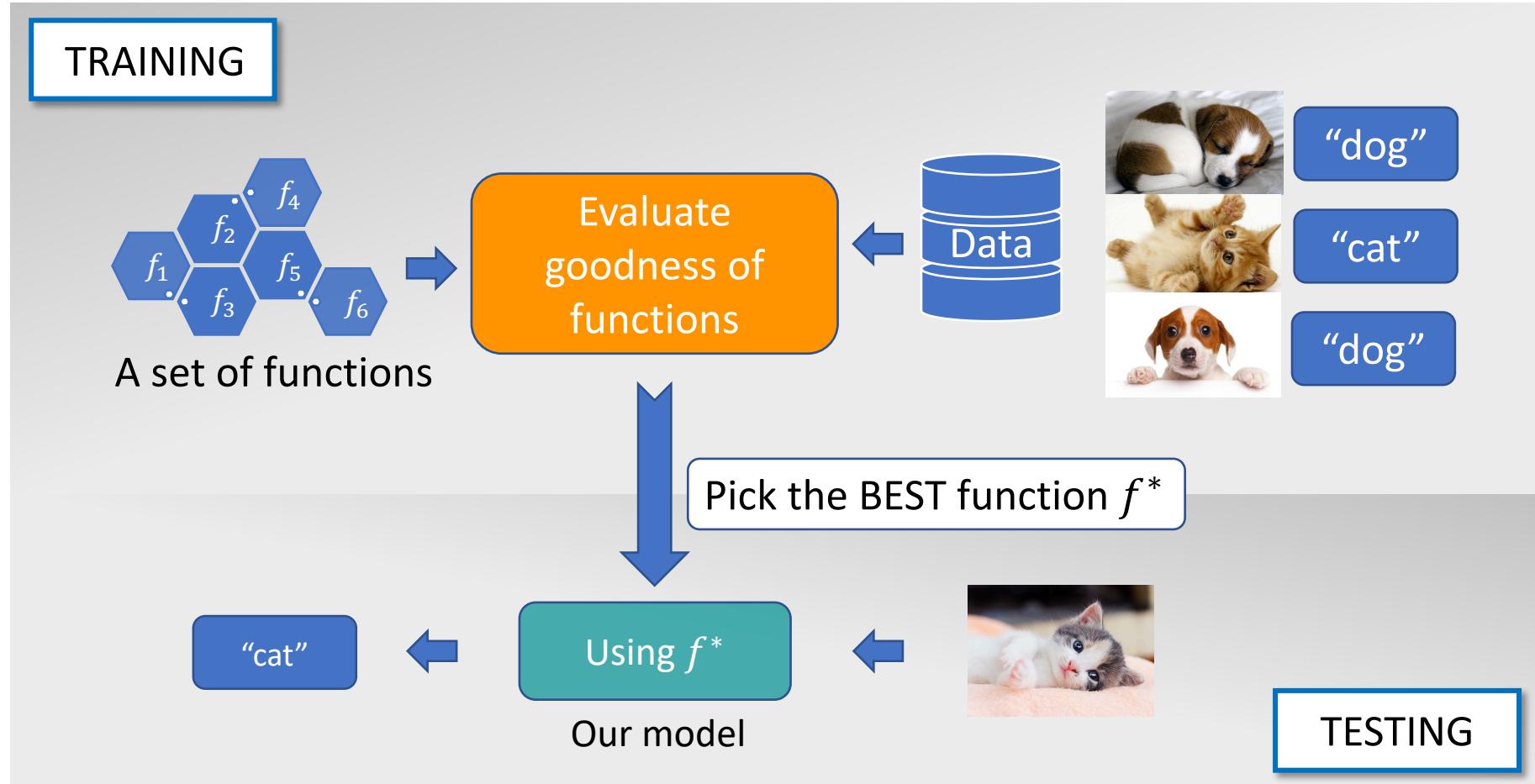


(What the user said)

= “*Hello*”

(system response)

# Machine Learning Framework



# Taxonomy of Machine Learning

Unsupervised  
Learning

Supervised  
Learning

Semi-supervised  
Learning

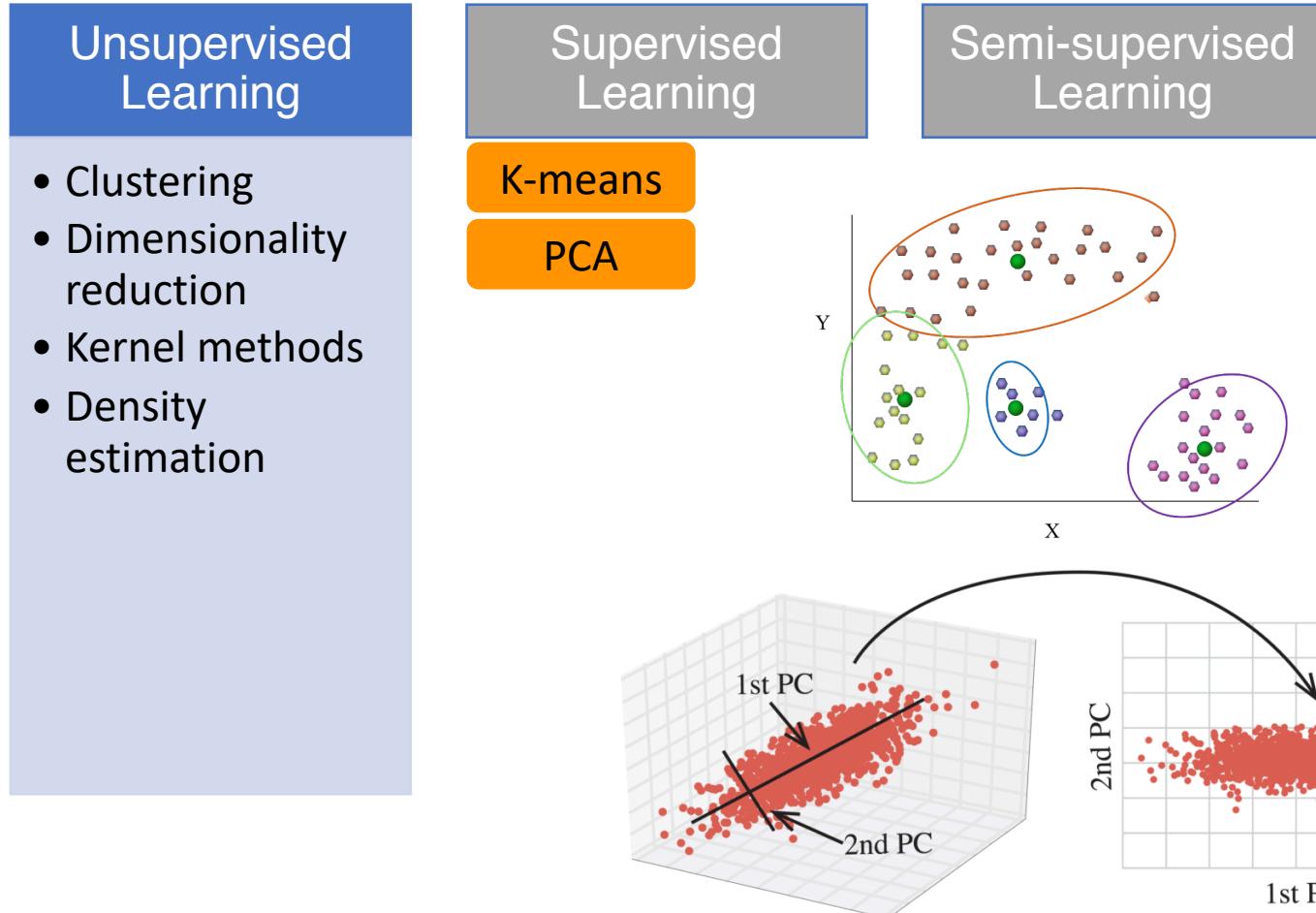
Unsupervised Learning  
*only inputs  $x$ ;  
no labels/outputs  $y$*

Supervised Learning  
*training data with inputs  $x$   
and labels/outputs  $y$*

Semi-supervised Learning  
*subsets of data have  
labels/outputs  $y$*

## Scenarios

# Taxonomy of Machine Learning



# Taxonomy of Machine Learning

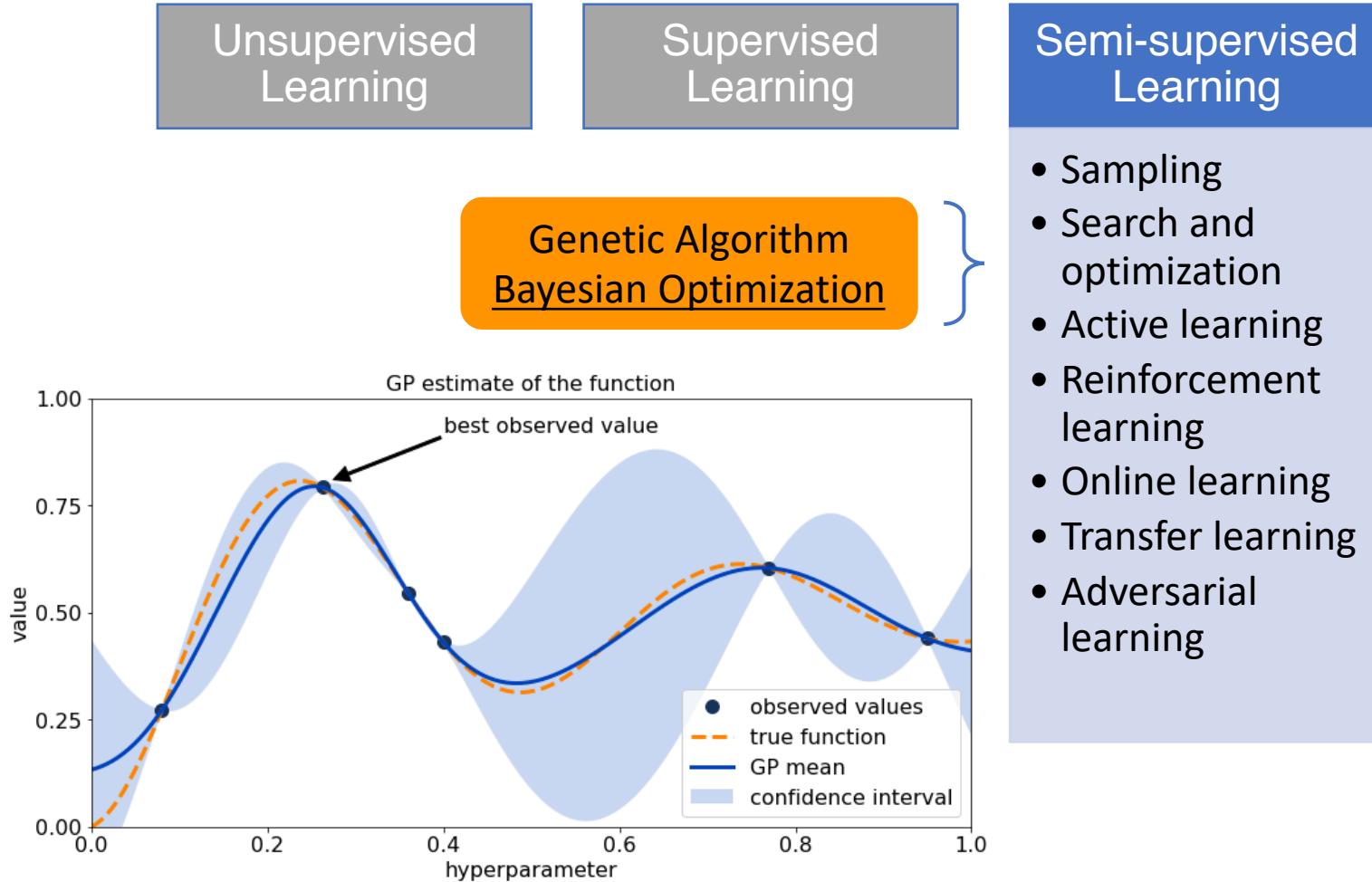
Unsupervised  
Learning

Supervised  
Learning

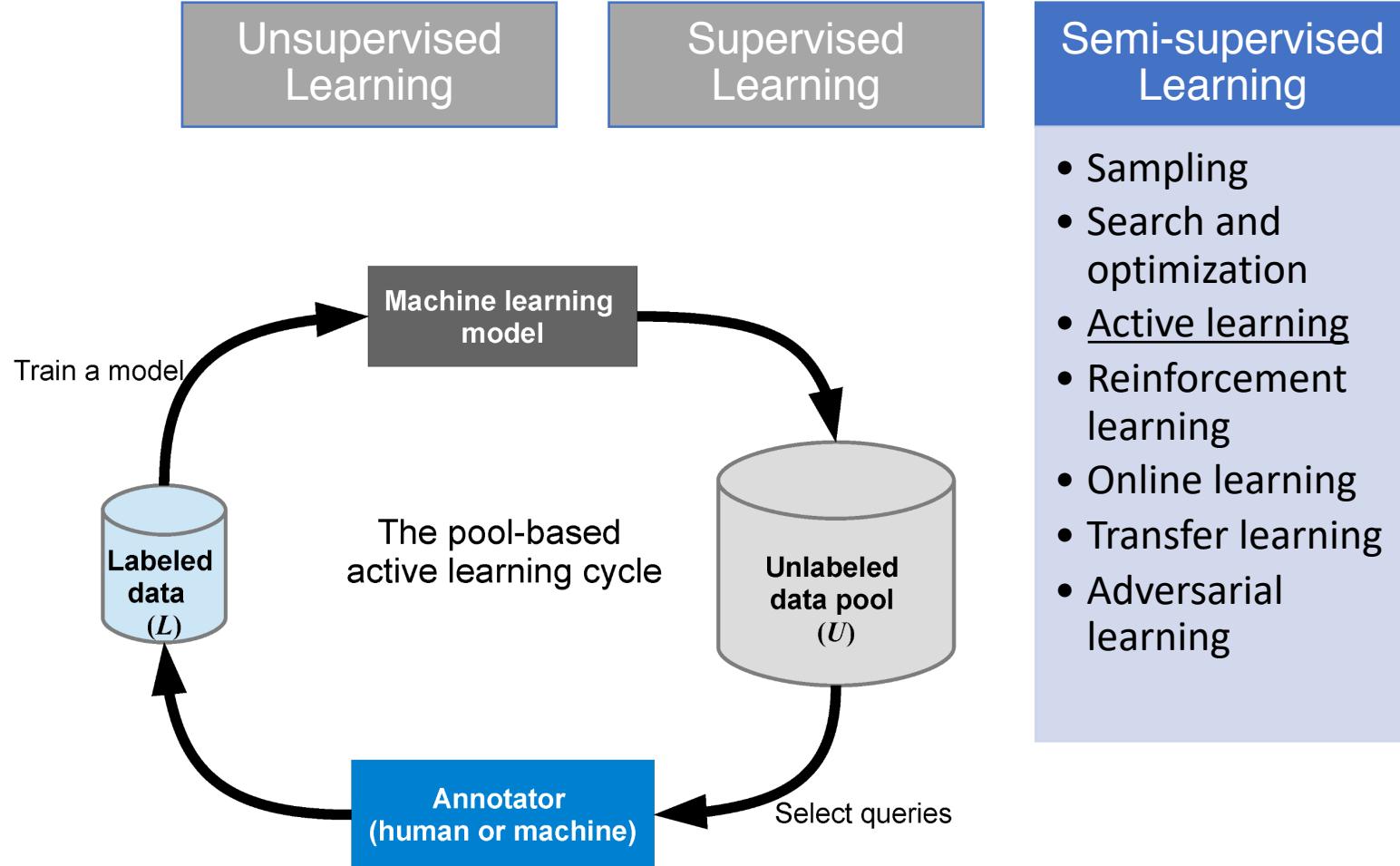
Semi-supervised  
Learning

- Sampling
- Search and optimization
- Active learning
- Reinforcement learning
- Online learning
- Transfer learning
- Adversarial learning

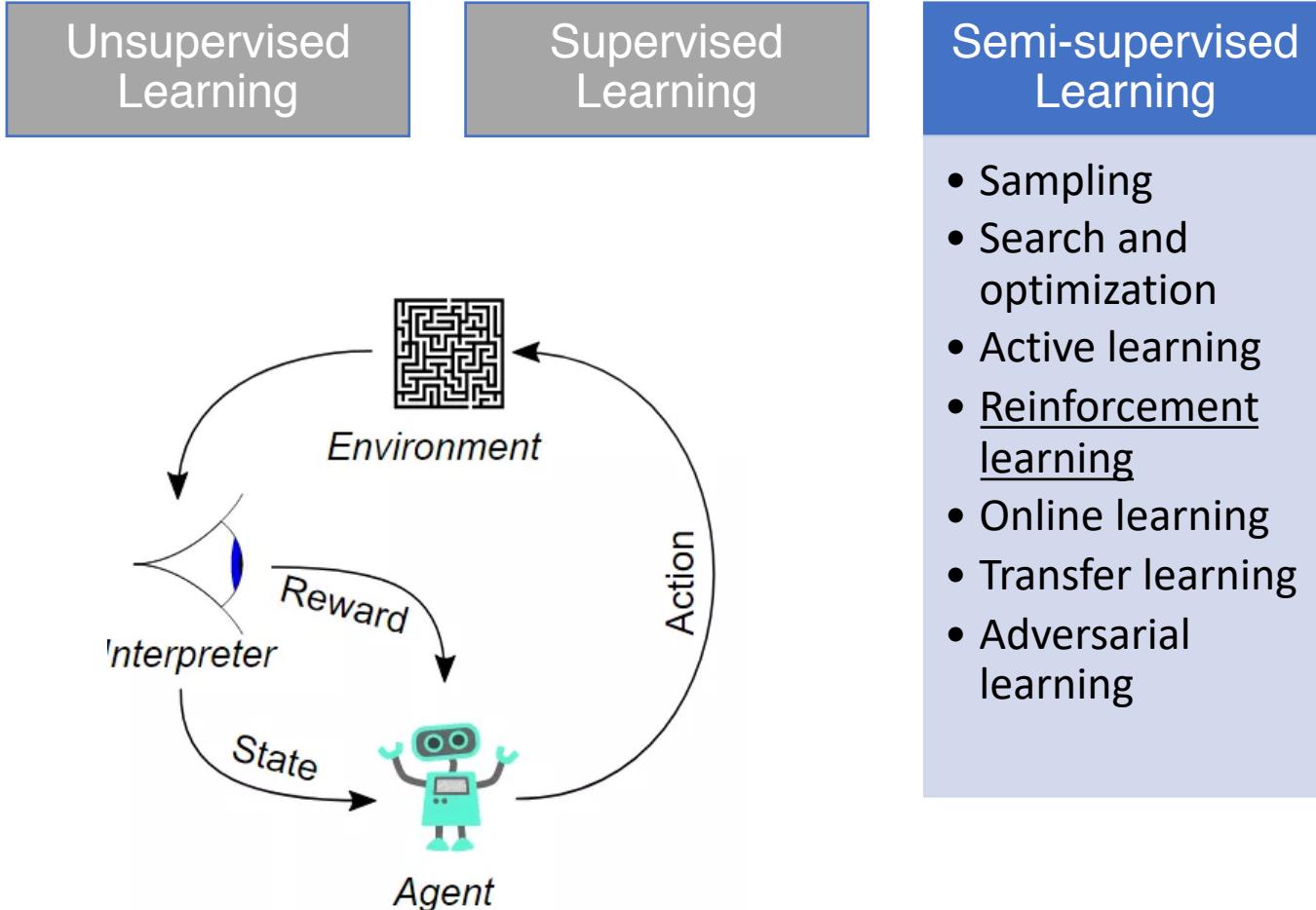
# Taxonomy of Machine Learning



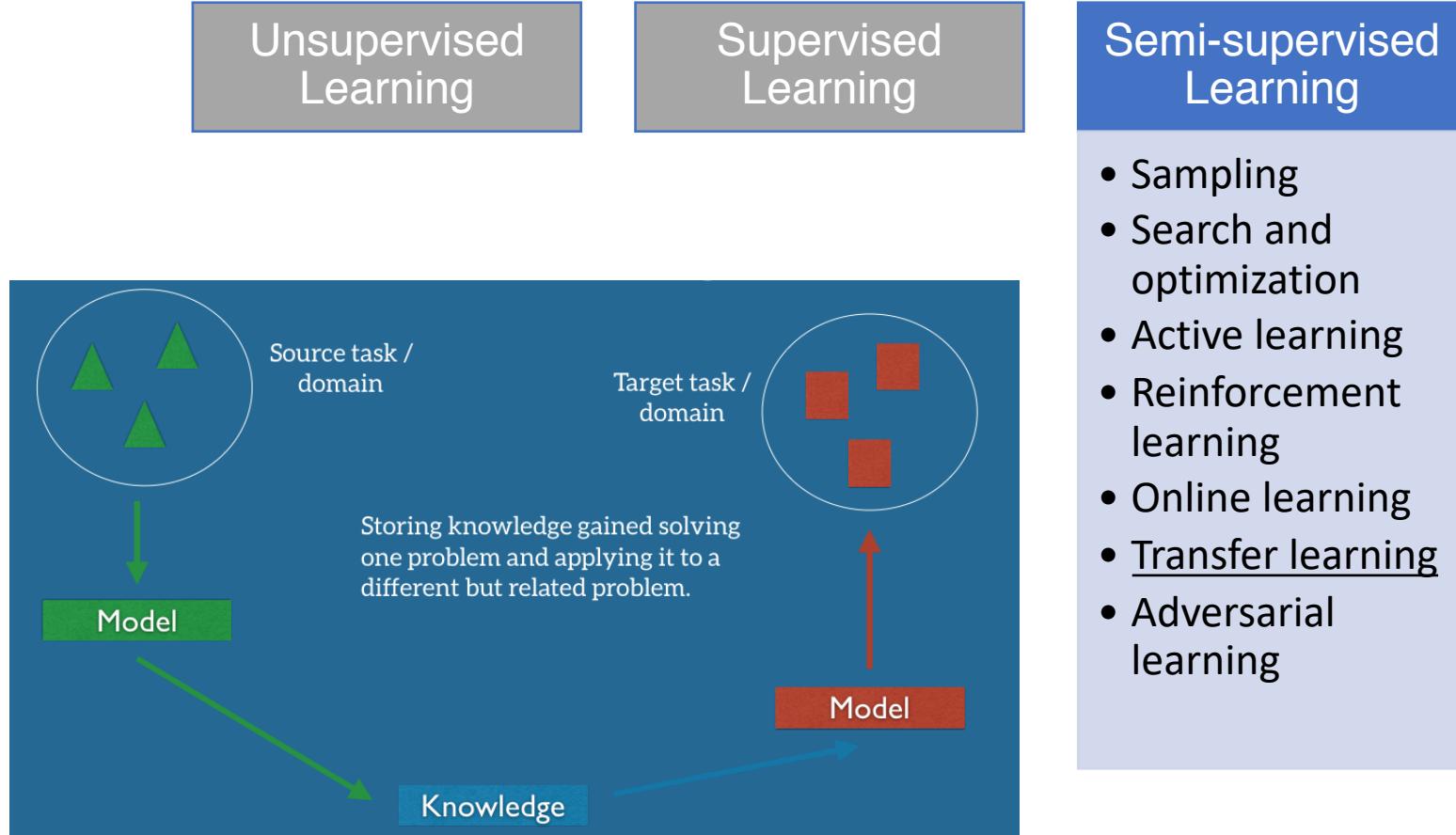
# Taxonomy of Machine Learning



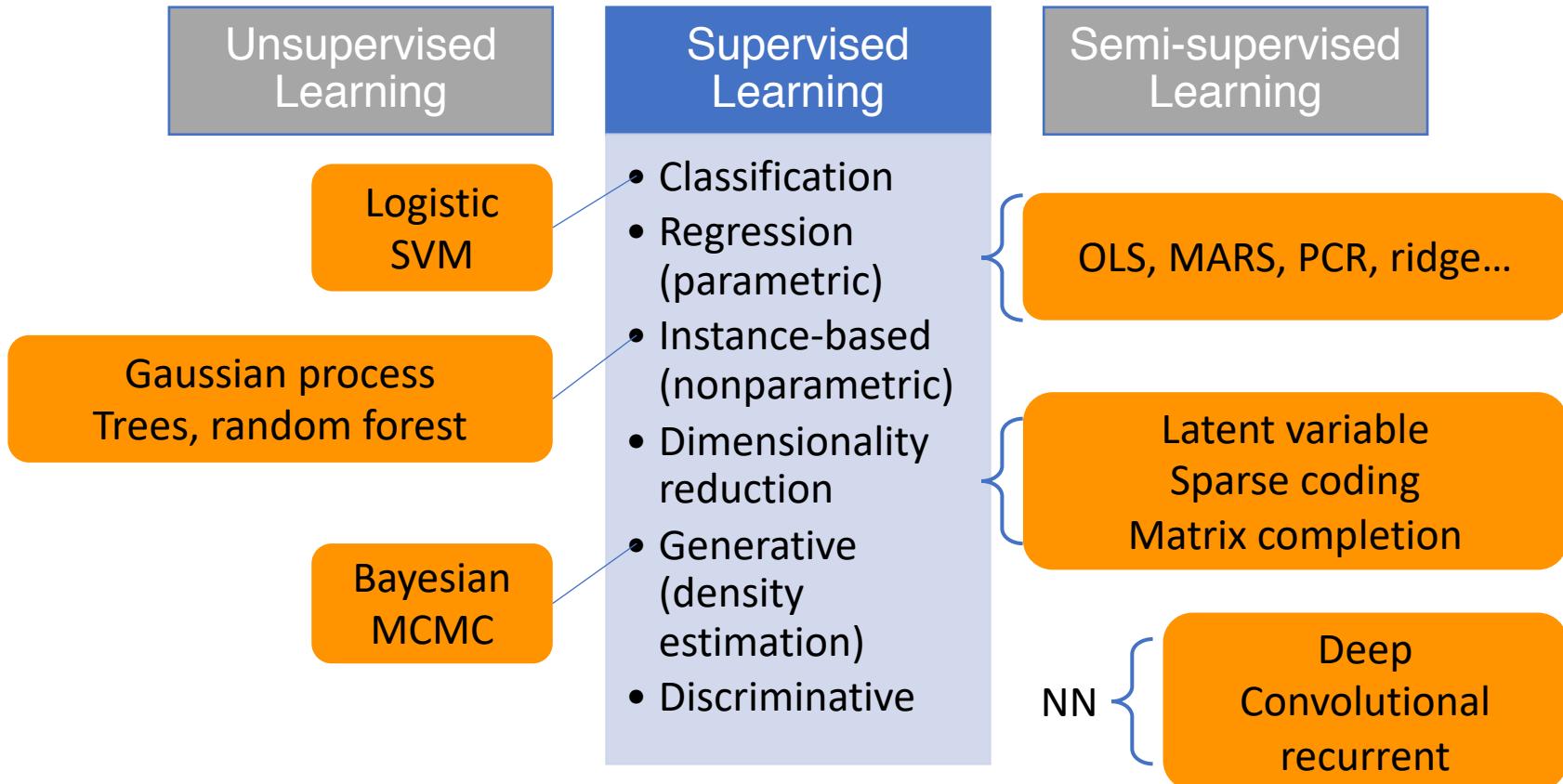
# Taxonomy of Machine Learning



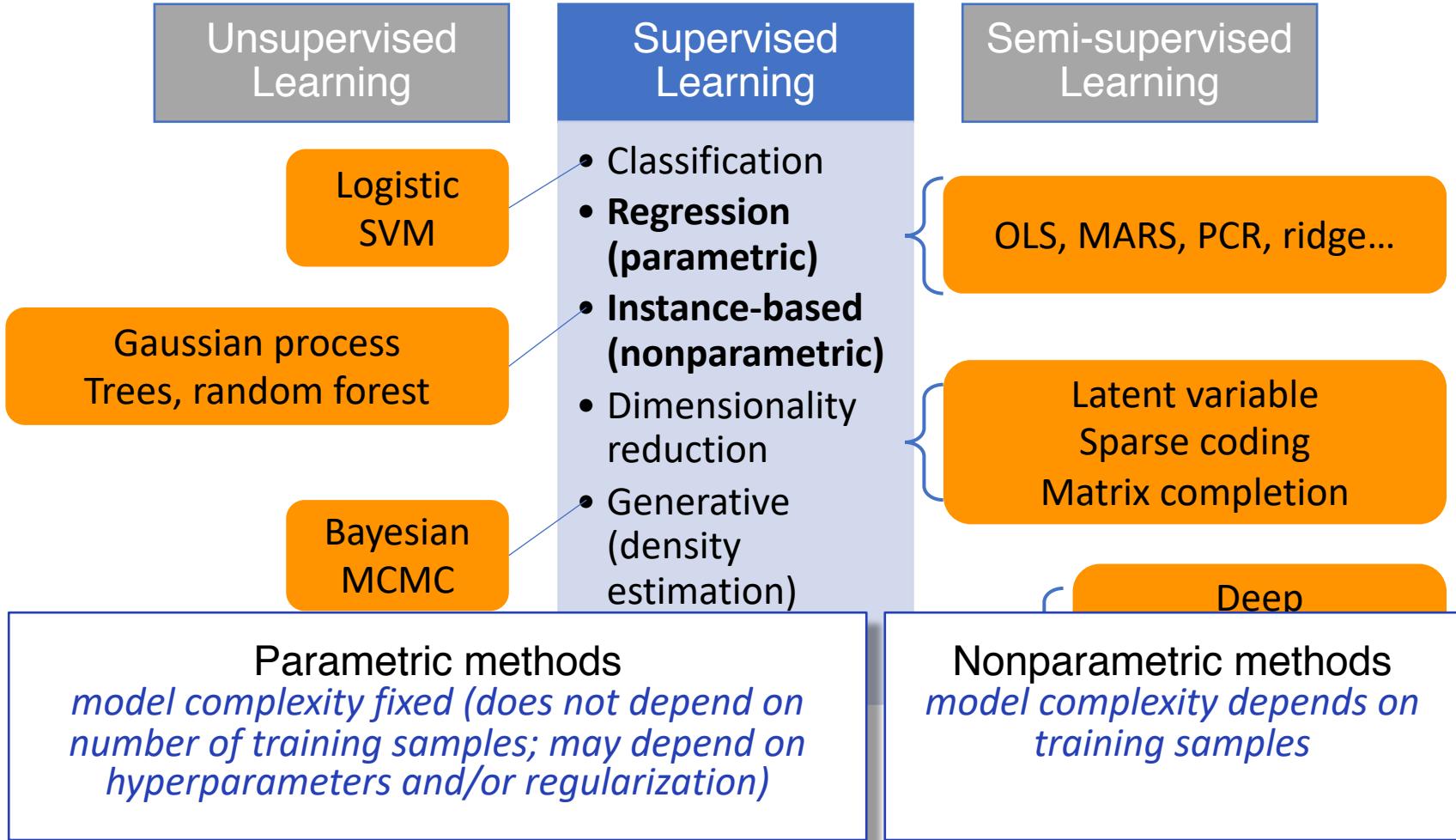
# Taxonomy of Machine Learning



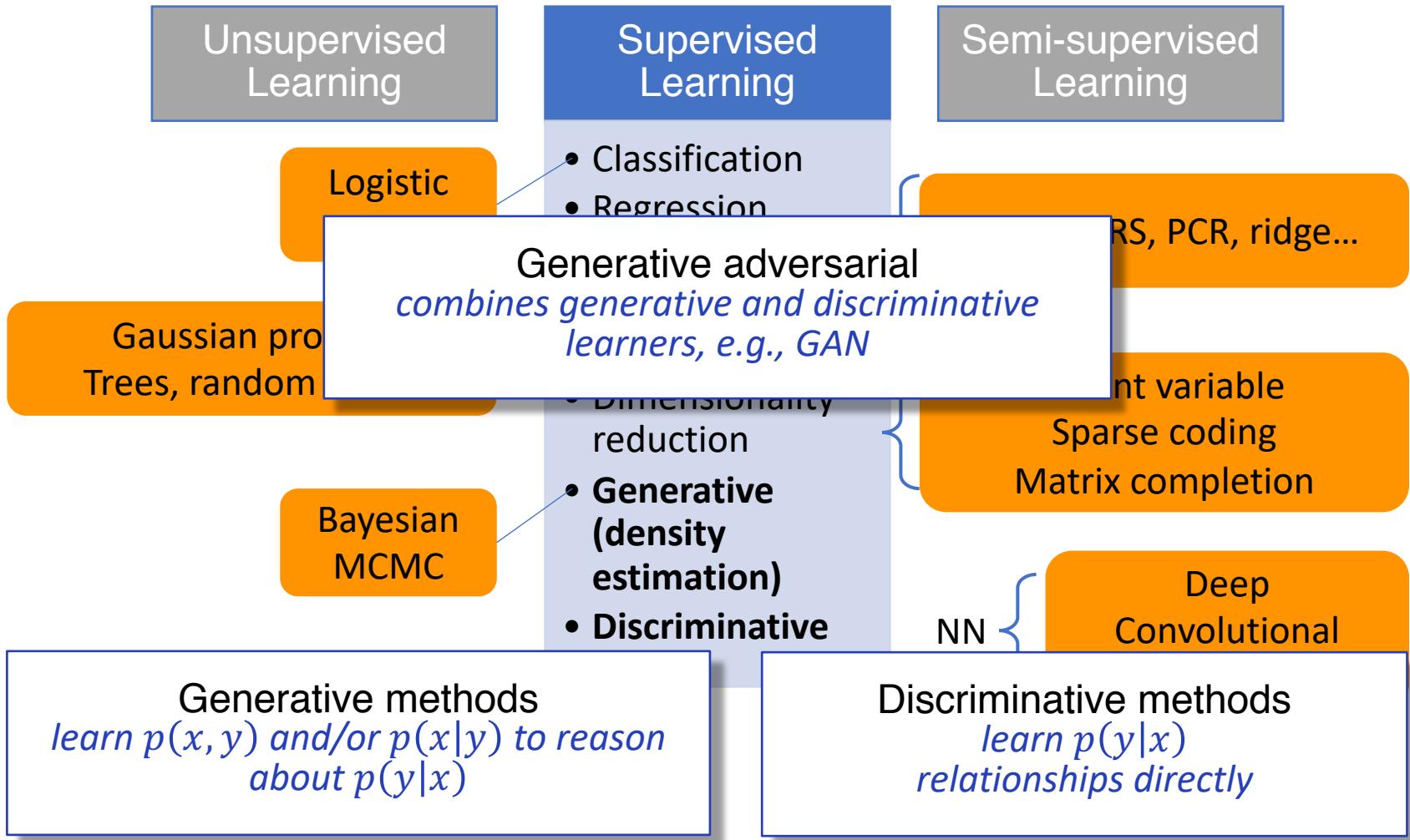
# Taxonomy of Machine Learning



# Taxonomy of Machine Learning



# Taxonomy of Machine Learning



# Before Going too Technical...



# New Job Opportunities: AI Trainer

- Machines can learn by themselves
- Why do we need AI trainers/engineers?
- Pokemons can fight by themselves. Why do they need pokemon trainers?



# To be Serious, Tasks for AI Trainer

- Proper model
  - Define the set of functions
- Proper loss function
- Not always easy to find the best function
  - Optimality? E.g., Deep learning
- Require experienced engineers



# Taxonomy of Machine Learning

Unsupervised Learning	Supervised Learning	Semi-supervised Learning
<ul style="list-style-type: none"><li>• Clustering</li><li>• Dimensionality reduction</li><li>• Kernel methods</li><li>• Density estimation</li></ul>	<ul style="list-style-type: none"><li>• Classification</li><li>• Regression (parametric)</li><li>• Instance-based (nonparametric)</li><li>• Dimensionality reduction</li><li>• Generative (density estimation)</li><li>• Discriminative</li></ul>	<ul style="list-style-type: none"><li>• Sampling</li><li>• Search and optimization</li><li>• Active learning</li><li>• Reinforcement learning</li><li>• Online learning</li><li>• Transfer learning</li><li>• Adversarial learning</li></ul>

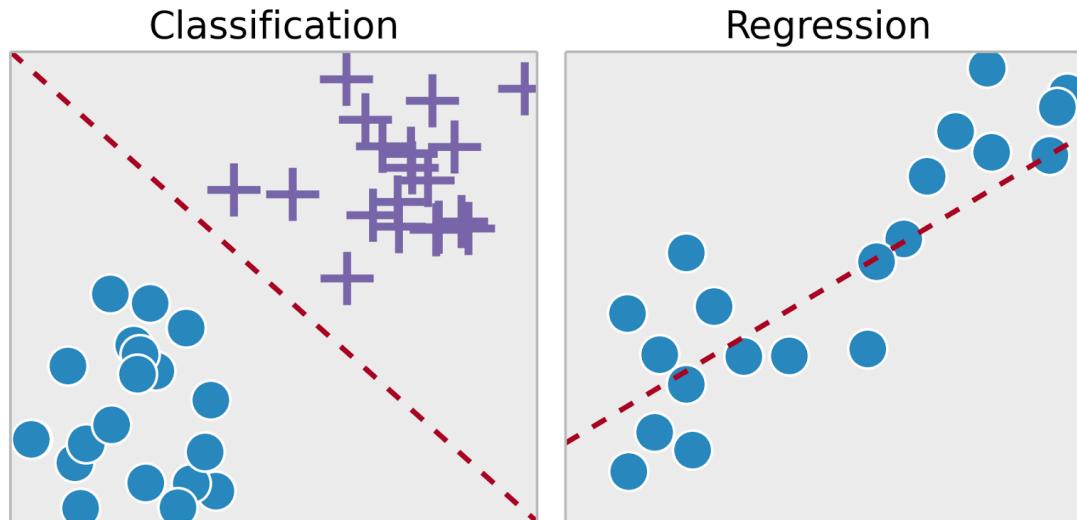
# Linear Models

- Linear regression

- $f(x) = \langle w \cdot x \rangle + b = \sum_{i=1}^N w_i x_i + b$

- Logistic classification

- $P(y = 1|x) = \frac{1}{1+e^{-(\sum_{i=1}^N w_i x_i + b)}}$



# Linear Models – Training

- Ordinary Least Squares (OLS)
  - Minimizes the mean square error over the  $n$  data points
  - Direct solution is possible

$$\min_{w,b} \quad \frac{1}{n} \sum_{i=1}^n (w^T x^{(i)} + b - y^{(i)})^2$$

- Ridge Regression
  - Regularization by penalizing large weights

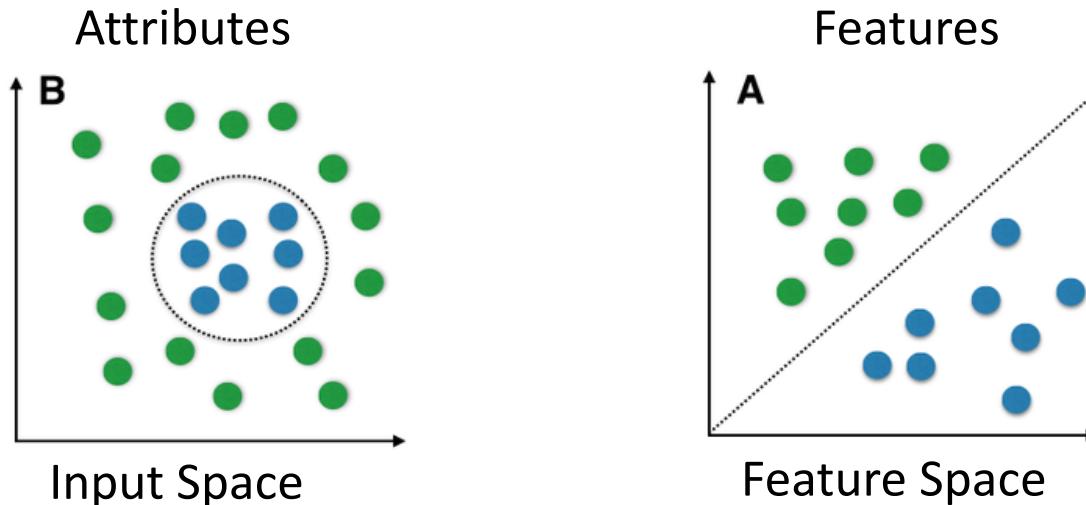
$$\min_{w,b} \quad \left( \frac{1}{n} \sum_{i=1}^n (w^T x^{(i)} + b - y^{(i)})^2 \right) + \lambda \|w\|^2$$

- Stochastic gradient descent (SGD)
  - Pick a data point  $i$  (or a batch) at random for iterative model updates, same idea as neural networks

# Feature Space

- Mapping from input space to feature space

$$x = [x_1, x_2, \dots, x_N] \mapsto \phi(x) = [\phi(x_1), \phi(x_2), \dots, \phi(x_N)]$$

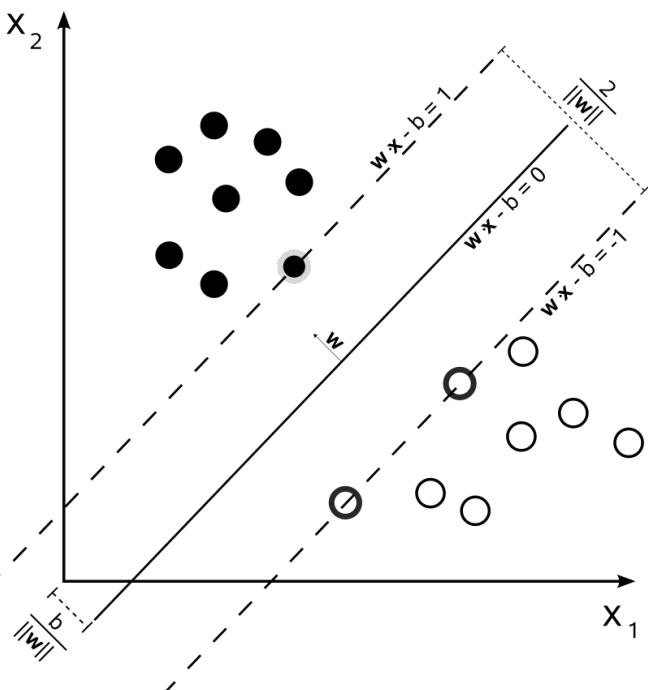


- Nonlinear features under a linear model

$$\bullet f(x) = \sum_{i=1}^M w_i \phi_i(x) + b$$

# Support Vector Machine

- A learning method that uses a hypothesis space of linear functions in a high dimensional feature space trained with an optimization based learning algorithm



$x_i$ : feature vector  
 $y_i$ : label,  $\{-1, 1\}$   
Consider  $\hat{y}_i = w_i x_i - b$

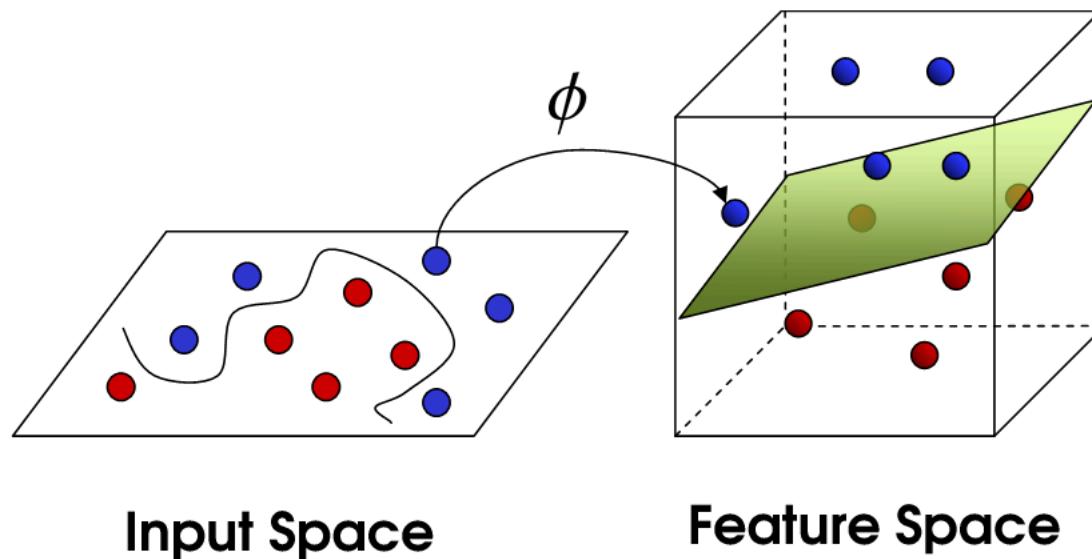
Objective

$$\min. \frac{1}{2} \|w\|^2$$

Subject to  
 $(w_i x_i - b)y_i \geq 1$

# Support Vector Machine

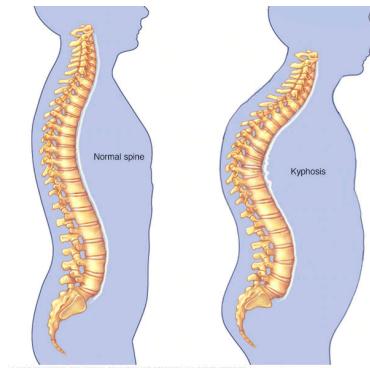
- Extend to a high-dimensional feature space through the (nonlinear) kernel
- Data can be linearly separable in feature space



# Decision Trees for Classification

Partition the input space and fit very simple models to predict the output in each partition.

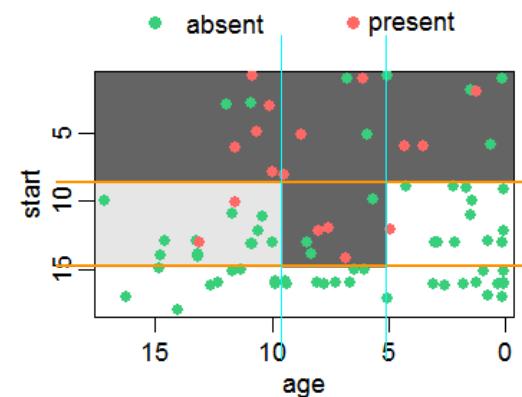
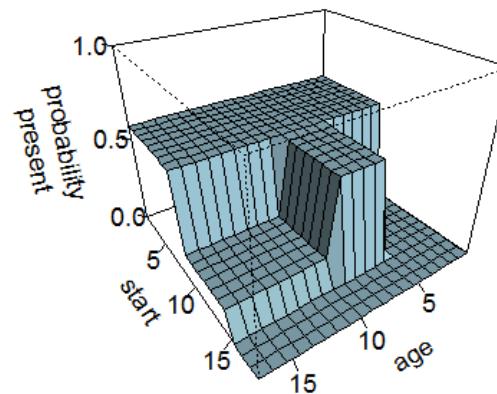
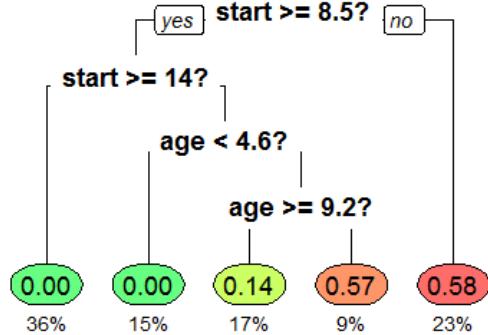
- Split nodes: select the “best” feature and value to split
- “Best”: usually defined in terms of some notion of “impurity” in the resulting partition of training data. Typical impurity measures include misclassification error, Gini index, or entropy



# Decision Trees for Classification

Partition the input space and fit very simple models to predict the output in each partition.

- Split nodes: select the “best” feature and value to split
- “Best”: usually defined in terms of some notion of “impurity” in the resulting partition of training data. Typical impurity measures include misclassification error, Gini index, or entropy



# K-Means Clustering

## Unsupervised learning

- Only have feature  $x$ , no label  $y$

Target: identify natural groups of data

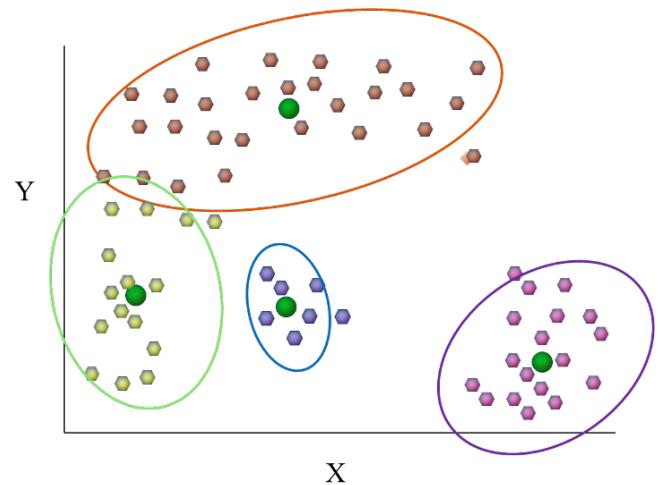
- $\min \sum_{i=1}^K \sum_{x \in S_i} \|x - \mu_i\|^2$

## Iterative algorithm

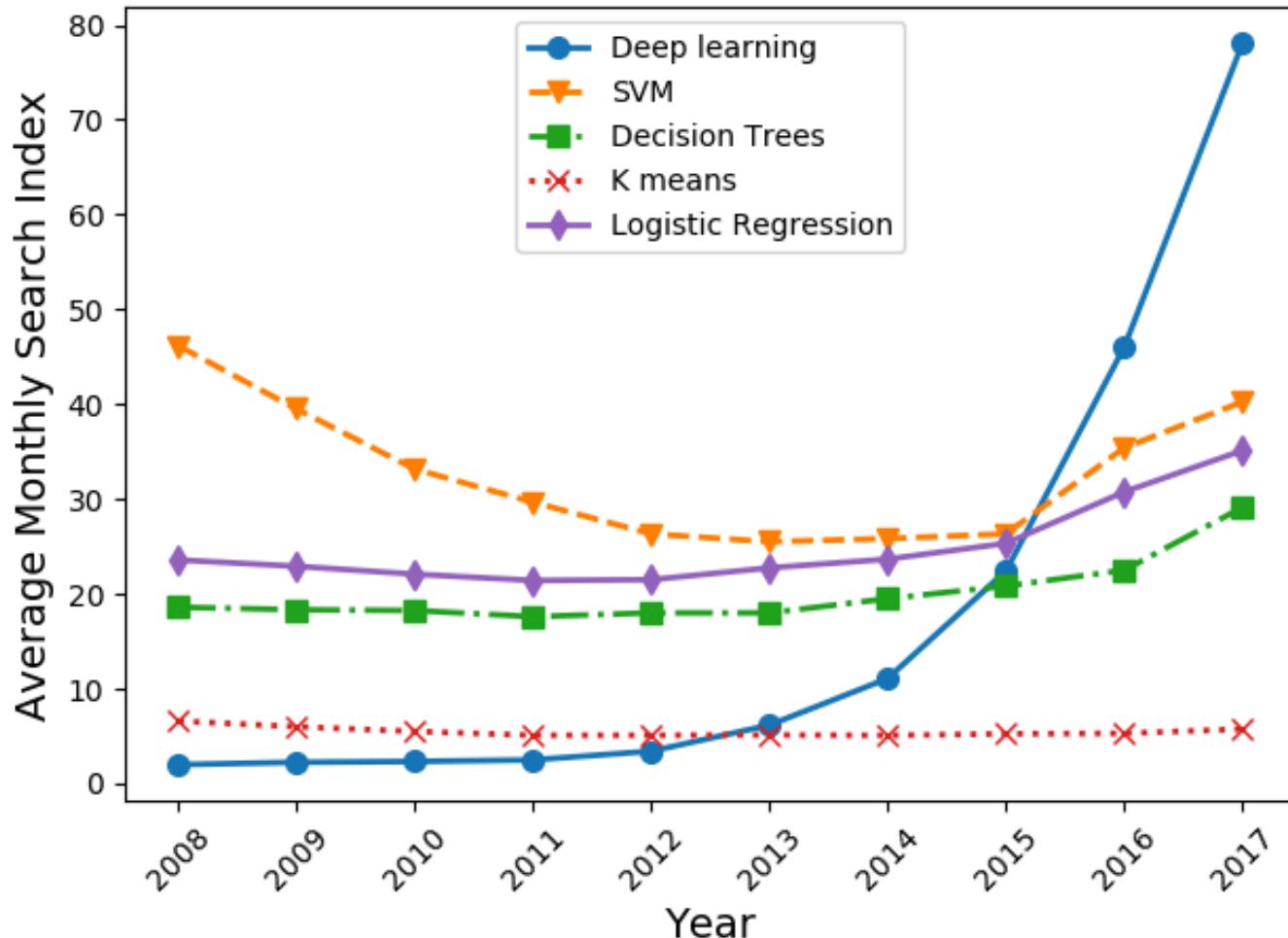
Randomly set cluster centers  $m_1, \dots m_k$ ;

For not converged

- Use these centers to assign each data point to the nearest cluster;
- Adjust centers  $m_i$  based on those memberships;



# Deep Learning

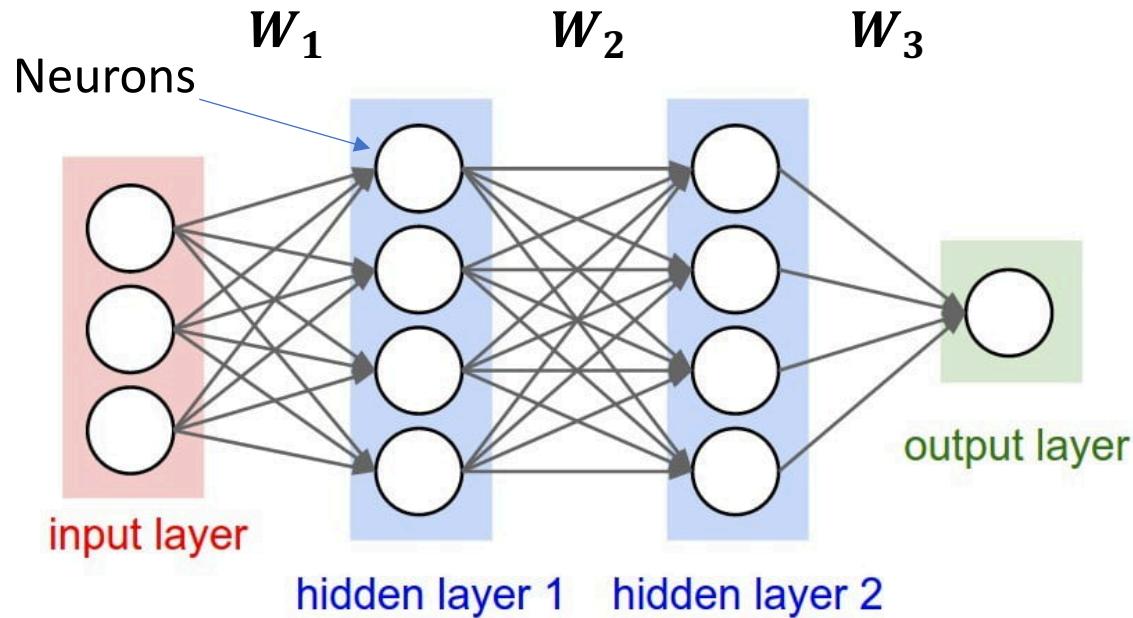
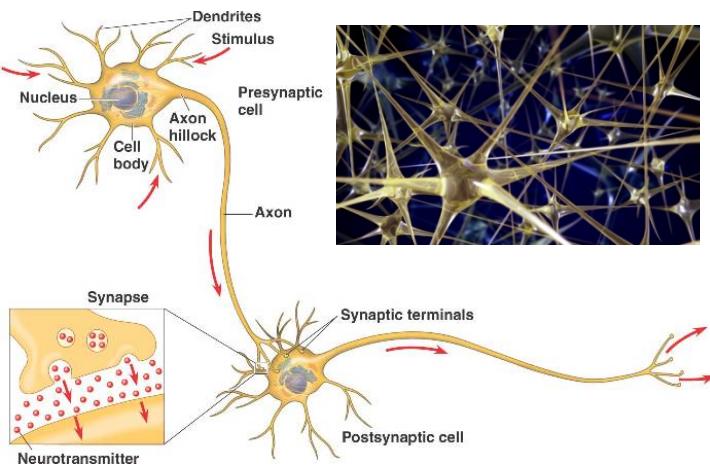


# Neural Networks

- Multilayer perceptron (MLP)

$$f(x) = \sigma_3(W_3\sigma_2(W_2\sigma_1(W_1x)))$$

$\sigma_i$ : activation function

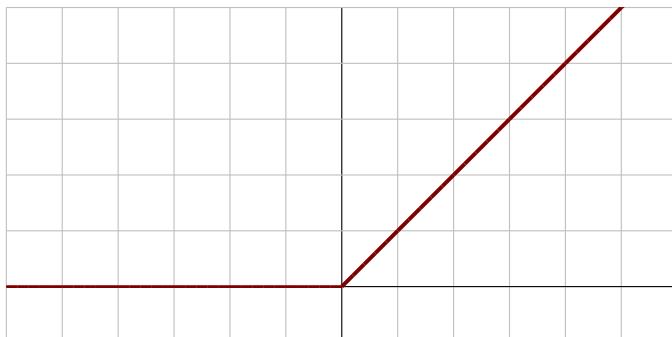


# Neural Networks

- Multilayer perceptron (MLP)

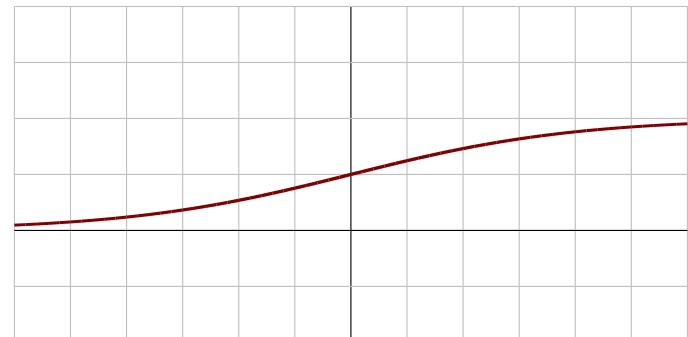
$$f(x) = \sigma_3(W_3\sigma_2(W_2\sigma_1(W_1x)))$$

$\sigma_i$ : activation function



Rectified linear unit (ReLU)

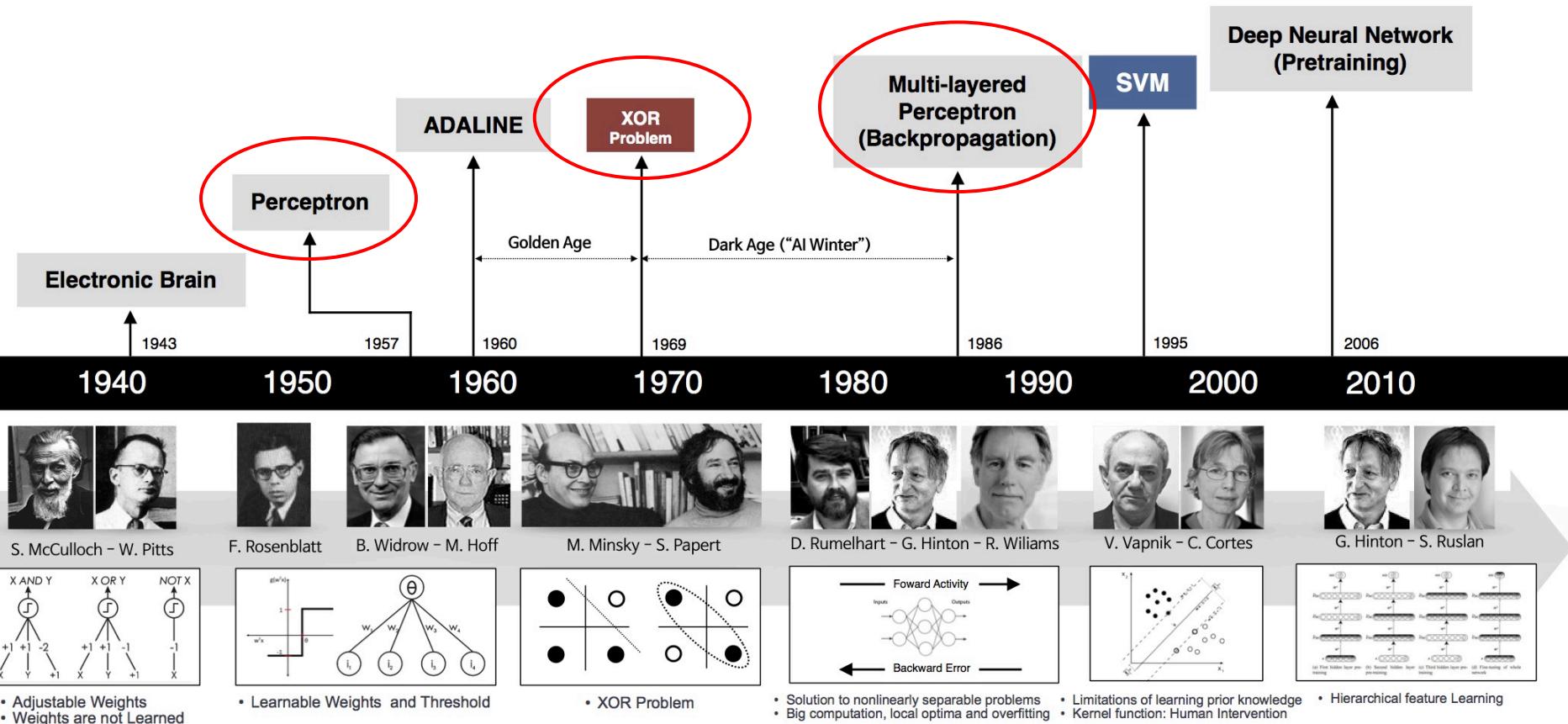
$$f(x) = \begin{cases} 0, & \text{for } x < 0 \\ x, & \text{for } x \geq 0 \end{cases}$$



Logistic (Sigmoid)

$$f(x) = \frac{1}{1 + e^{-x}}$$

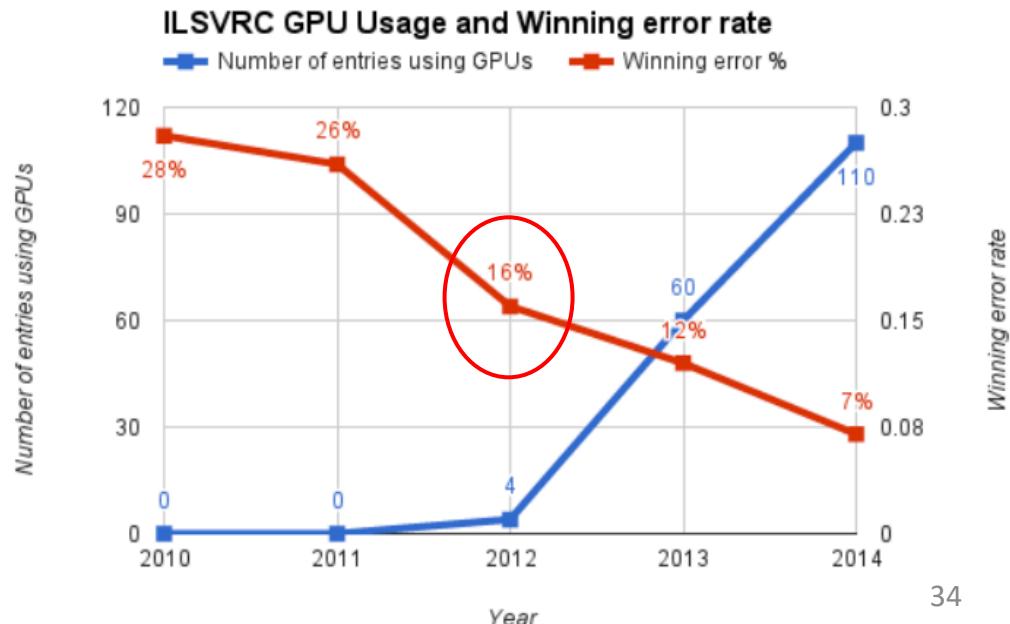
# A Bit History on Deep Learning



[https://beamandrew.github.io/deeplearning/2017/02/23/deep\\_learning\\_101\\_part1.html](https://beamandrew.github.io/deeplearning/2017/02/23/deep_learning_101_part1.html)

# A Bit History on Deep Learning

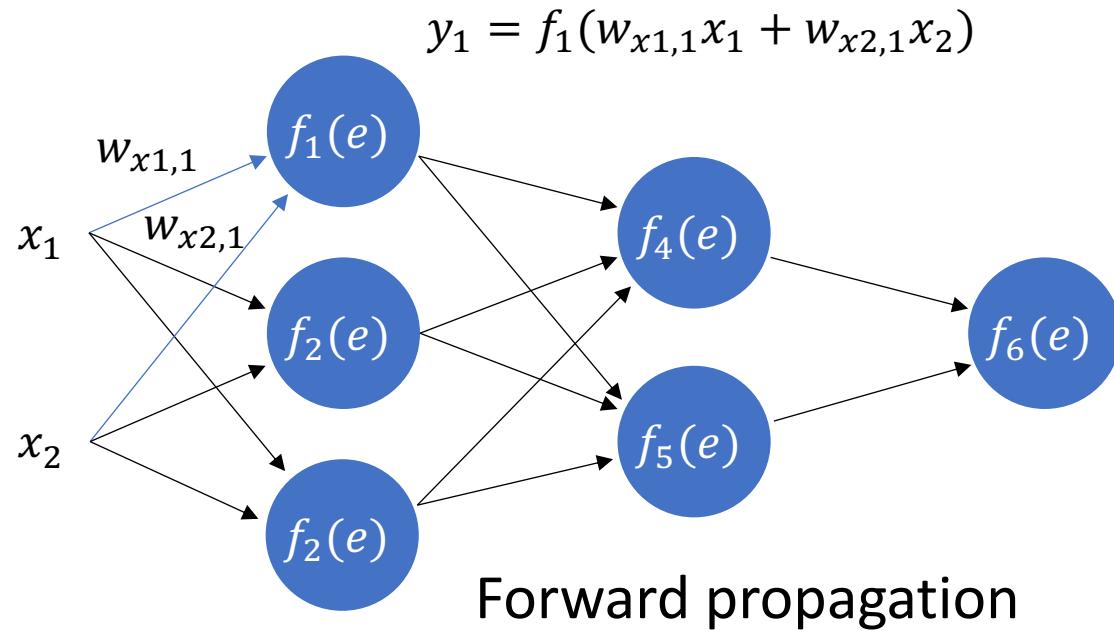
- “Neural networks” → “Deep learning” in 2006
  - Geoffrey Hinton
- Breakthrough in 2012
  - Large scale visual recognition challenge (LSVRC)
  - ImageNet



[https://beamandrew.github.io/deeplearning/2017/02/23/deep\\_learning\\_101\\_part1.html](https://beamandrew.github.io/deeplearning/2017/02/23/deep_learning_101_part1.html)

# How to Train a Neural Network

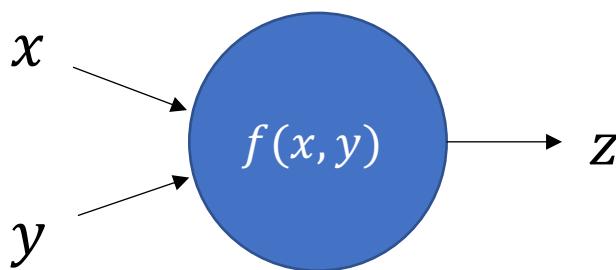
- Objective:  $\min. \sum_i Loss(f(x_i), y_i)$
- Gradient descent
- Backpropagation



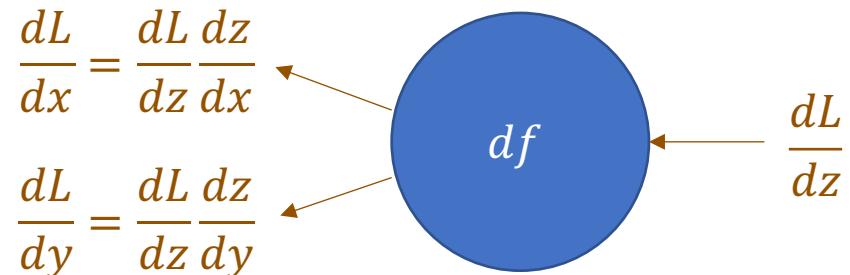
# How to Train a Neural Network

- Gradient descent
  - Loss function:  $L(z)$
- Backpropagation
  - Chain rule

Forward pass

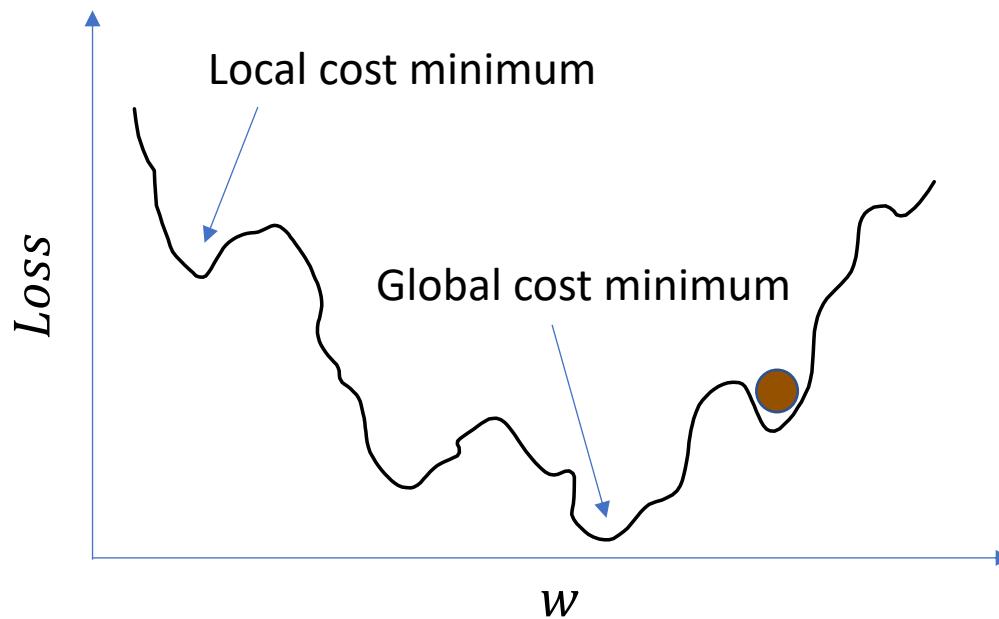


Backward pass



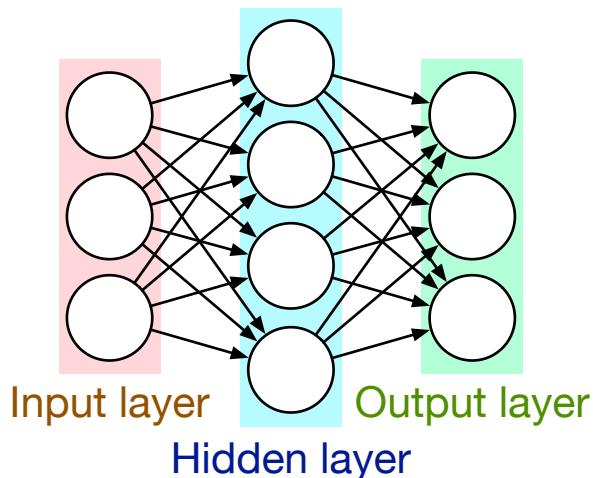
# How to Train a Neural Network

- Gradient descent
- Backpropagation
- Non-linear optimization



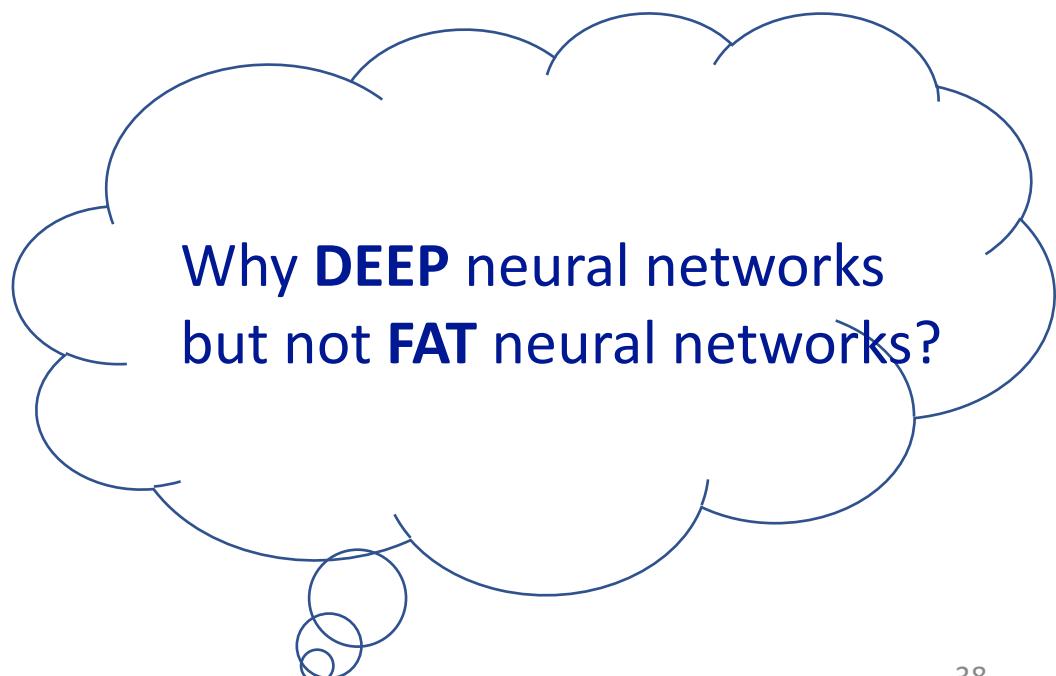
# Why Deep? Universality Theorem

- Any function  $f: R^N \rightarrow R^M$
- Can be realized by a neural network with one hidden layer
- (given enough hidden neurons)



Reference for the reason:

<http://neuralnetworksanddeeplearning.com/chap4.html>

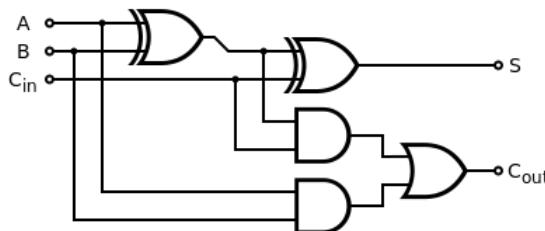


# Why Deep? Analogy

## Logic Circuits

- Consist of logic **gates**
- A two layers of logic gates can represent **any Boolean function**
- Use multiple layers of logic gates to build functions in a much simpler way

Less gates required



## Neural Networks

- Consist of **neurons**
- A hidden layer network can represent **any continuous function**
- Use multiple layers to represent functions in a much simpler way

Less parameters



Less data?

More reason:

[https://www.youtube.com/watch?v=XsC9byQkUH8&list=PLJV\\_el3uVTsPy9oCRY30oBPNLCo89yu49&index=13](https://www.youtube.com/watch?v=XsC9byQkUH8&list=PLJV_el3uVTsPy9oCRY30oBPNLCo89yu49&index=13)

# Why Deep? NOT Fat

- Ocaam's razor: Entities should not be multiplied without necessity
  - The simplest solution is most likely the right one
  - Less parameters, better generalization
- Deep + Thin v.s. Short + Fat
  - Same # of parameters
  - Deep networks tend to generalize better
  - Require less amount of training data

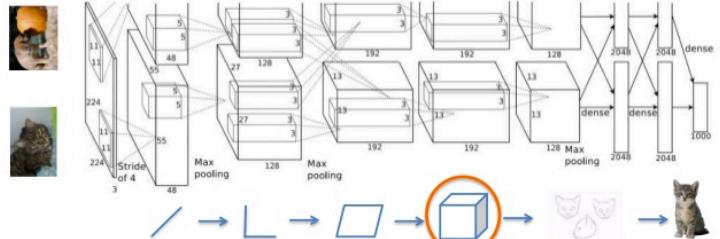
#Layers x #Neurons	Error Rate (%)	1 x #Neurons	Error Rate (%)
5x2k	17.2	1x3772	22.5
7x2k	17.1	1x4634	22.4

Seide, Frank, Gang Li, and Dong Yu. "Conversational speech transcription using context-dependent deep neural networks." *Twelfth annual conference of the international speech communication association*. 2011.

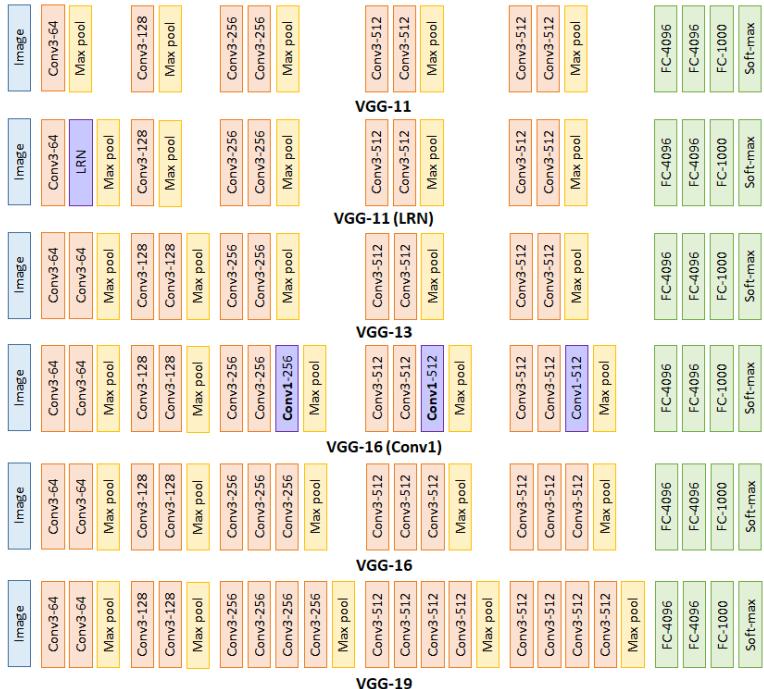
# How Deep?

## AlexNet (Krizhevsky et al. 2012)

*The class with the highest likelihood is the one the DNN selects*

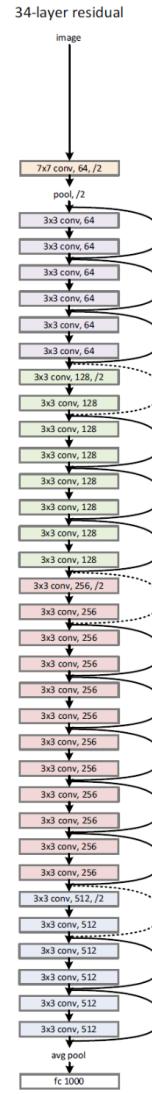


When AlexNet is processing an image, this is what is happening at each layer.



5-layers  
Top-5 err.  
16.4

Number of Parameters (millions)	Top-5 Error Rate (%)
133	10.4
133	10.5
133	9.9
134	9.4
138	8.8
144	9.0

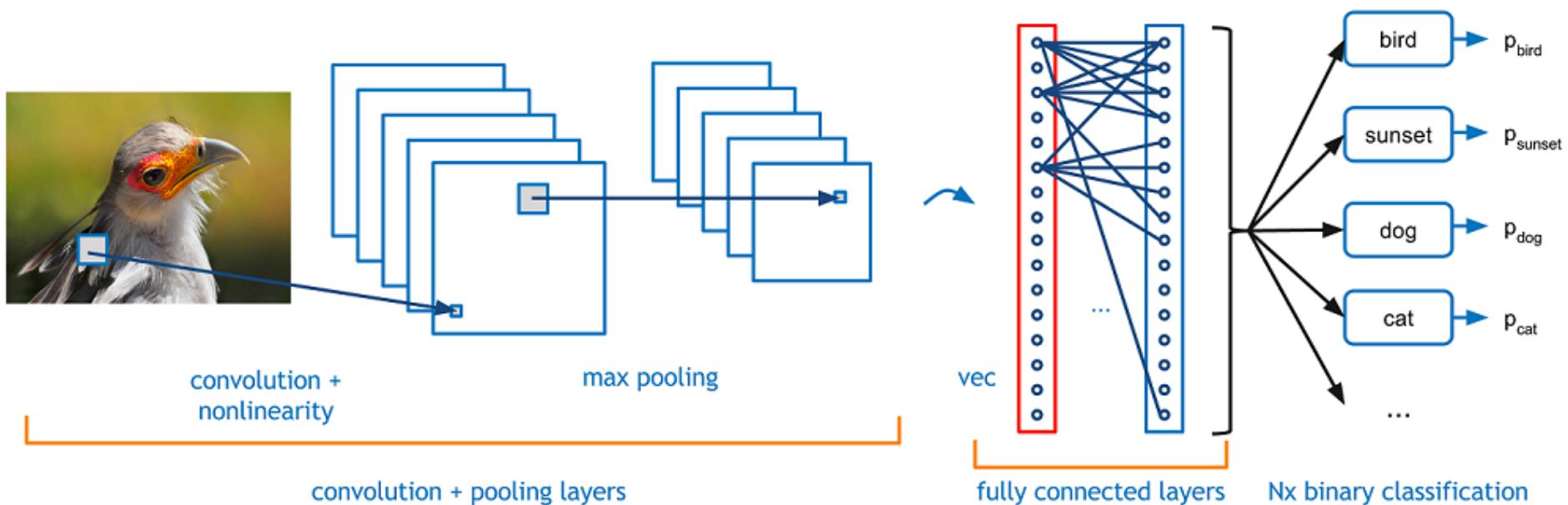


ResNet	Top-5 err.
34	7.4
101	6.0
152	5.7

# More Flavors... Convolutional Neural Networks

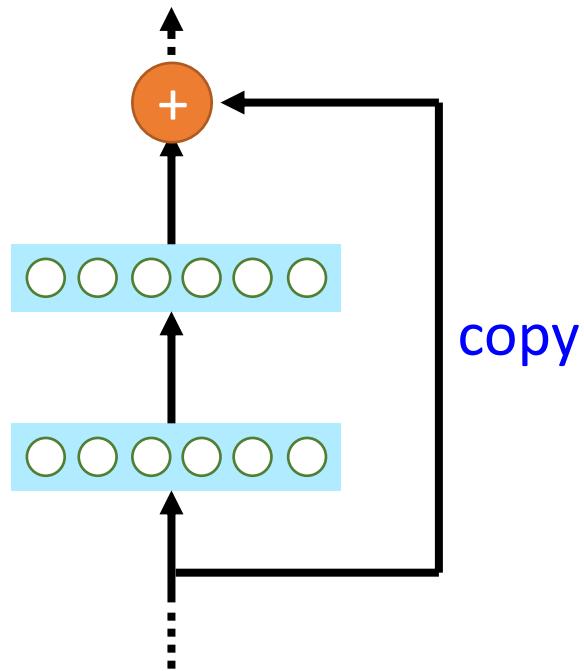
## Convolutional layer

- Suitable to images
- Correlation with neighboring pixels

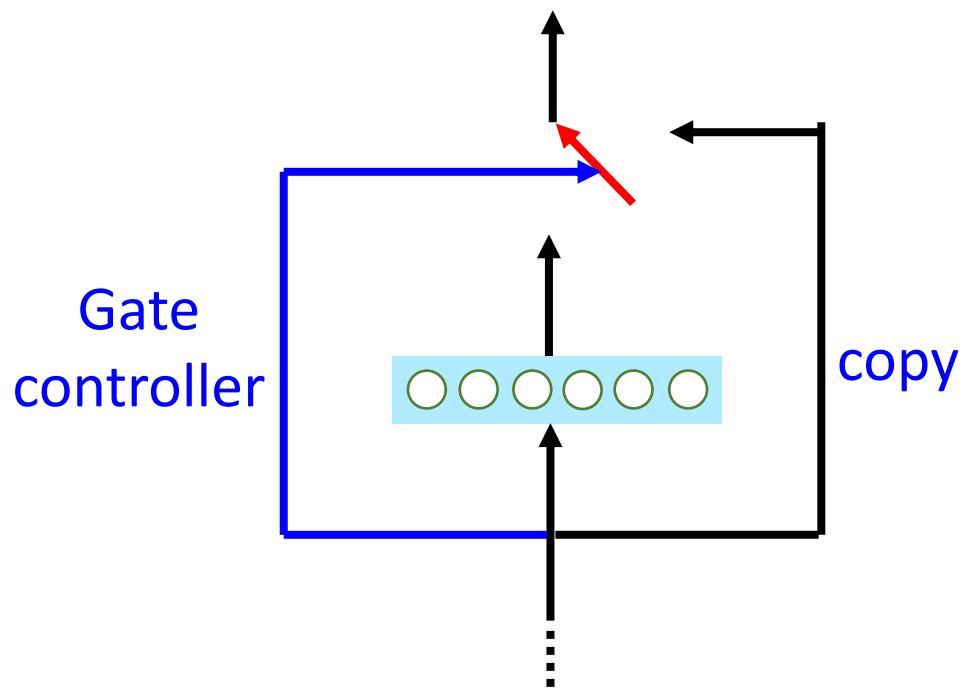


# More Flavors... Highway Networks

## Residual Network



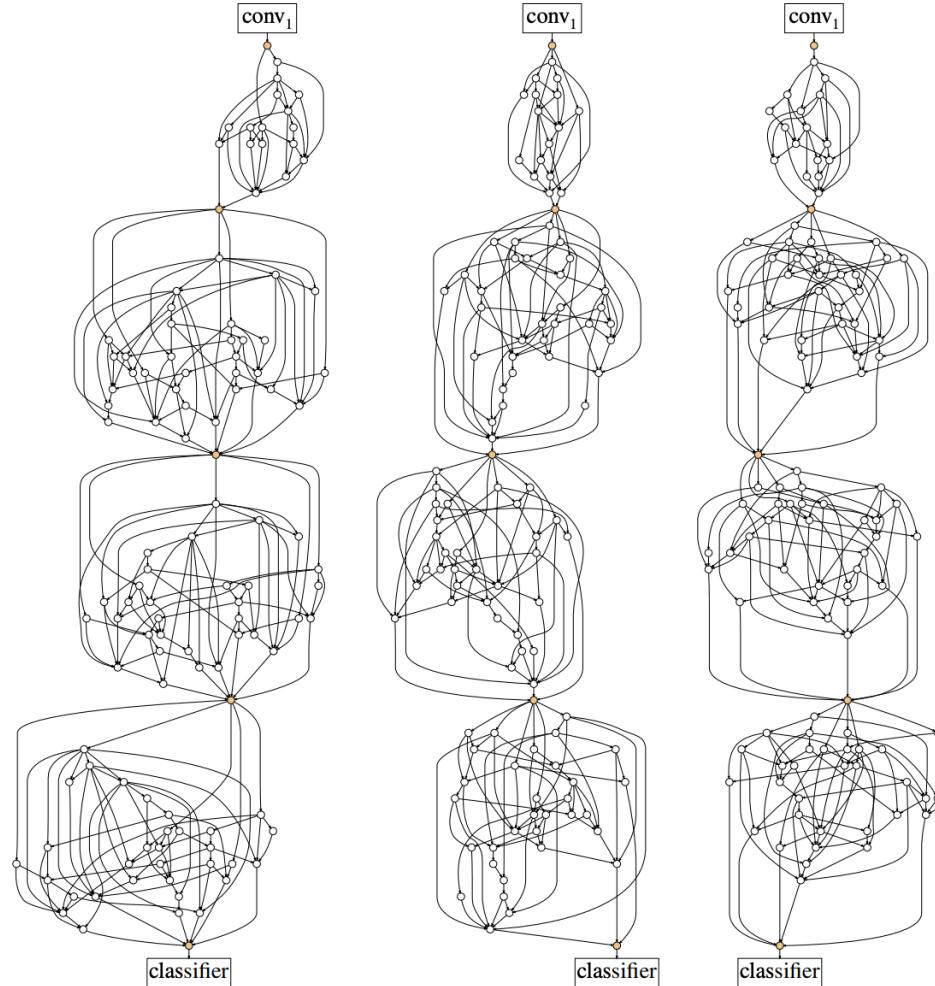
## Highway Network



Deep Residual Learning for Image  
Recognition  
[http://arxiv.org/abs/1512.03385](https://arxiv.org/abs/1512.03385)

Training Very Deep Networks  
<https://arxiv.org/pdf/1507.06228v2.pdf>

# More Flavors... Random Networks



Exploring Randomly Wired  
Neural Networks for Image  
Recognition

<https://arxiv.org/pdf/1904.01569.pdf>

# Generative Adversarial Networks

- GAN [[Goodfellow et al, 2014](#)] [[Radford et al, 2015](#)]
  - Two networks contest (generator and discriminator)
  - Produces images similar to those in the training data

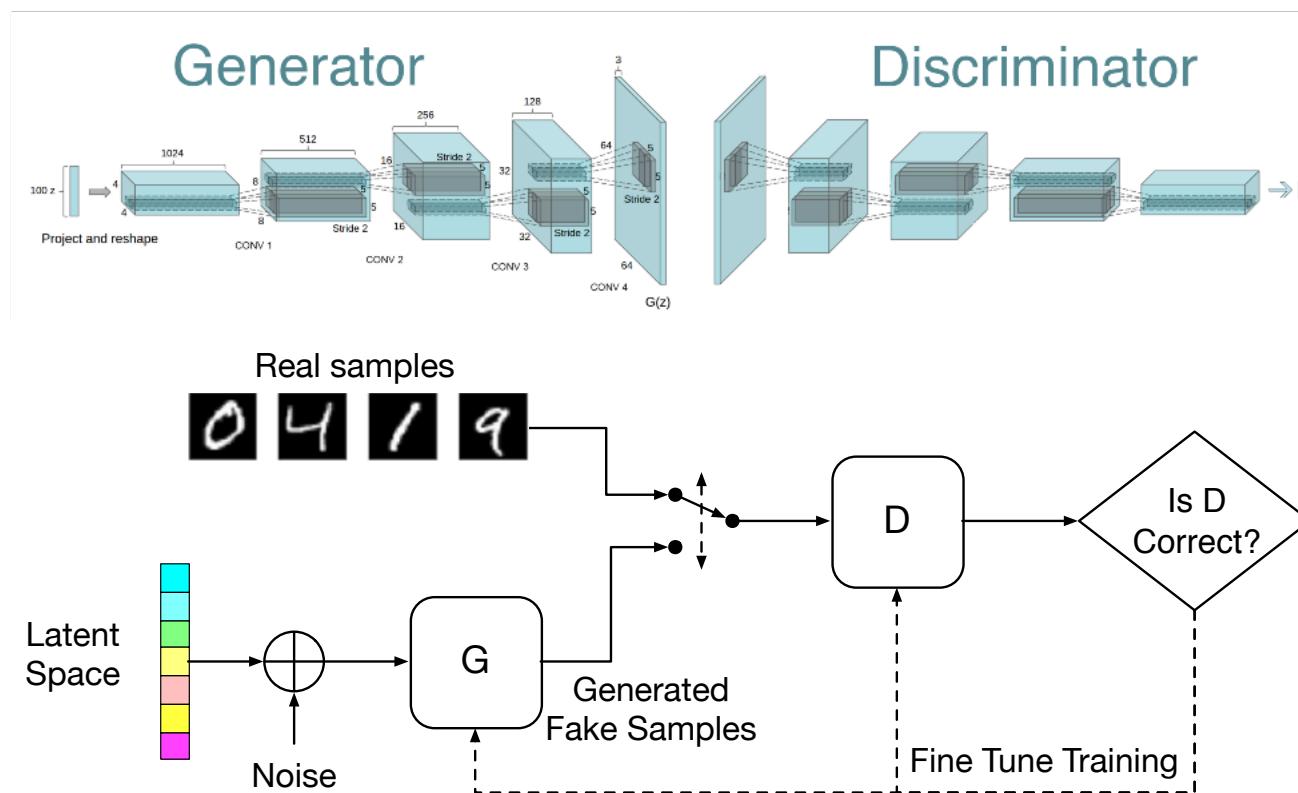


"Generative Adversarial Networks is the **most interesting idea in the last ten years** in machine learning."

Yann LeCun, Director, Facebook AI

# Generative Adversarial Networks

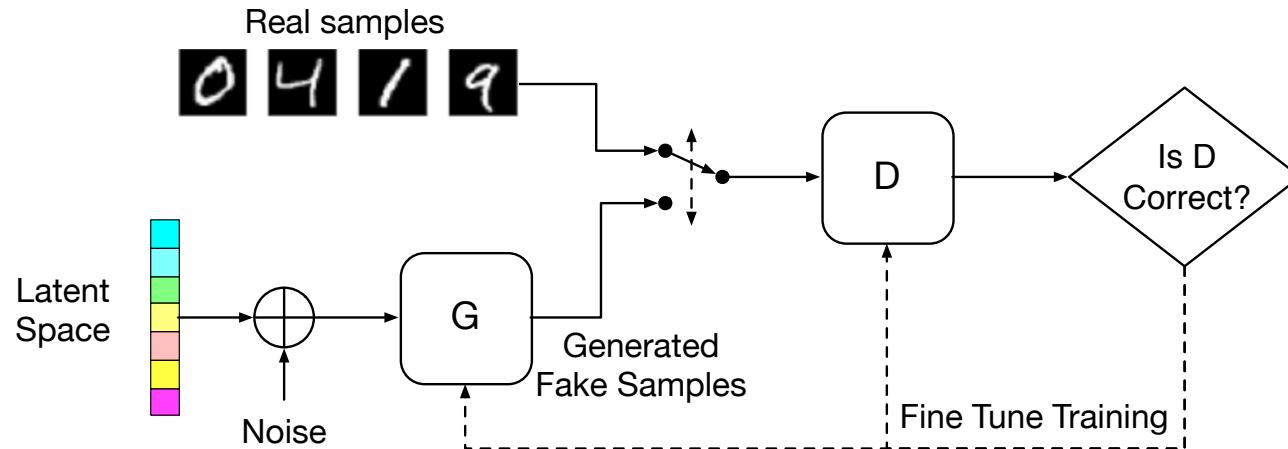
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# Generative Adversarial Networks

- GAN [Goodfellow et al, 2014] [Radford et al, 2015]
  - Two networks contest (generator and discriminator)
  - Produces images similar to those in the training data

$$\min_G \max_D \underbrace{\mathbb{E}_{x \sim p_{data}(x)} [\log D(x)]}_{\text{Loss for real samples}} + \underbrace{\mathbb{E}_{z \sim p_z(z)} [\log(1 - D(G(z)))]}_{\text{Loss for generated samples}}$$



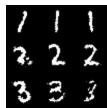
# Generative Adversarial Networks

- GAN [[Goodfellow et al, 2014](#)] [[Radford et al, 2015](#)]
  - Two networks contest (generator and discriminator)
  - Produces images similar to those in the training data

6	7	8	3	6	1	9	8
3	6	9	7	0	5	1	3
1	1	5	1	0	1	8	9
0	1	1	9	4	4	9	5
3	5	0	3	1	5	7	2
9	8	7	2	2	0	3	4
2	8	3	7	4	4	9	8
7	0	8	7	1	9	9	8

[DCGAN](#)

# Recent Development of GANs



## Conditional GANs (CGANs)

What if I want my GAN to generate data with specific attributes



## Image-to-Image Translation with CGAN (pix2pix)

Let's build a generic CGAN architecture where the condition is an image, and learn to translate this image into another domain



## BigGAN

Google: "Hold my beer Nvidia, my interns can use thousands of TPUs to generate cheeseburgers"

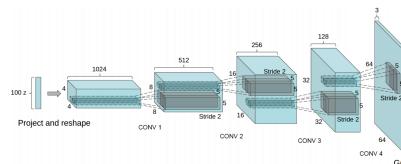


## Generative Adversarial Networks (GANs)

The architecture of a generator and a discriminator is first proposed by Goodfellow *et al.*

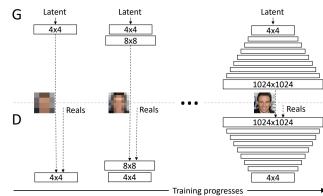
## Deep Convolutional GANs (DCGANs)

As the first major improvement on the GAN architecture, DCGAN is more stable during training and generates higher quality samples

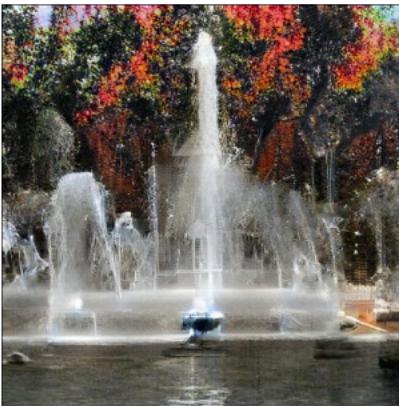


## PG-GAN/pix2pixHD

Nvidia: "Let's make some high-resolution GANs with multi-scale approaches"



# Recent Development of GANs



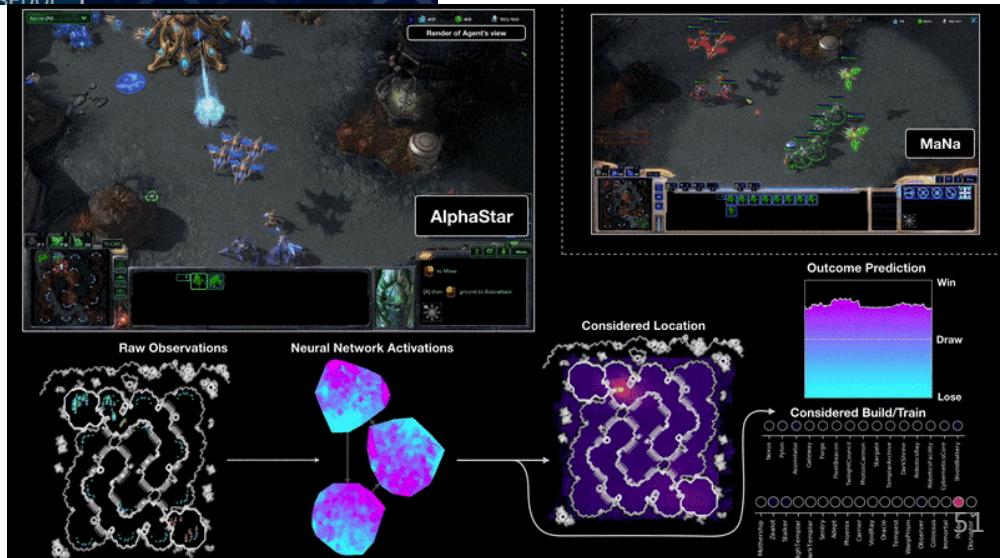
High quality images generated by BigGAN

# Reinforcement Learning



AlphaGO

AlphaStar



# Supervised v.s. Reinforcement

- Supervised
  - Learning from teachers
  - Labeled data



Next move: "5-5"



Next move: "3-3"

- Reinforcement
  - Learn from critics



- AlphaGO
  - Supervised learning + reinforcement learning

# Reference and More Resources

## ML courses from Hung-Yi Lee at NTU

- <http://speech.ee.ntu.edu.tw/~tlkagk/courses.html>

## Stanford ML courses on Coursera

- <https://www.coursera.org/learn/machine-learning>

## Tutorials on GANs

- NIPS 2016: <https://arxiv.org/pdf/1701.00160.pdf>
- CVPR 2018: <https://sites.google.com/view/cvpr2018tutorialongans/>

## Toolkit tutorials

- Tensorflow: <https://www.tensorflow.org/tutorials>
- PyTorch: <https://pytorch.org/tutorials/>

# Outline

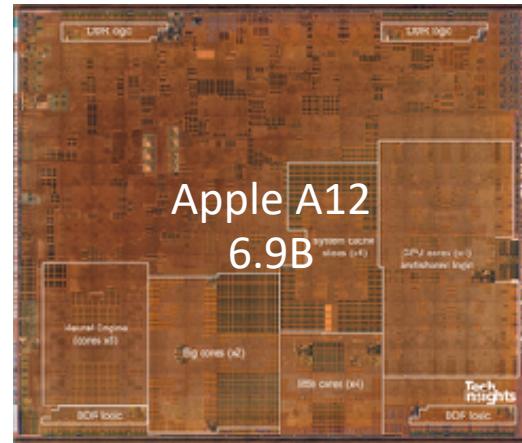
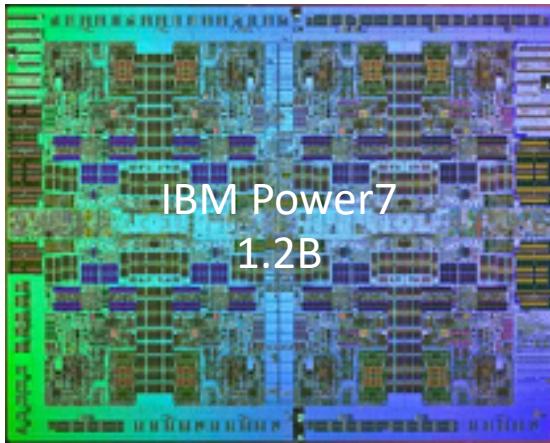
## Part I: Introduction to Machine Learning

- What is Machine Learning
- Taxonomy of Machine Learning
- Machine Learning Techniques

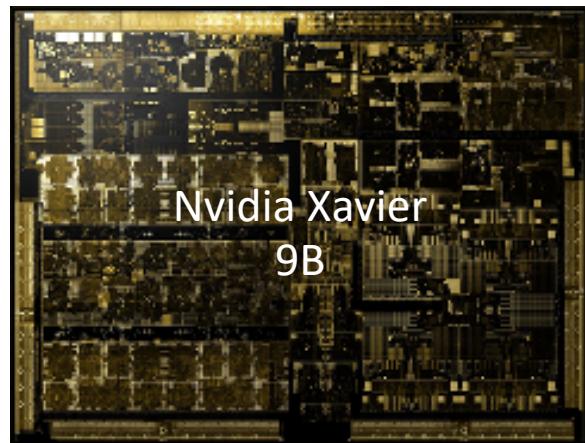
## Part II: Machine Learning for Physical Design

- Motivations
- Opportunities
- Challenges and Future Directions

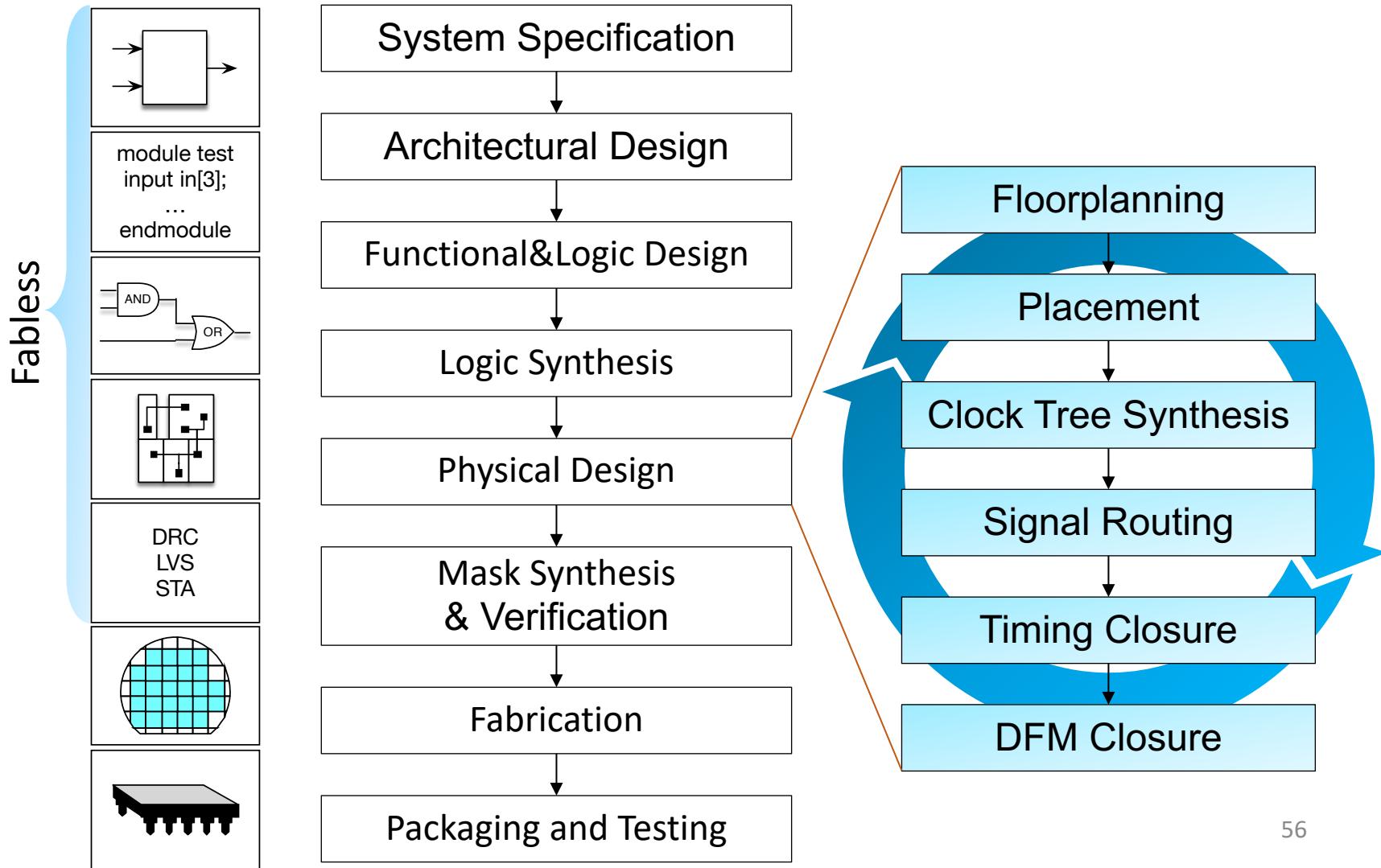
# Modern VLSI Layouts



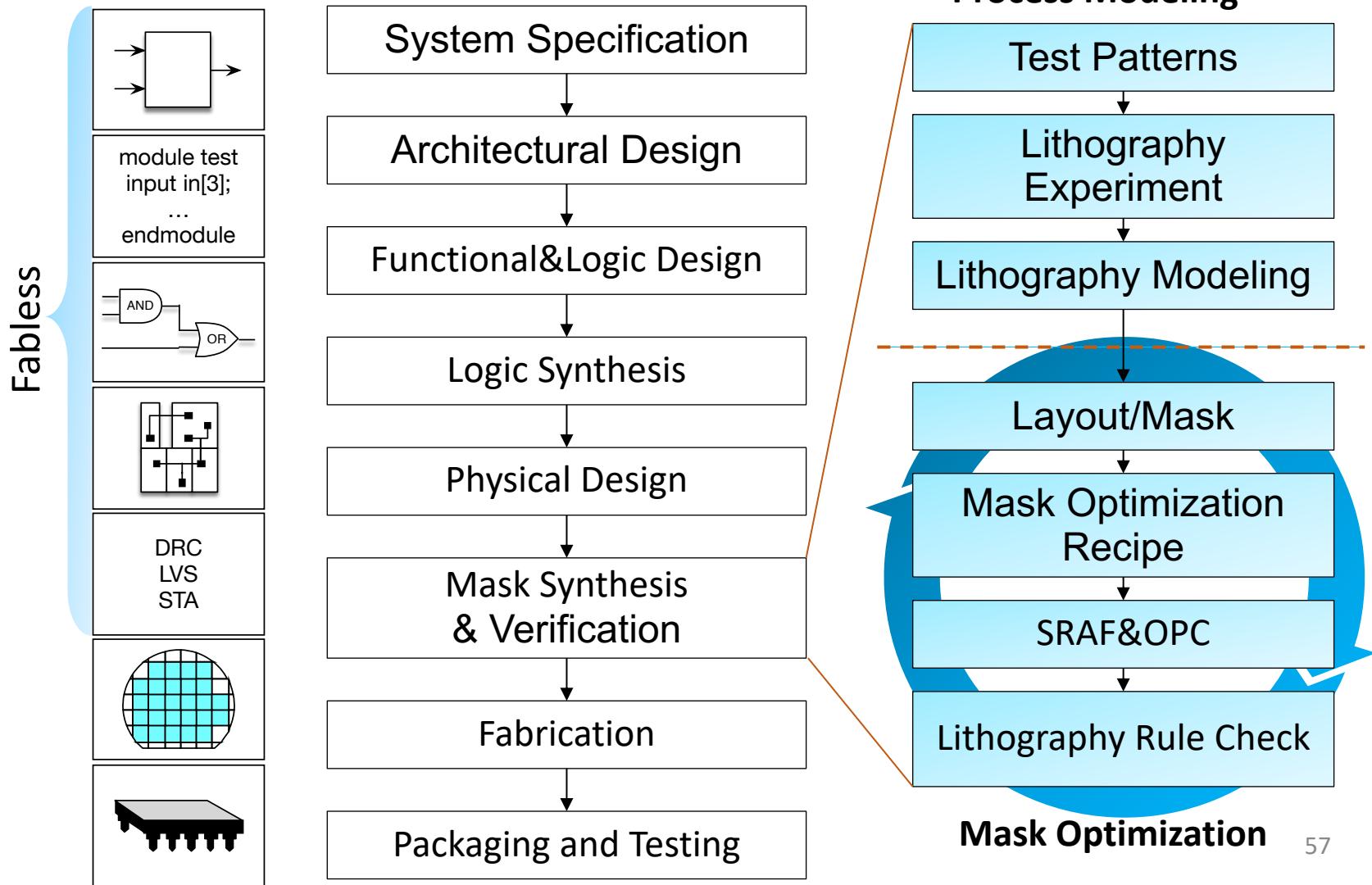
- Large scale: billions of transistors
- Complicated design flow
- Long design cycles



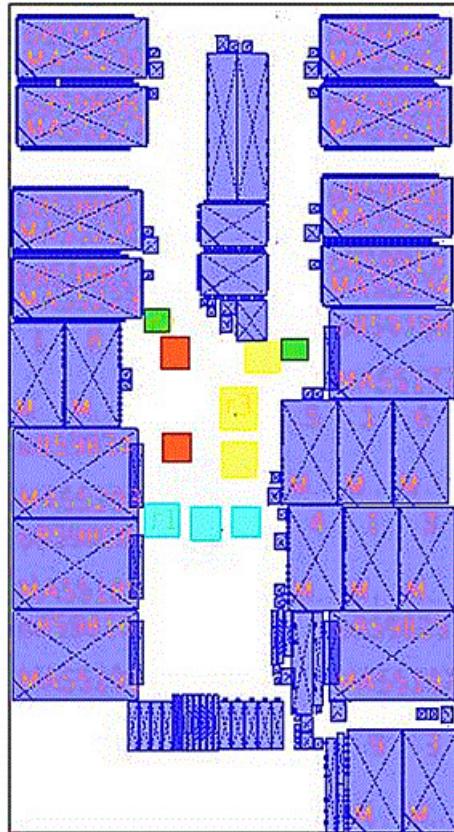
# IC Design Flow – Silicon Compiler



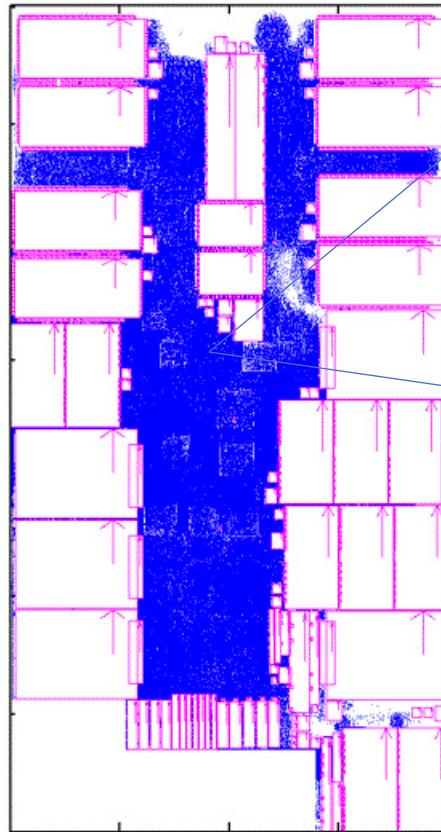
# IC Design Flow – Silicon Compiler



# Placement Example

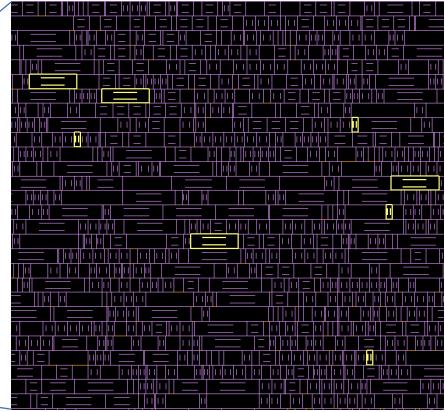


Floorplan



Placement

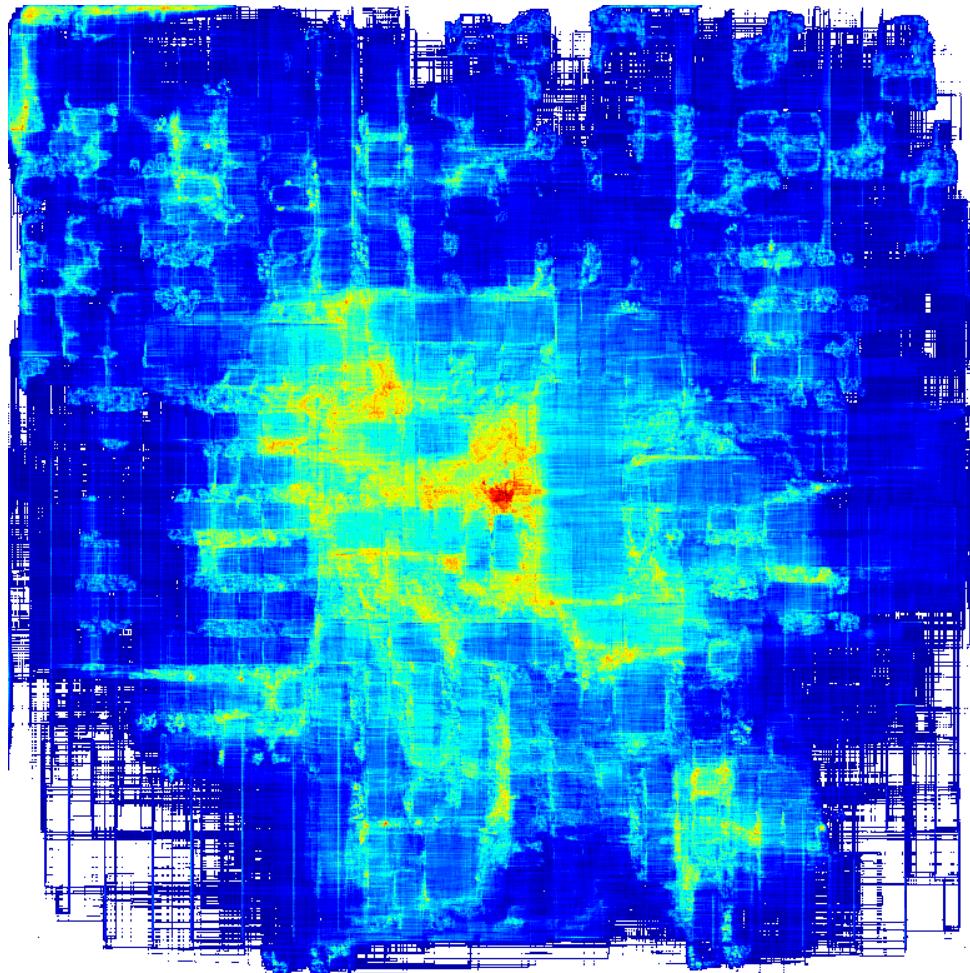
[Courtesy NTU team]



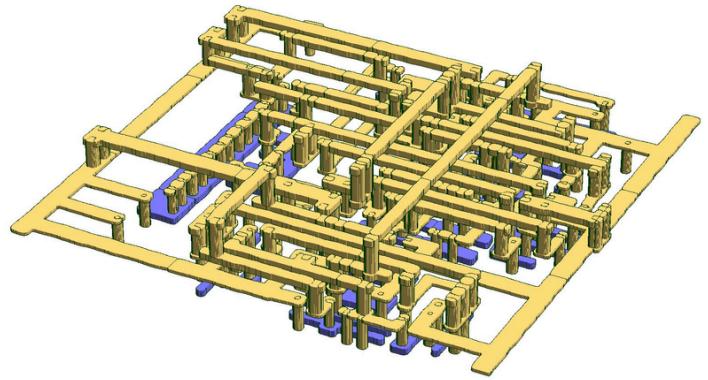
## Optimization targets

- Satisfy timing constraints?
- Satisfy power constraints?
- 100% routable?
- Wirelength minimized?
- ...

# Routing Example



[\[Courtesy Umich\]](#)

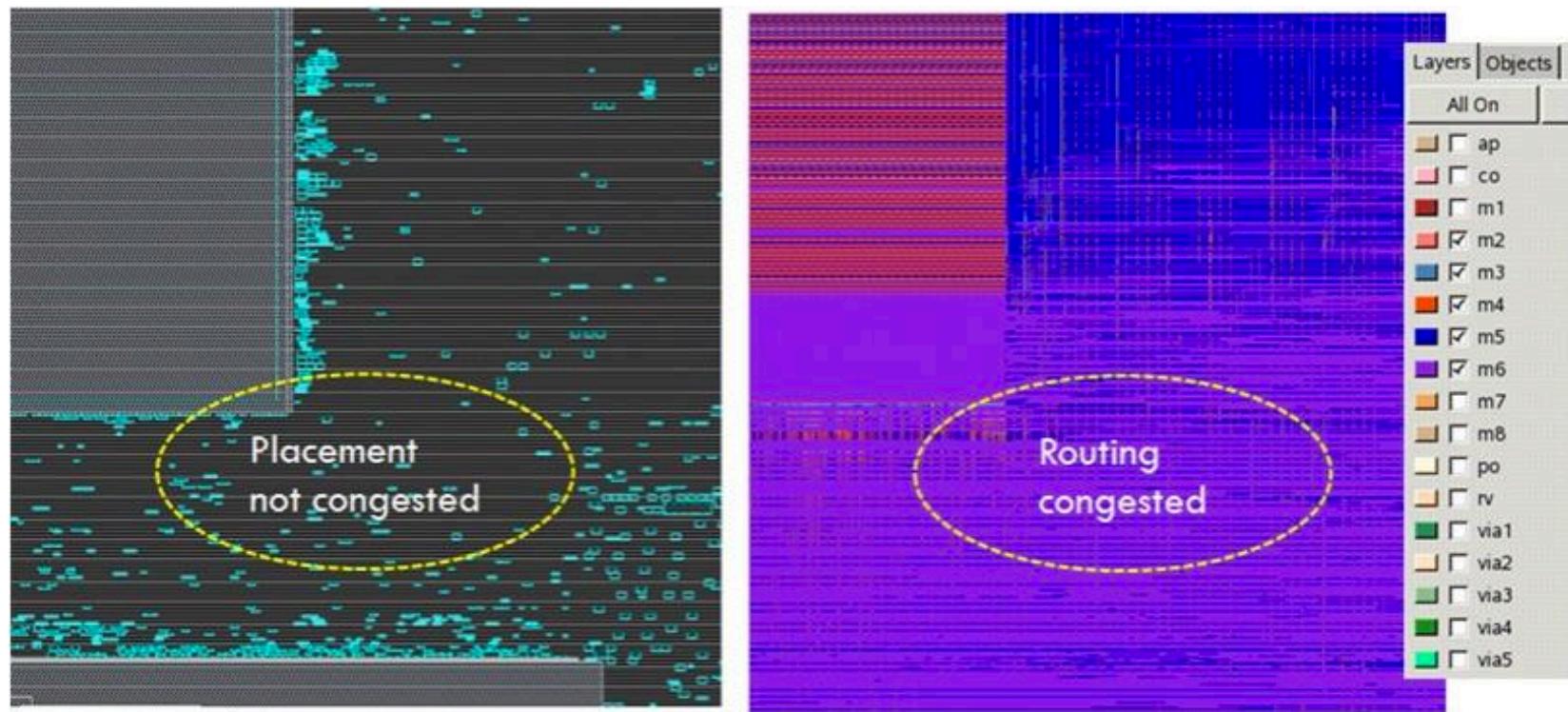


A zoom-in 3D view  
[\[courtesy samyzaf\]](#)

## Challenging problem

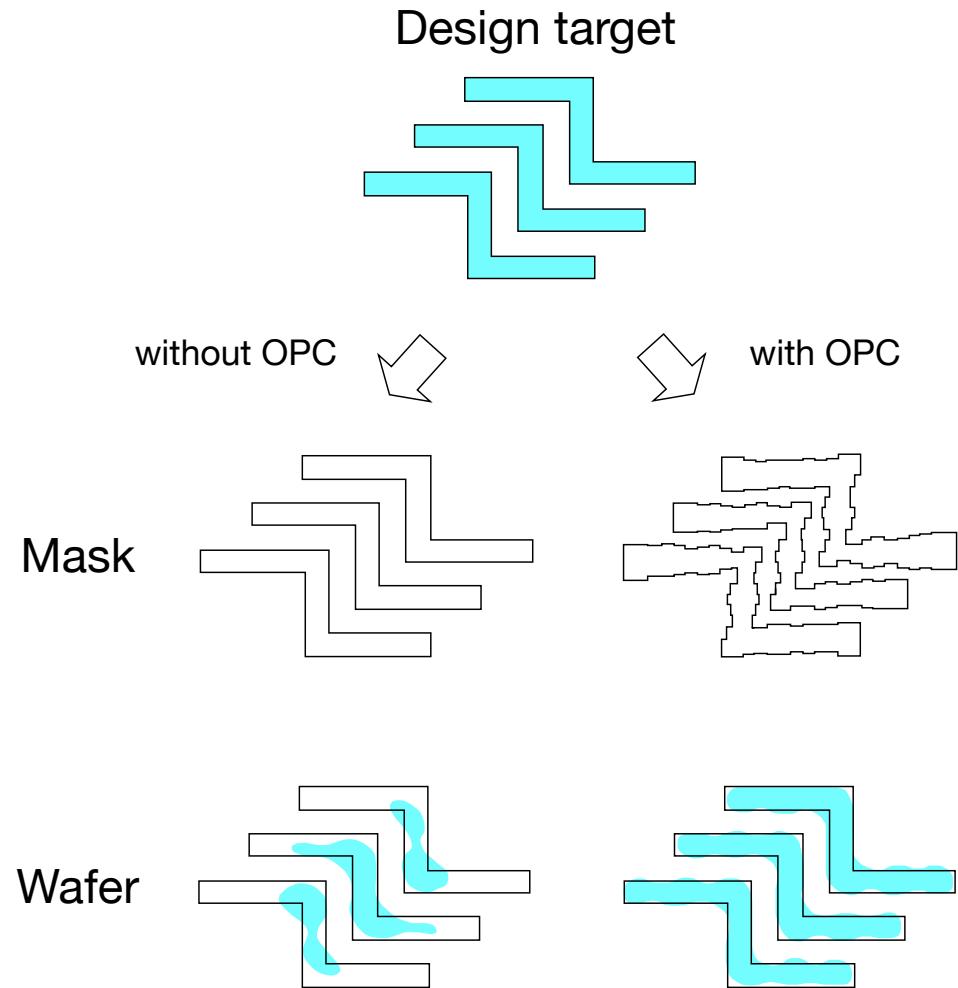
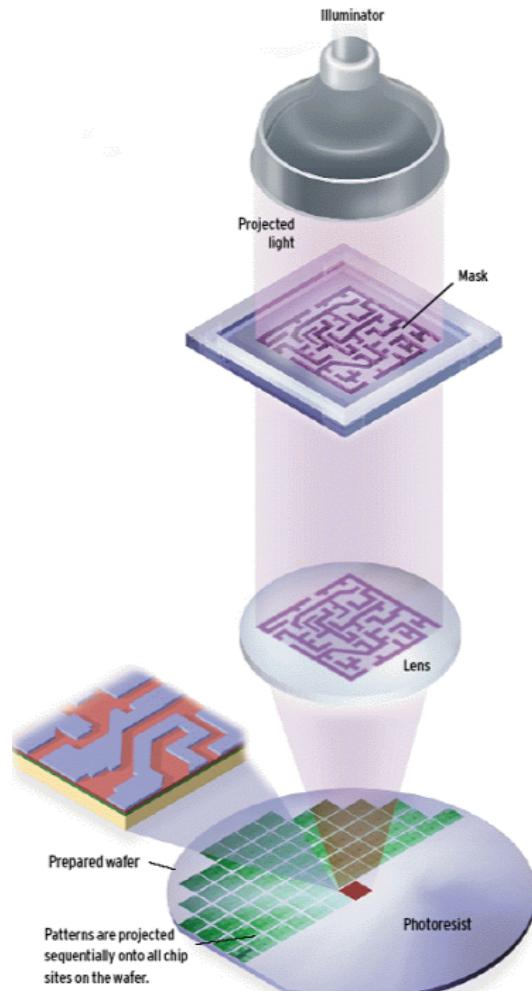
- 10+ metal layers
- Millions of nets
- May be highly congested
- Minimize wirelength

# High Correlation between P&R

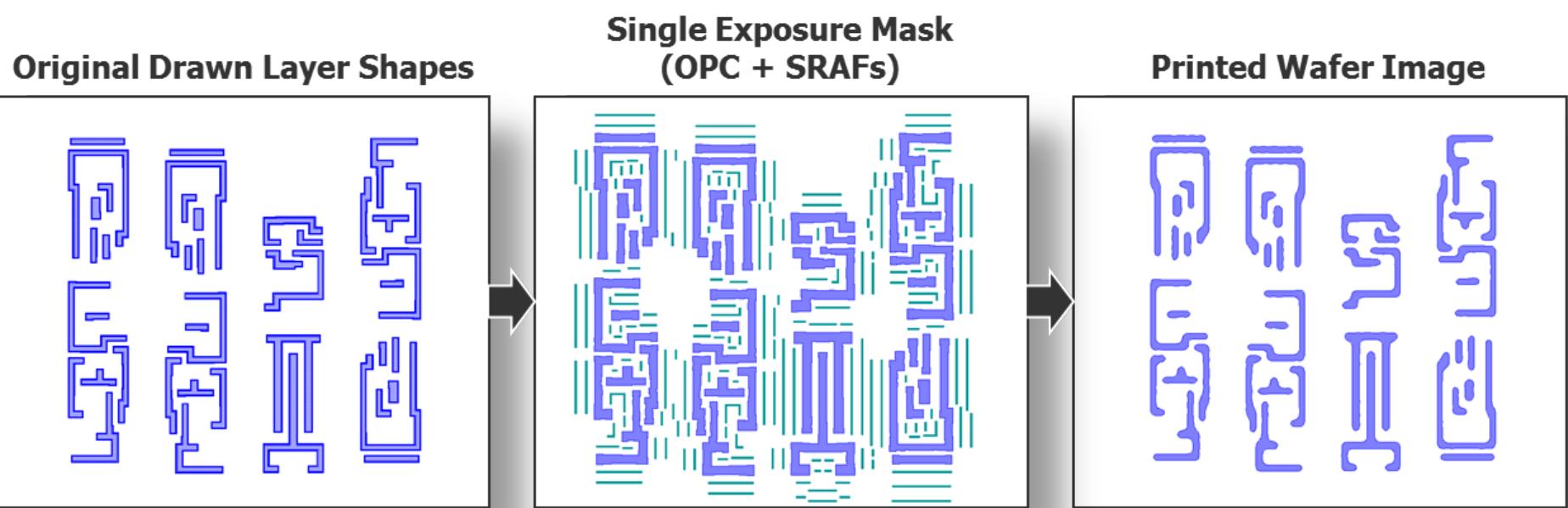


[Courtesy semiwiki](#)

# Mask Synthesis

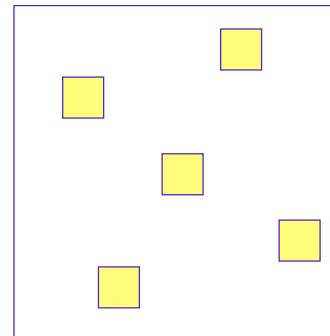
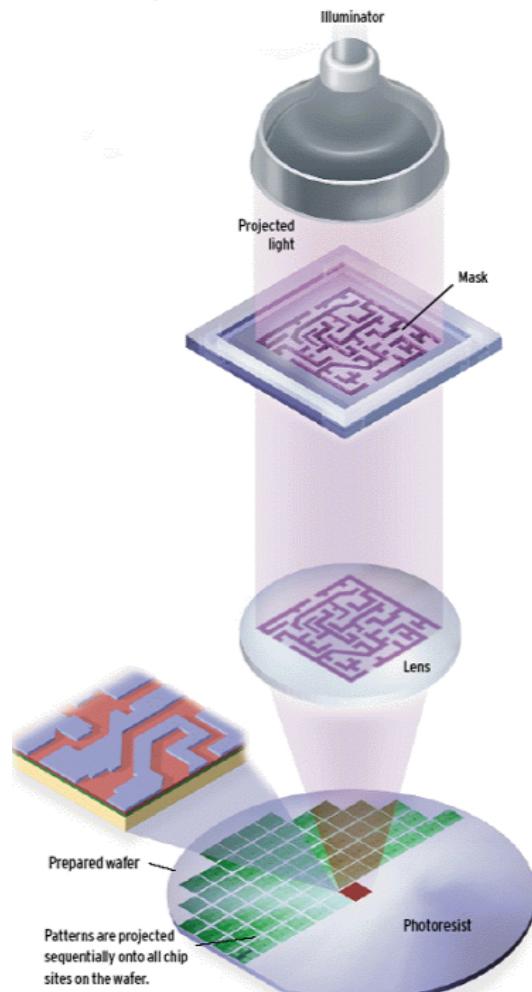


# Mask Synthesis: OPC+SRAFs

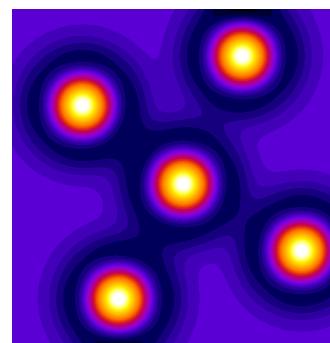


[\[Courtesy Semiengineering\]](#)

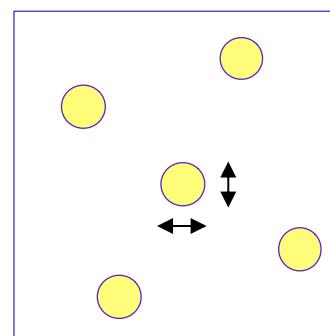
# Mask Verification: Lithography Simulation



Contact Mask

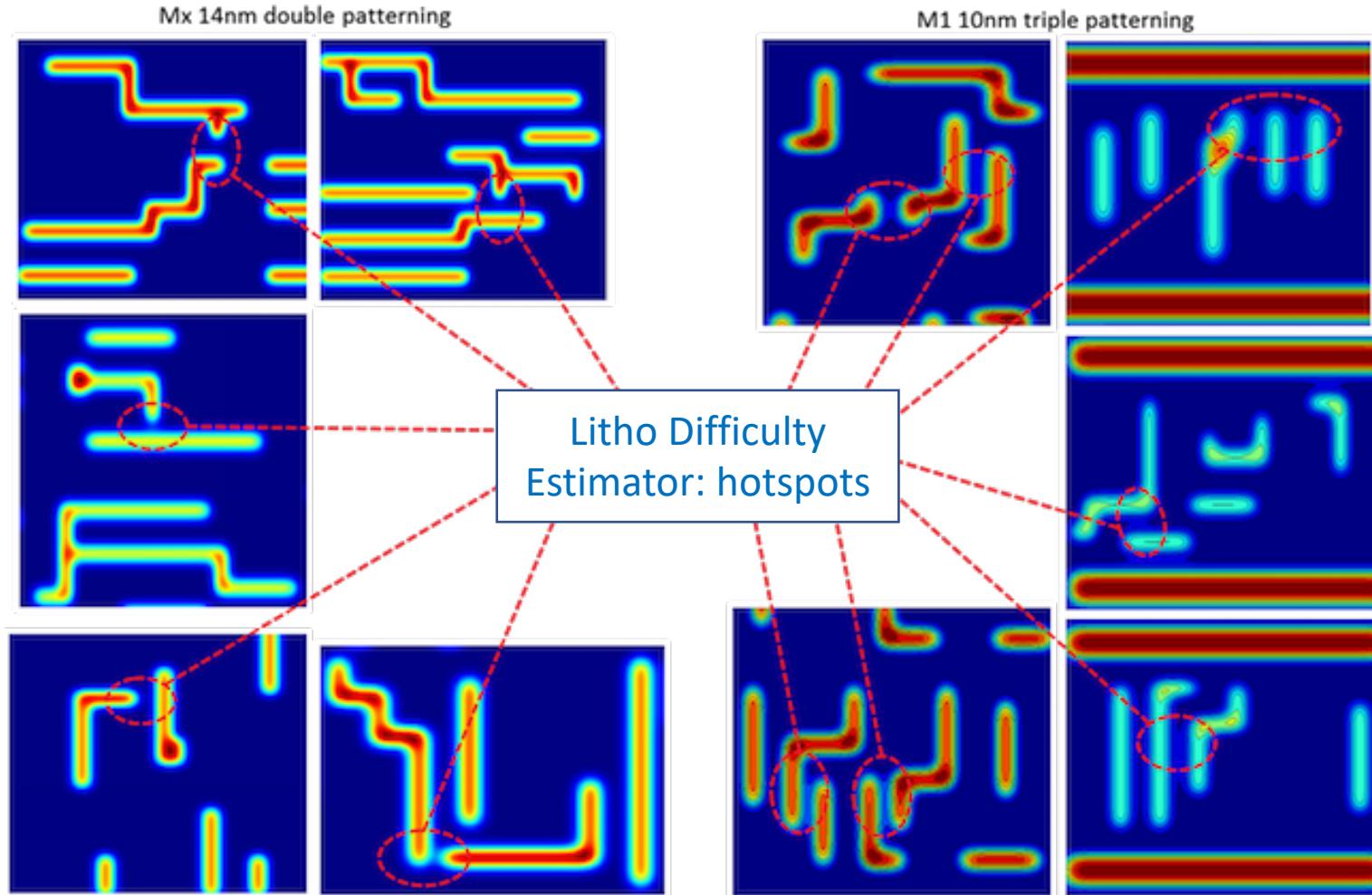


Aerial Image  
(Light intensity map)



Resist Pattern

# Mask Verification: Lithography Hotspots

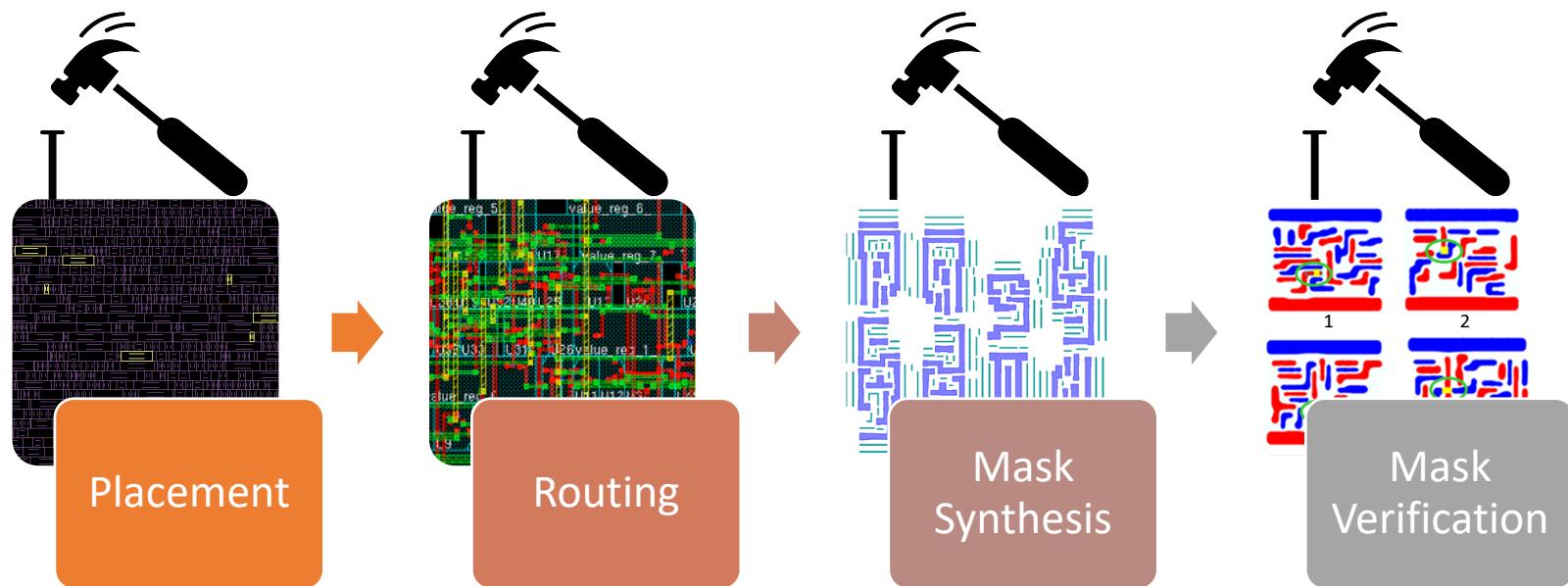


[Courtesy Tech Design Forums]

# Challenges for VLSI Design

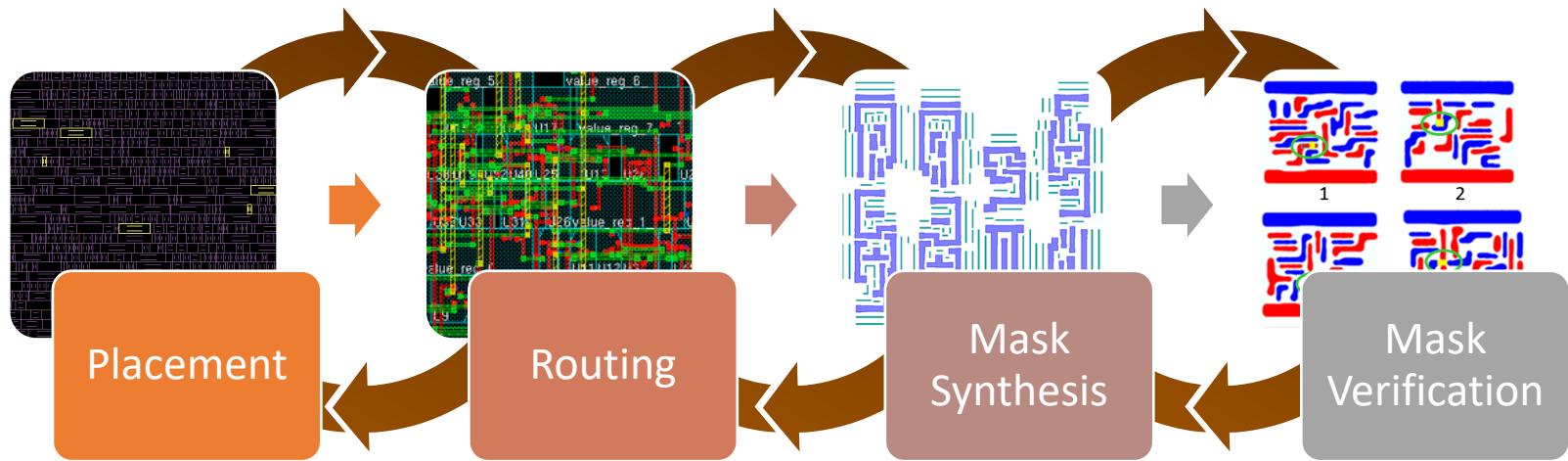
- Long and complicated design flow
- Nested chicken-egg loops
  - P&R, OPC&SRAF...
- Nearly all problems are NP-hard
- Stacking of metaheuristics
- High expectation to optimality
  - Shoot for even 1% improvement
- Single iteration is expensive
  - One iteration of backend flow may take days
- Require many iterations for convergence

# How Machine Learning Can Help



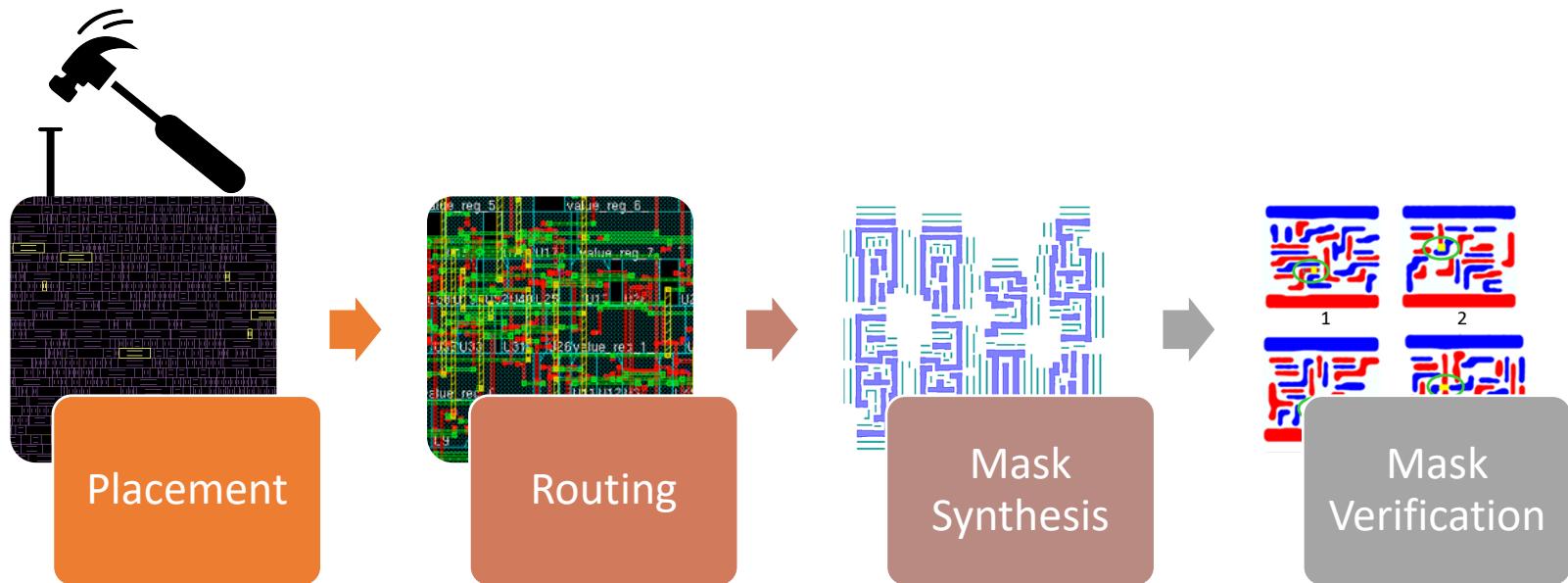
Hammers to tackle each step

# How Machine Learning Can Help



Bridges to connect each step

# Placement



# VLSI Placement

**Placement is critical to VLSI design quality and design closure**

## Input

Gate-level netlist

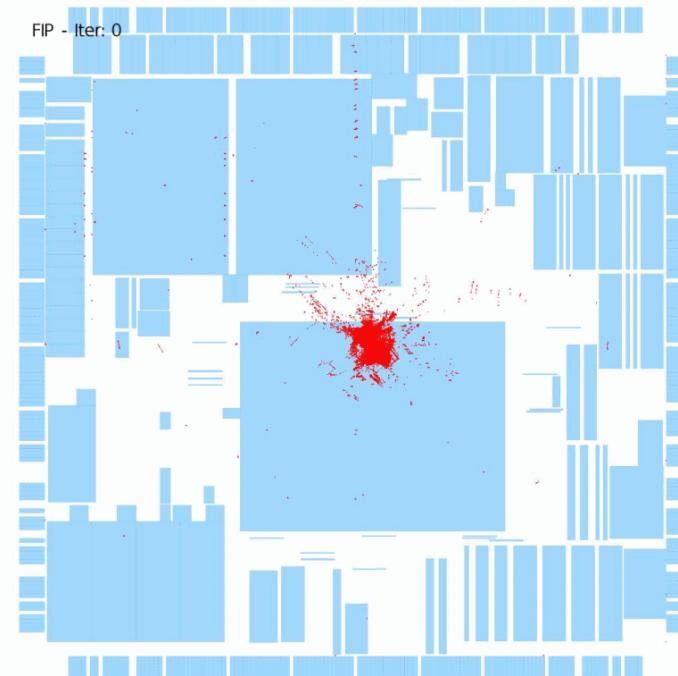
Standard cell library

## Output

Legal placement solution

## Objective

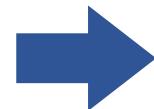
Optimize wirelength,  
routability, etc.



RePIAce

# Nonlinear Placement Algorithm

$$\begin{aligned} \min_{\mathbf{x}, \mathbf{y}} \quad & WL(\mathbf{x}, \mathbf{y}), \\ \text{s.t.} \quad & D(\mathbf{x}, \mathbf{y}) \leq t_d \end{aligned}$$



## Objective of nonlinear placement

$$\min \underbrace{\left( \sum_{e \in E} WL(e; \mathbf{x}, \mathbf{y}) \right)}_{\text{Wirelength}} + \lambda \underbrace{D(\mathbf{x}, \mathbf{y})}_{\text{Density}}$$

### Challenges of Nonlinear Placement

#### Low efficiency

- > 3h for 10M-cell design

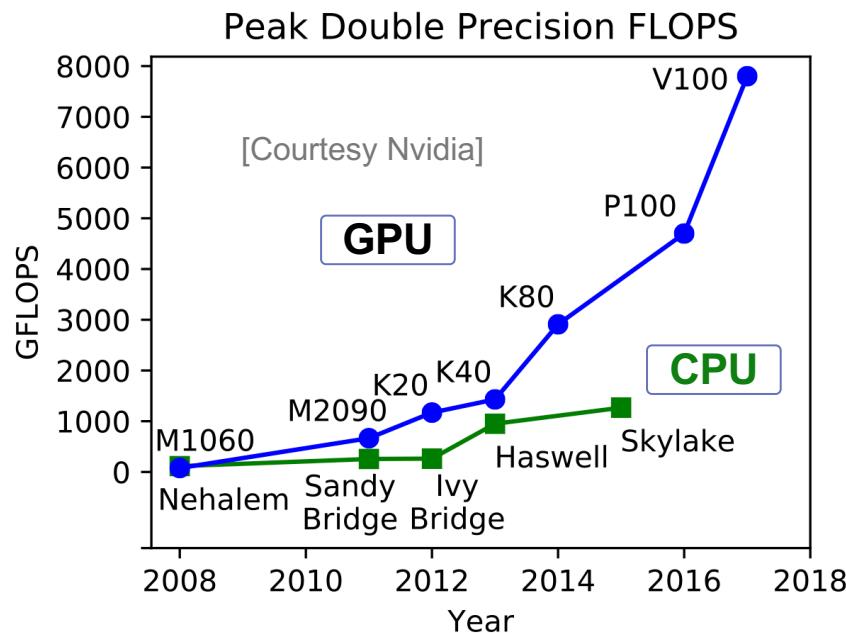
#### Limited acceleration

- Limited speedup, e.g., mPL, due to clustering

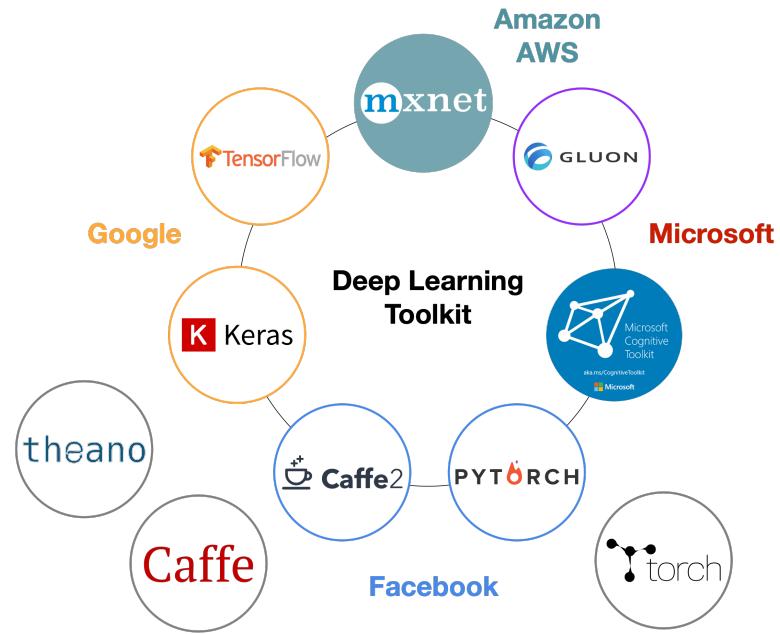
#### Huge development effort

- > 1 year for ePlace/RePIAce

# Advances in Deep Learning Hardware/Software



Over **60x** speedup in neural network training since 2013



Deep learning toolkits

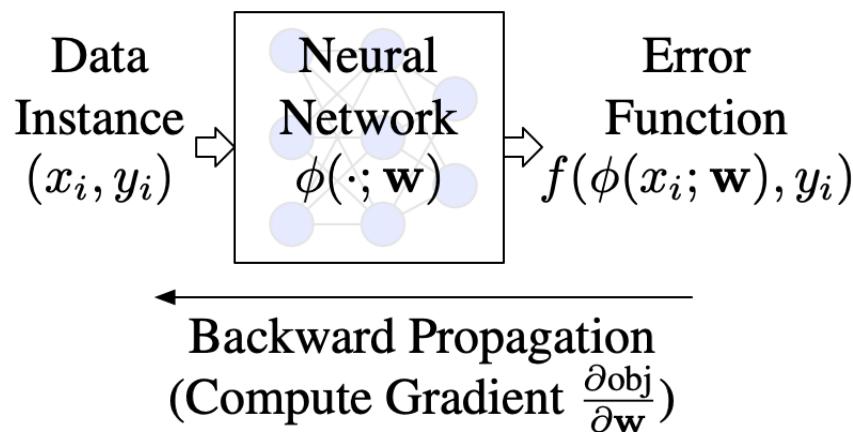
# DREAMPlace Strategies

- We propose a novel **analogy** by casting the nonlinear placement optimization into a neural network training problem
- Greatly leverage deep learning hardware (GPU) and software toolkit (e.g., PyTorch)
- Enable ultra-high parallelism and acceleration while getting the state-of-the-art results

# Analogy between NN Training and Placement

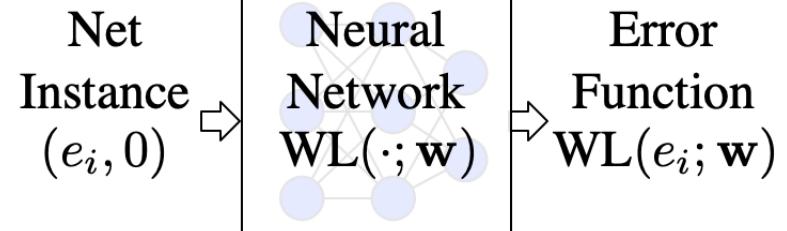
$$\min_{\mathbf{w}} \sum_i^n f(\phi(x_i; \mathbf{w}), y_i) + \lambda R(\mathbf{w})$$

Forward Propagation  
(Compute obj)



Train a neural network

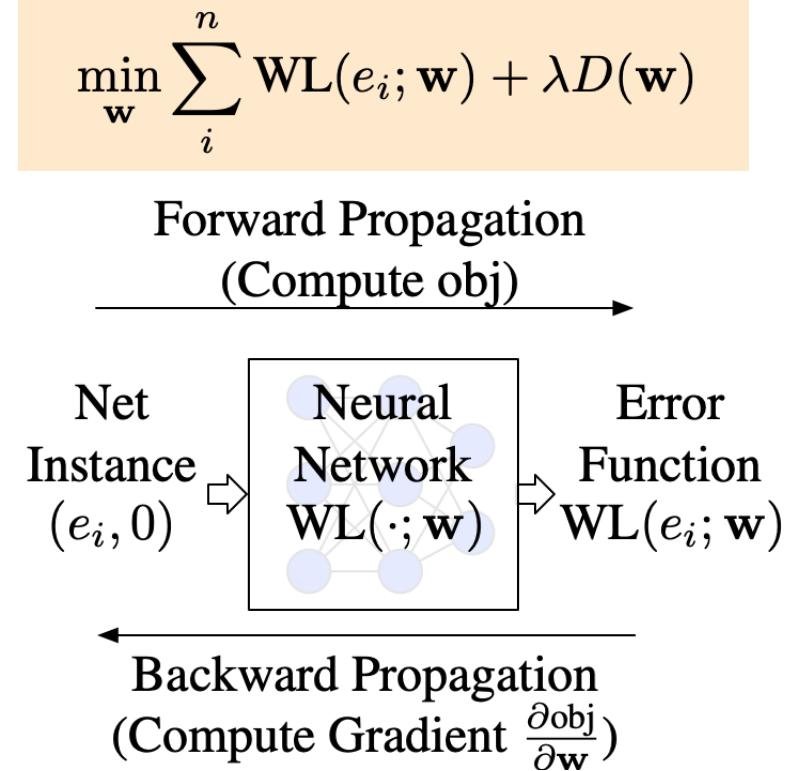
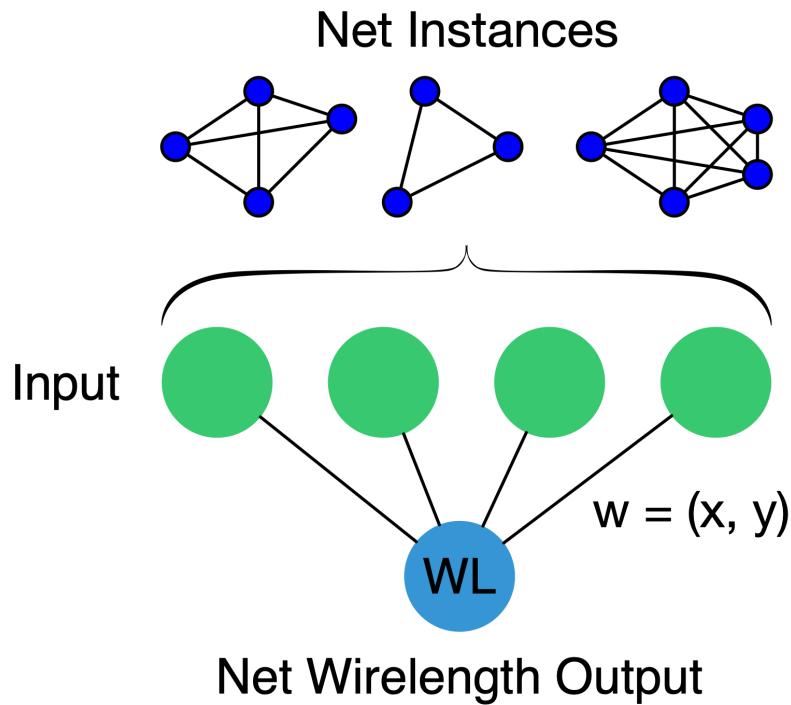
$$\min_{\mathbf{w}} \sum_i^n \text{WL}(e_i; \mathbf{w}) + \lambda D(\mathbf{w})$$



Solve a placement

# Analogy between NN Training and Placement

Casting the placement problem into neural network training



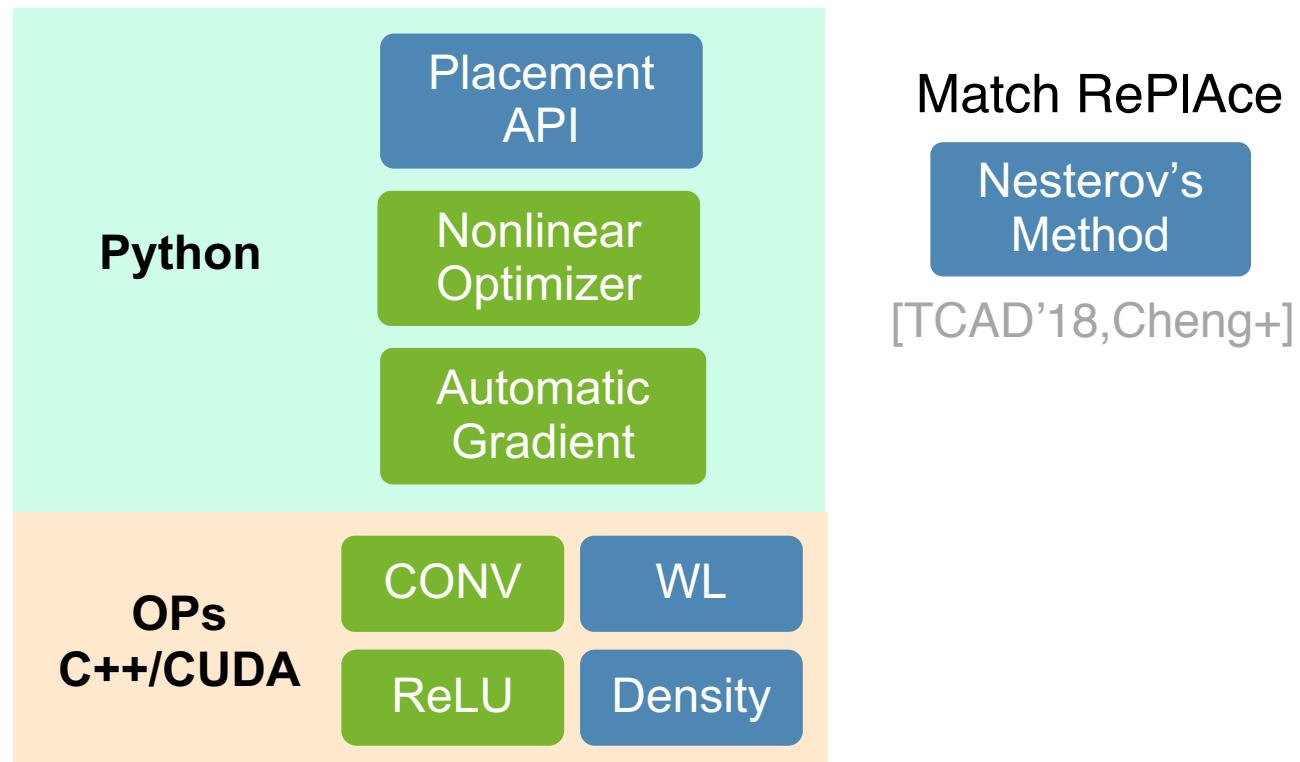
Train a neural network



Solve a placement

# DREAMPlace Architecture

Leverage highly optimized deep learning toolkit PyTorch



# Experimental Results

## DREAMPlace

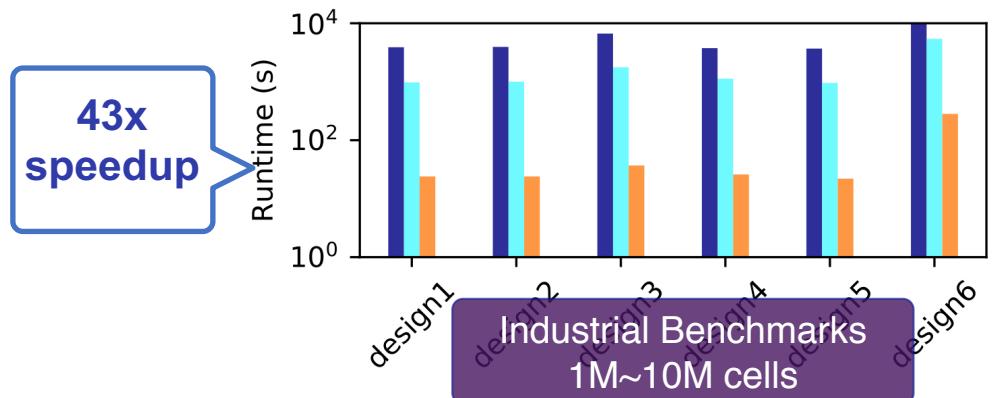
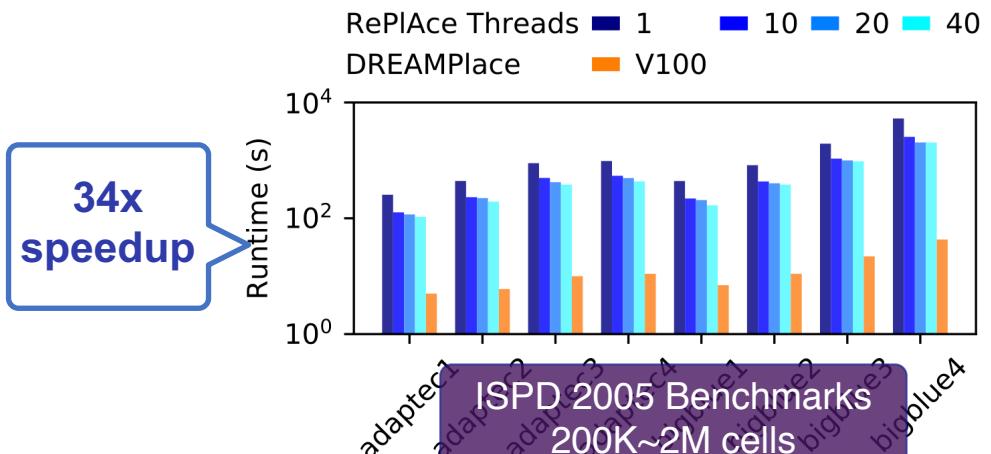
- CPU: Intel E5-2698 v4 @ 2.20GHz
- GPU: 1 NVIDIA Tesla V100
- Single CPU thread was used

## RePIAce [TCAD'18, Cheng+]

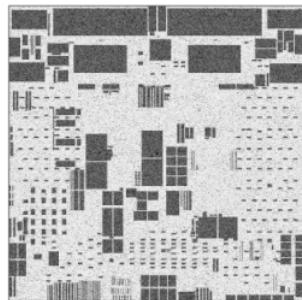
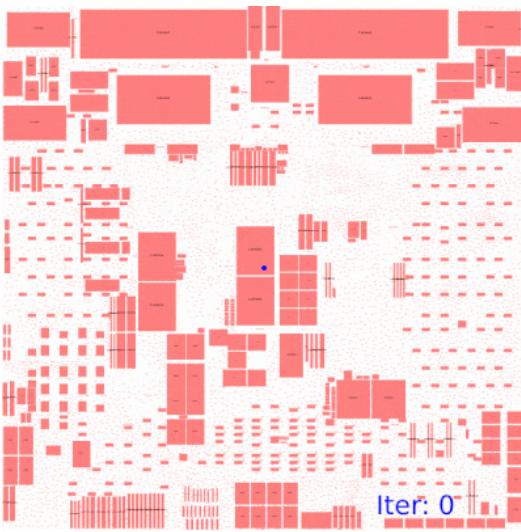
- CPU: 24-core 3.0 GHz Intel Xeon
- 64GB memory allocated

Same quality of results!

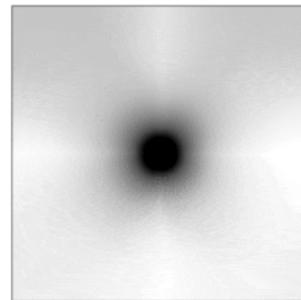
10M-cell design  
finishes within **5min** c.f. 3h



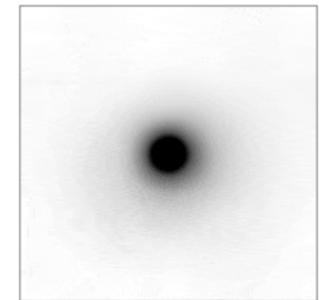
# Bigblue4 (2M-Cell Design)



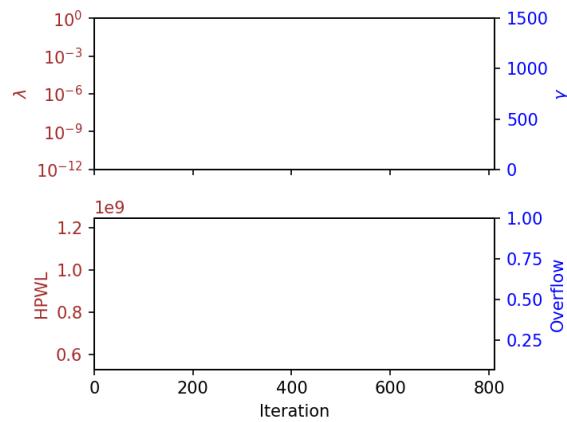
Density Map



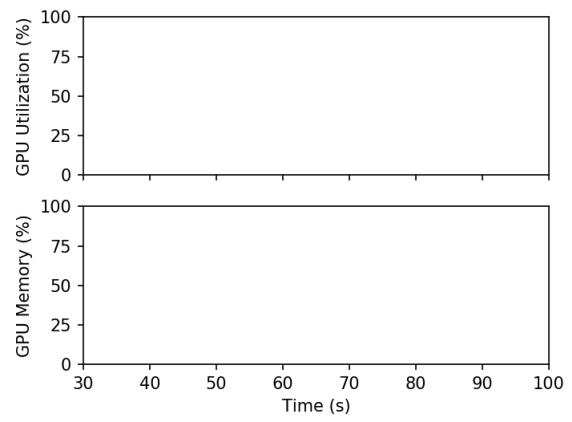
Potential Map



Field Map



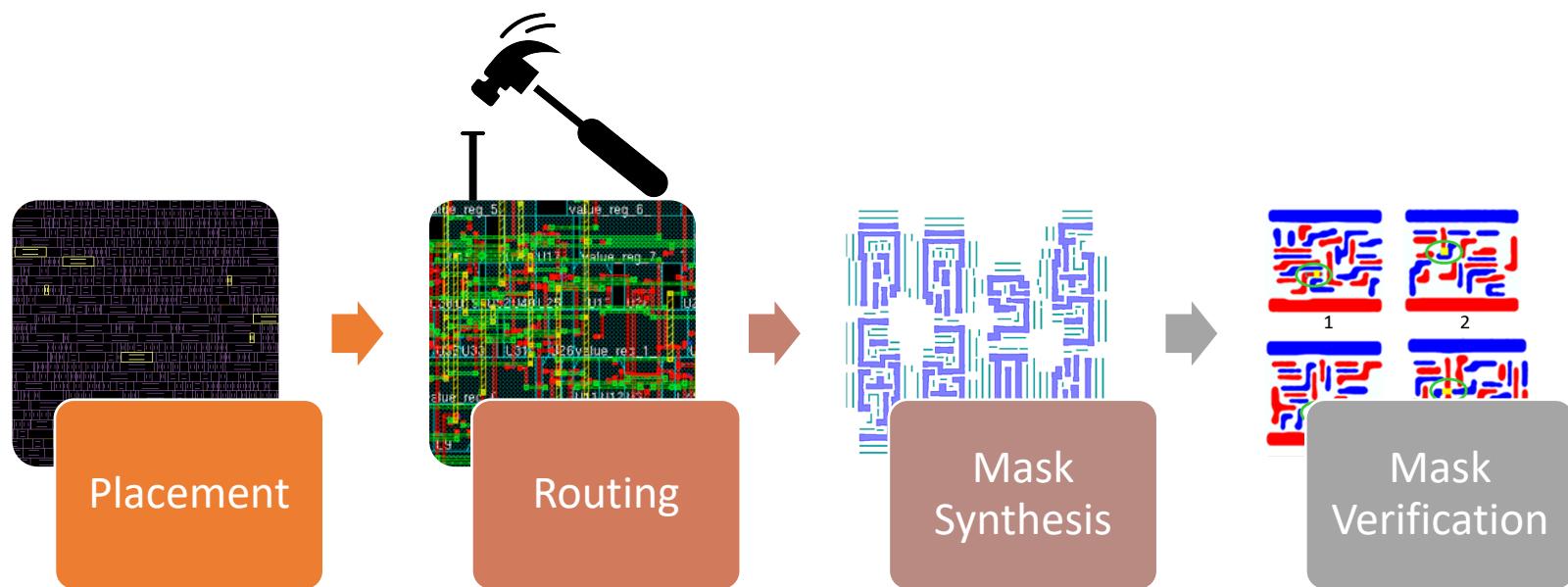
Placement Metrics



GPU Usage on Titan Xp

Code release: <https://github.com/limbo018/DREAMPlace>

# Routing



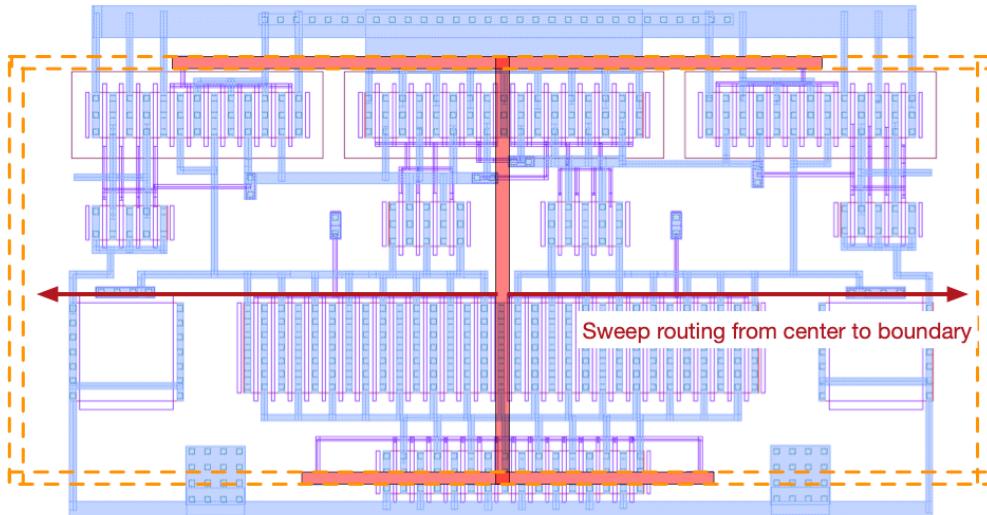
# Routing Guidance: GeniusRoute

Routing for analog circuits, e.g., comparator

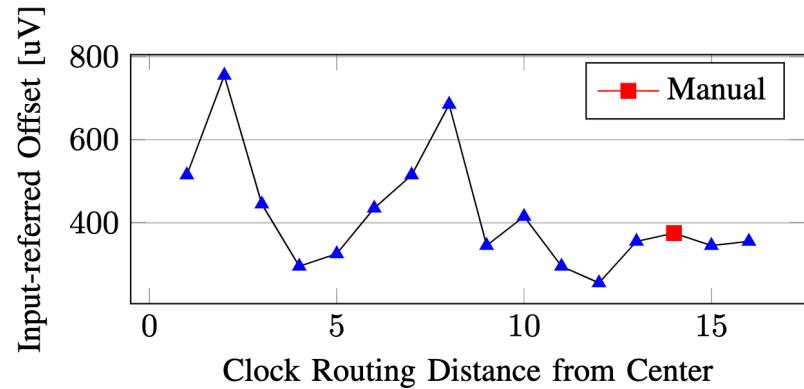
- Sensitive performance to clock routing

Existing manual layouts

- Hard to encode designer expertise into rules



Sweep the routing of the clock net



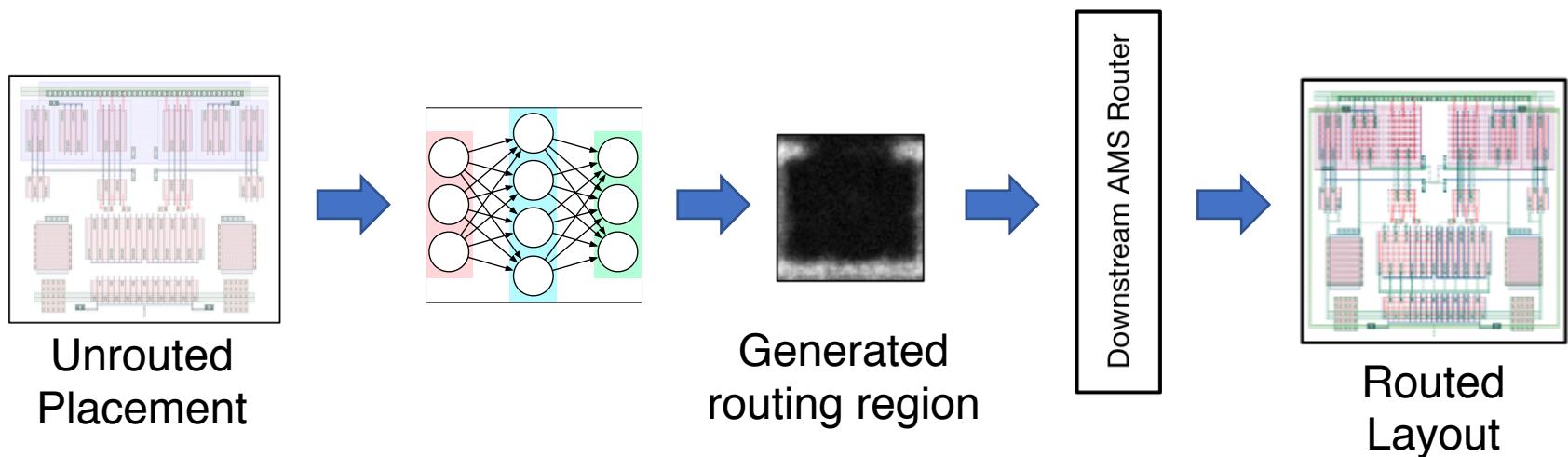
# Routing Guidance: GeniusRoute

Learn from manual layouts

- Encode designer expertise into neural networks!

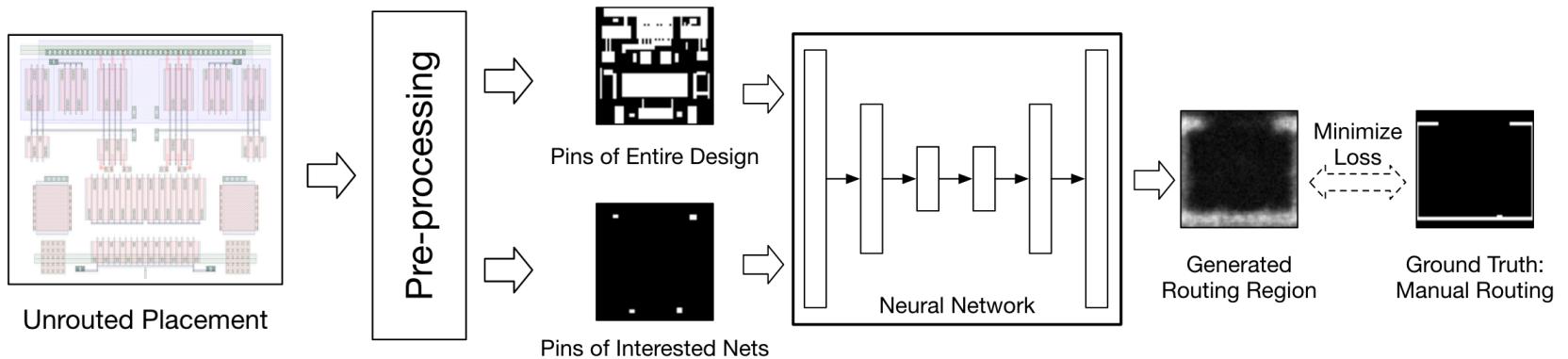
Generate routing guidance for critical nets

- Clock, power/ground, critical signal nets
- Probability map of routing



# Routing Guidance: GeniusRoute

- Adopt autoencoder for routing region generation
- Compare with routing from manual layouts

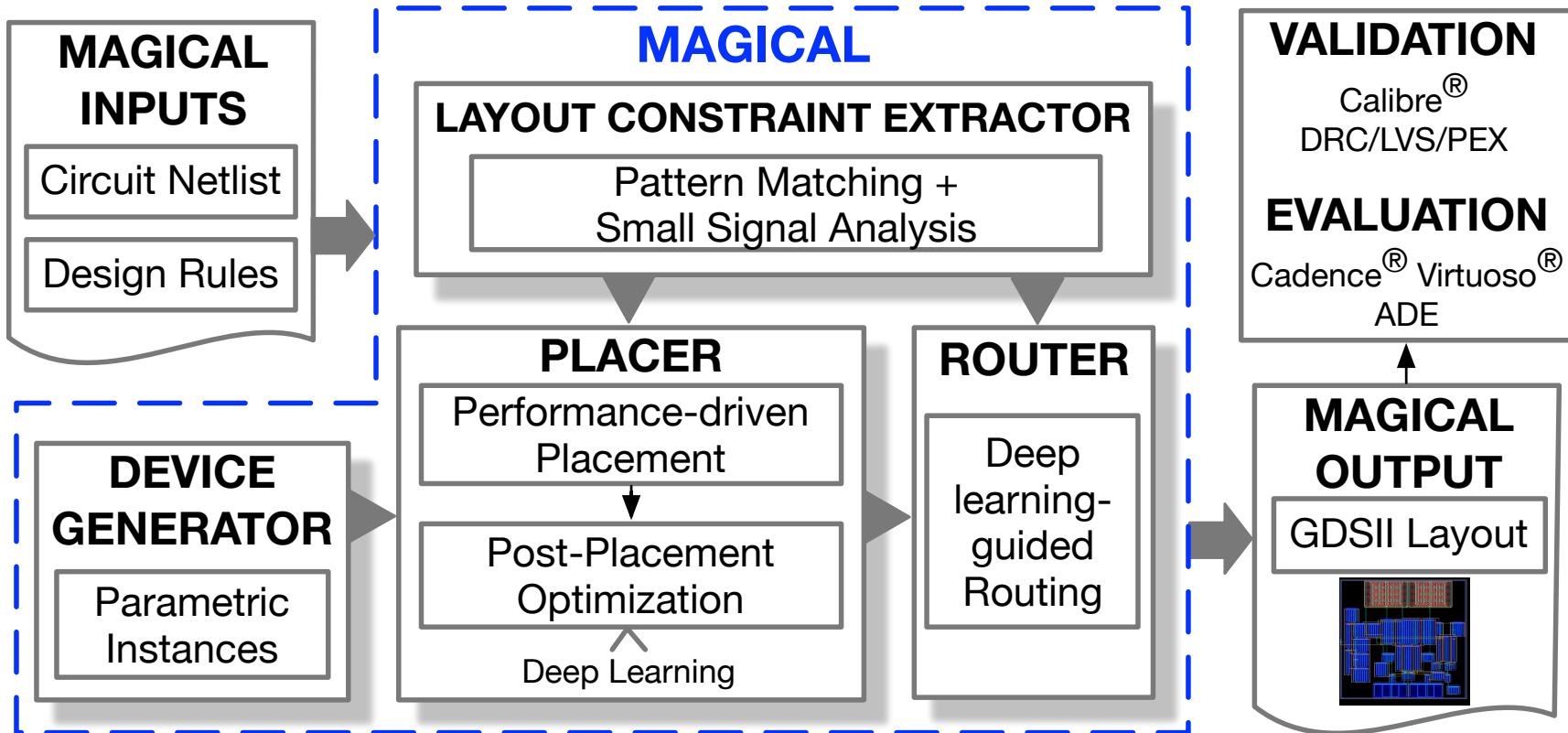


# Routing Guidance: GeniusRoute

- Test on comparators and OTAs
- Evaluate with post layout simulation
- Compare with manual layout and previous methods

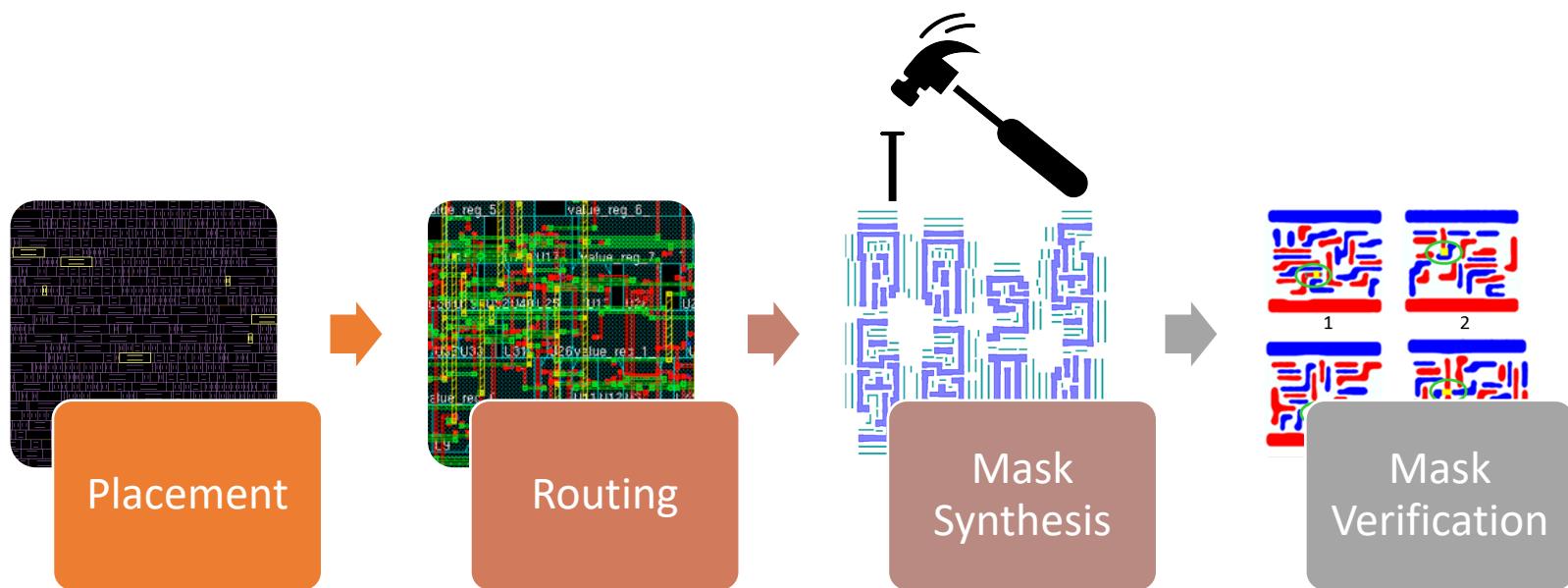
	Schematic	Manual	ICCAD'10	W/o guide	GeniusRoute
Offset ( $\mu\text{V}$ )	/	480	1230	2530	<b>830</b>
Delay (ps)	102	170	180	164	<b>163</b>
Noise ( $\mu\text{V}_{\text{rms}}$ )	439.8	406.6	437.7	439.7	<b>420.7</b>
Power ( $\mu\text{W}$ )	13.45	16.98	17.19	16.82	<b>16.80</b>

Closest results to the manual layout

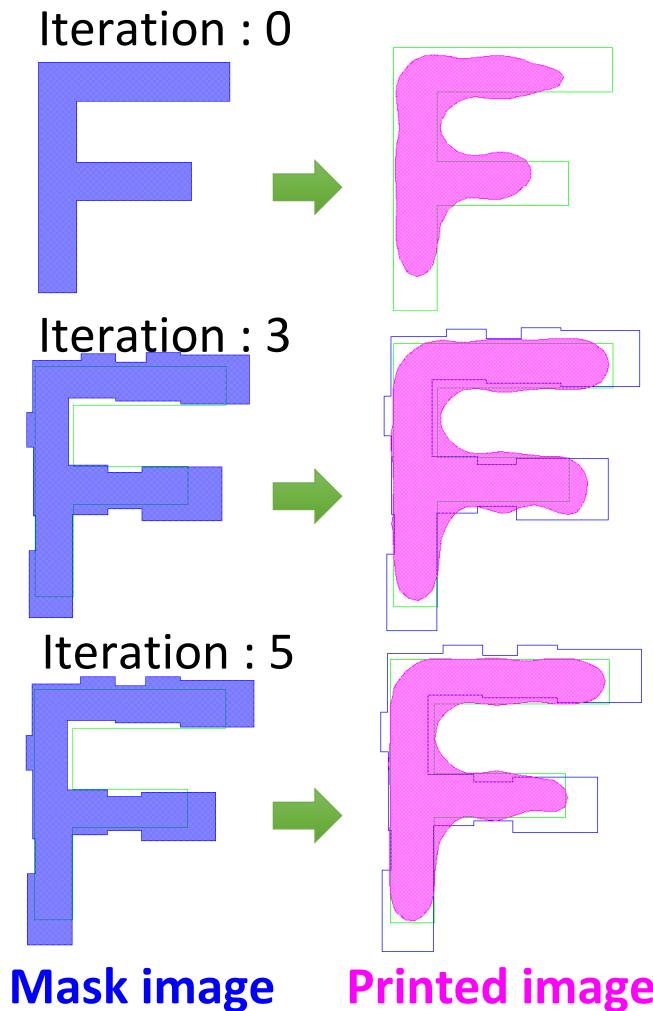


- MAGICAL 0.2 Version Open-source released in May 2019
- GitHub: <https://github.com/magical-eda/MAGICAL>
  - **End-to-end** analog layout generation from netlist to GDSII
  - **No dependency** on commercial tools
  - **Push-button, no-human-in-the-loop**

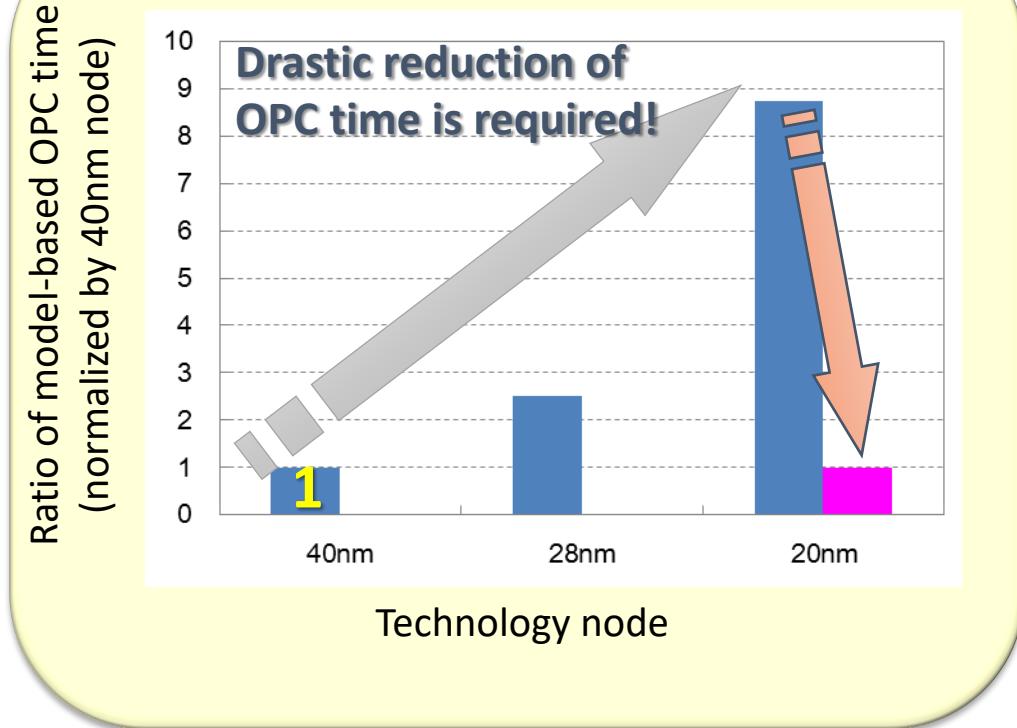
# Mask Synthesis



# Optical Proximity Correction



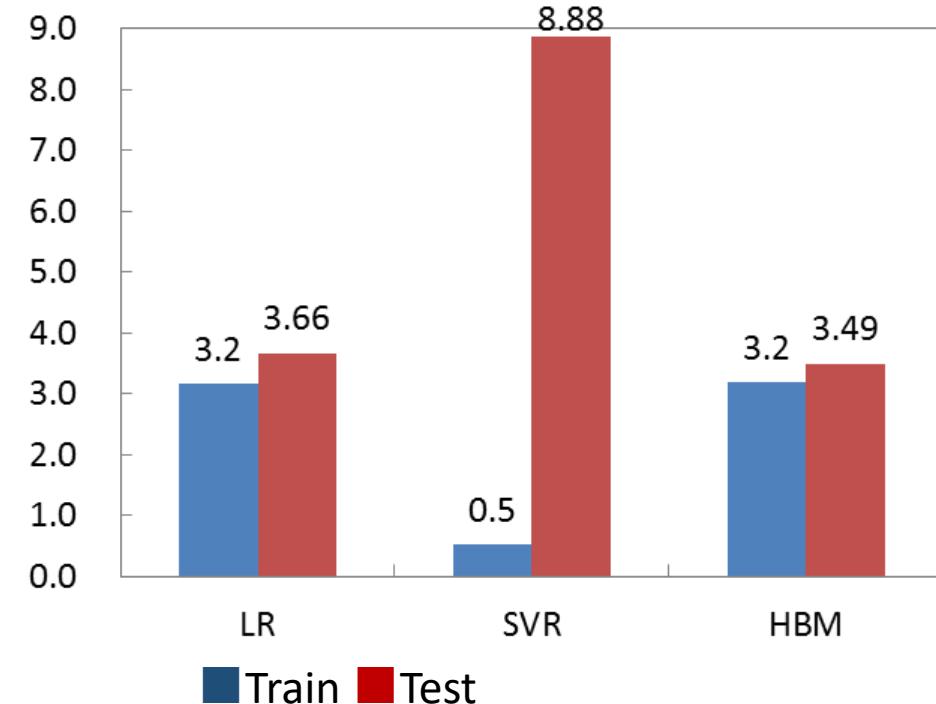
Issue: Conventional OPC consumes very long time  
Goal: High accurate correction in shorter runtime



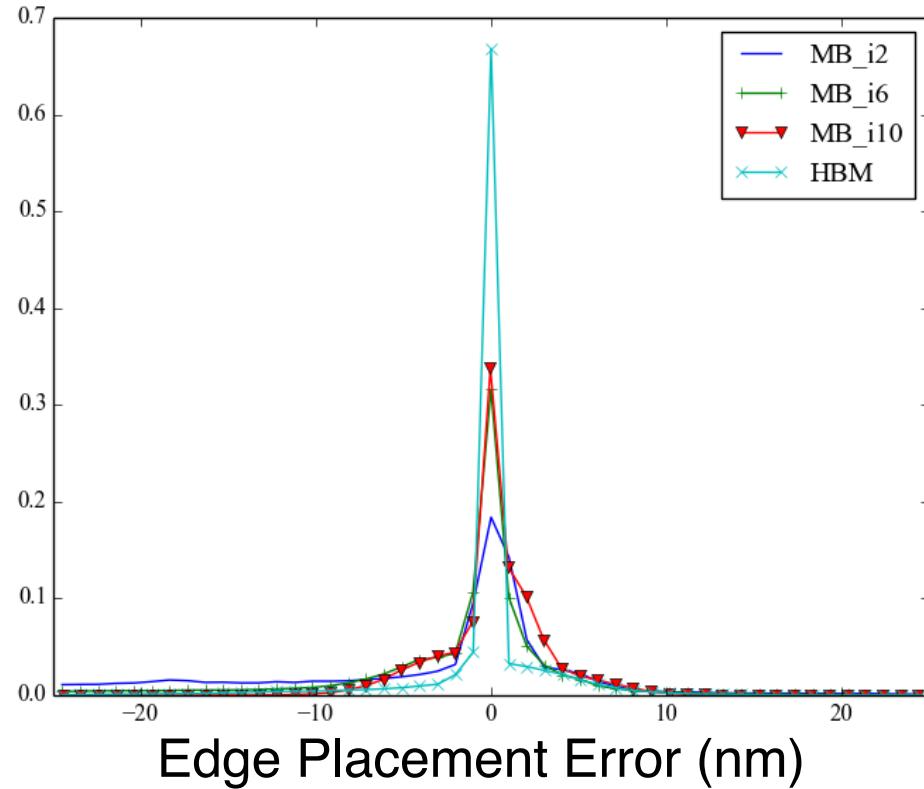
Model-based OPC is the most widely used technique

# Results on HBM-based OPC

RMSE (nm)  
(Root mean square error)



Compare with model-based OPC  
@iteration 2, 6, 10



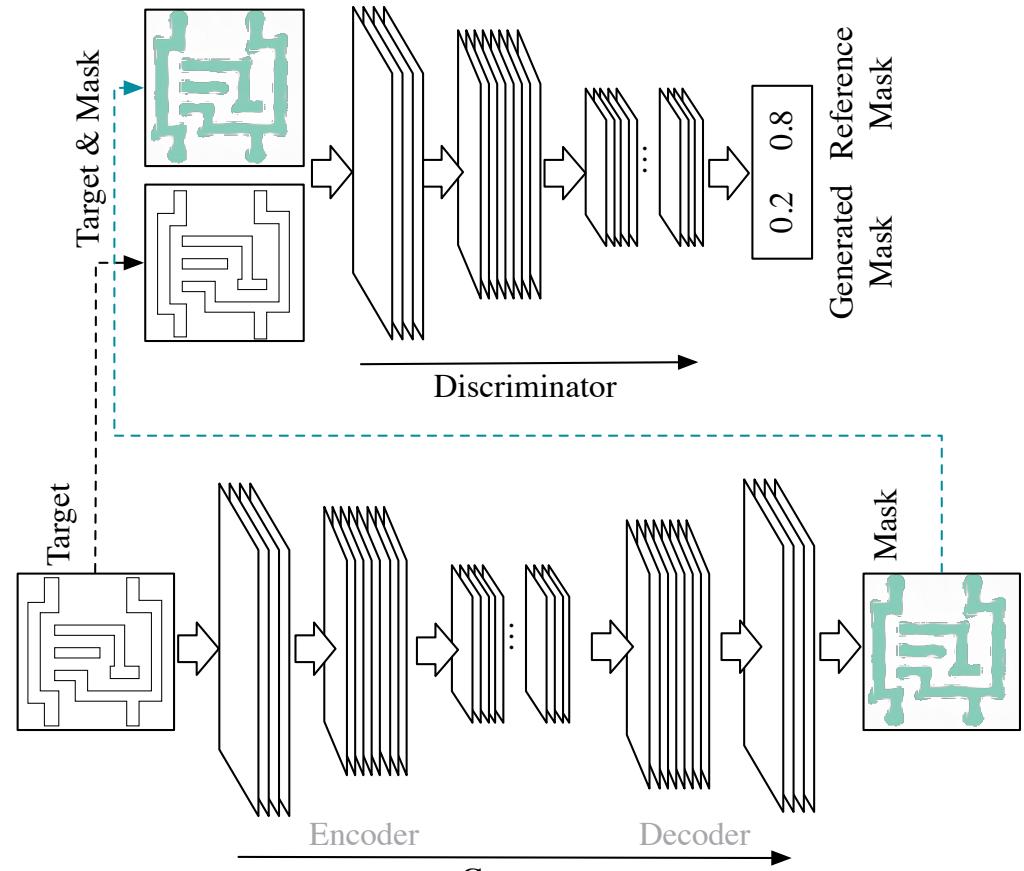
The number of iterations of model-based OPC can be reduced **by 2x**

[\[Matsunawa+, SPIE'15\]](#)

# GAN for OPC

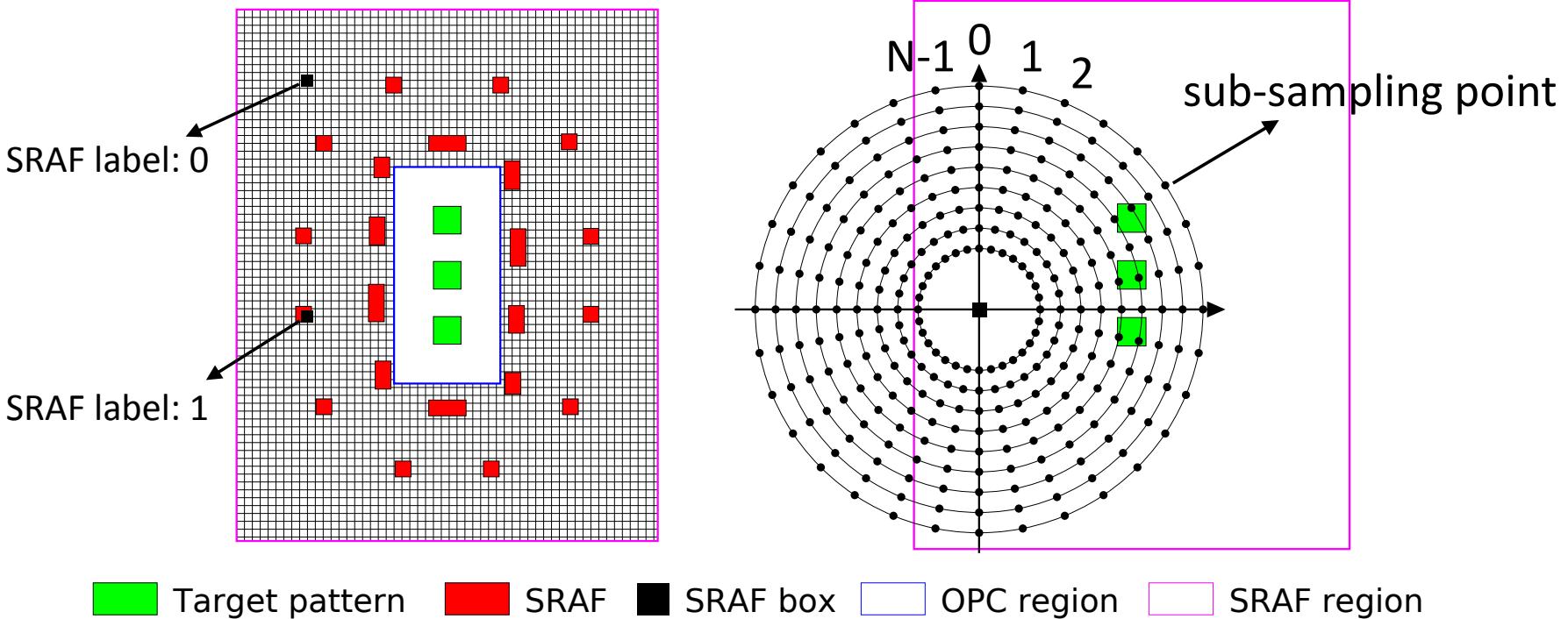
- Generative adversarial networks for OPC
  - [\[Yang+, DAC'18\]](#)

Compared with ILT flow  
EPE error: 9% reduction  
PV-band: 1% reduction  
Overall runtime: 2x less



# SRAF Insertion

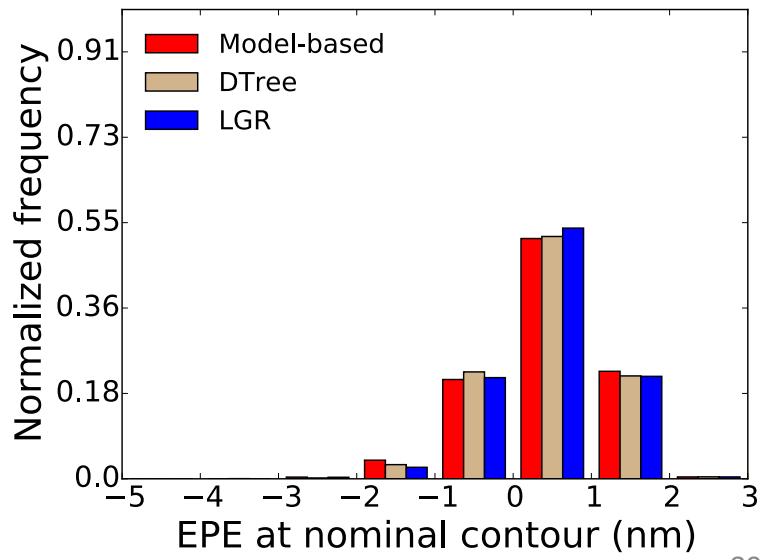
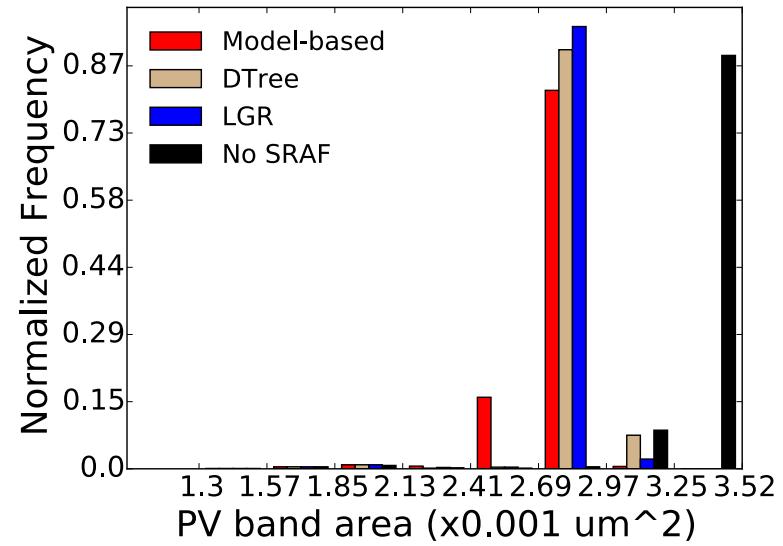
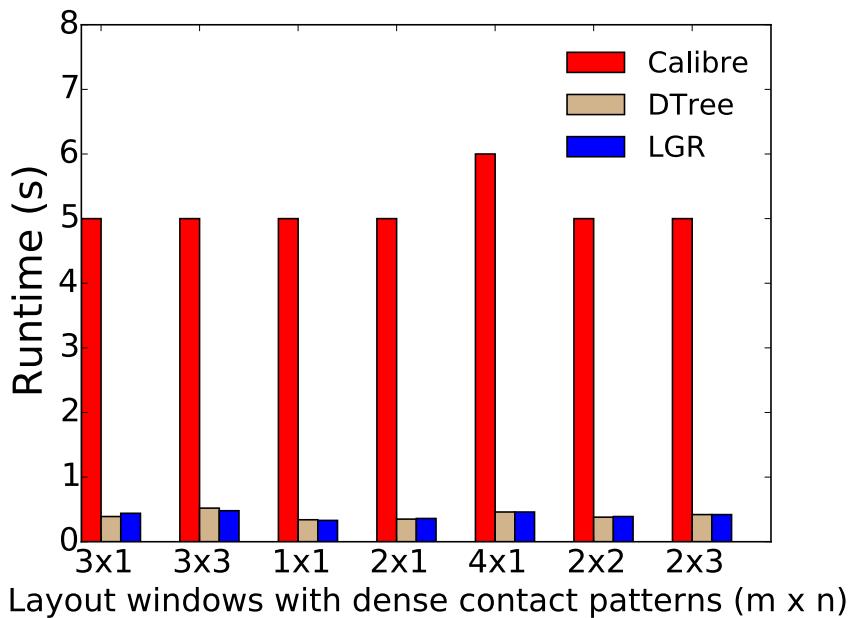
- SRAF (sub-resolution assist feature) insertion
- ML-based approach achieved similar result but 10x faster



# Comparison with Model-based SRAF

- Similar PV band and EPE
- But 10x faster

**Can we do better?!**



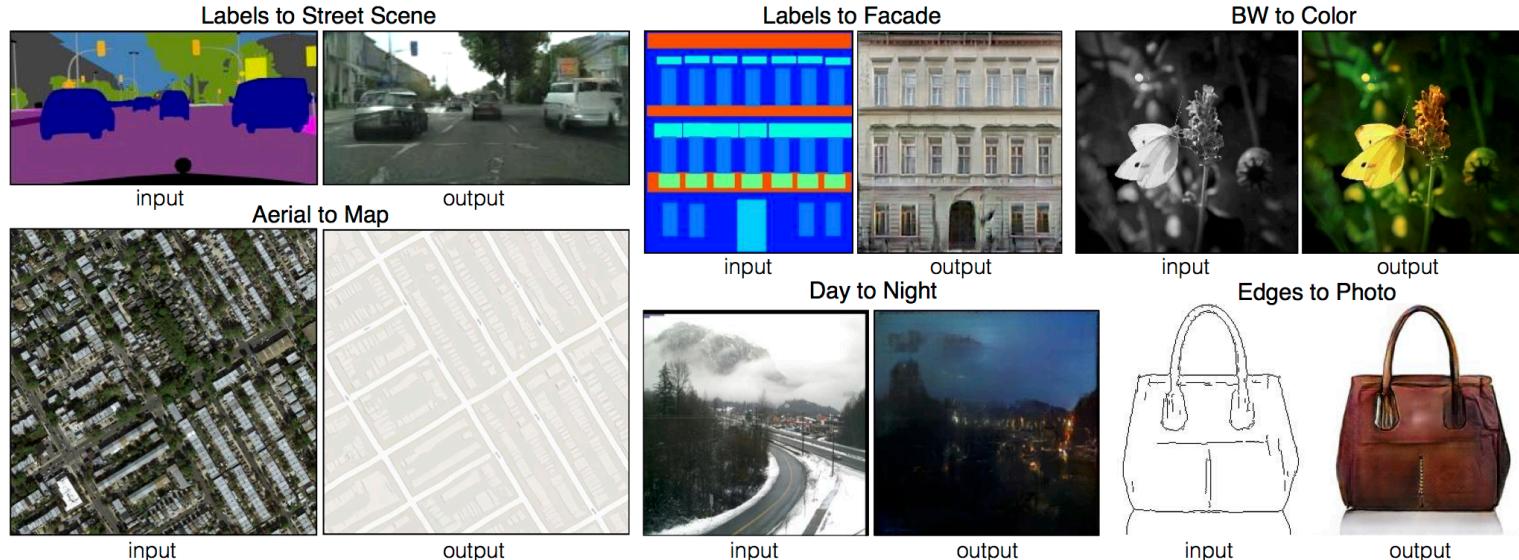
# Image Translation with Generative Adversarial Networks

Generative Adversarial Network (GAN) [\[Goodfellow+, 2014\]](#)

- Two neural networks contest (generator and discriminator)
- Produces images similar to those in the training data set

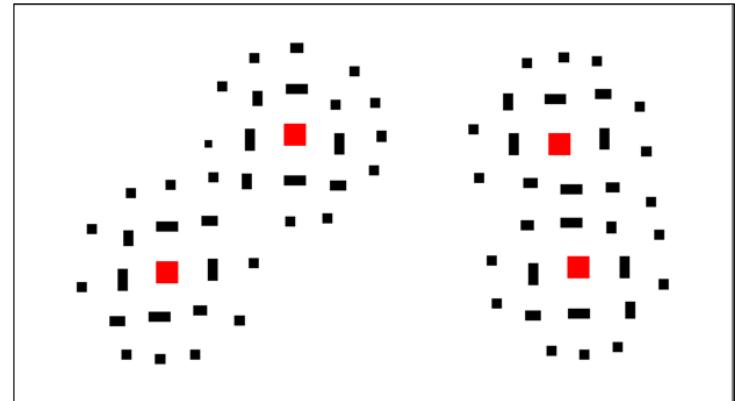
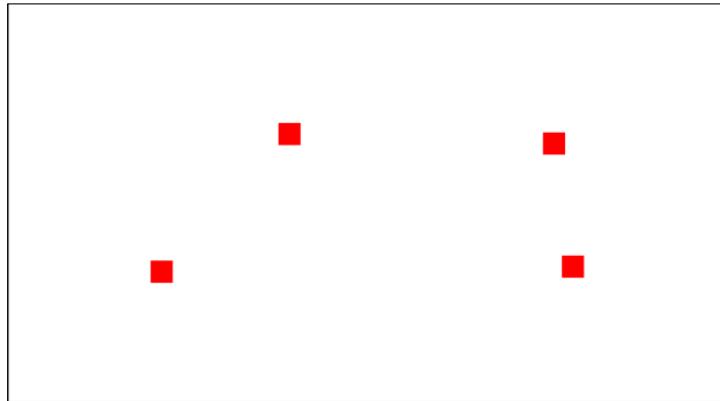
Conditional GAN (CGAN) for Image Translation [\[Isola+, CVPR'17\]](#)

- Takes an image in one domain and translate it to another one



# SRAF Insertion & Image Translation

- What does SRAF generation have to do with Image translation?!



■ Target Pattern ■ SRAF

- Can we define the problem as translating images from the Target Domain ( $D_T$ ) to the SRAF Domain ( $D_S$ )?

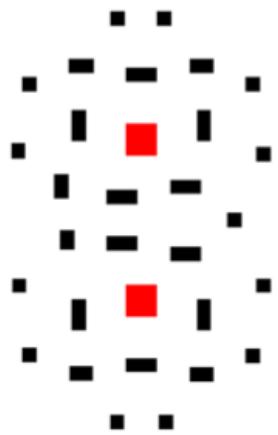
# Challenges for SRAF Insertion

- Layout images have sharp edges which pose a challenge to GANs
  - No guaranteed to generate polygon SRAF shapes
  - Sharp edges can complicate gradient propagation
- Generated images need ultimately be changed to layout format
  - Images cannot be directly mapped to ‘GDS’ format
  - Post-processing step should not be time consuming
- *Hence, a proper **encoding** is needed to address these challenges!*

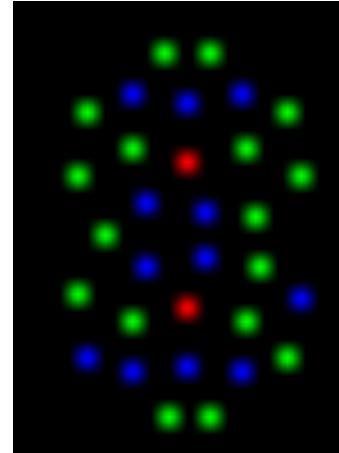
# Multi-Channel Heatmap Encoding

Key Idea: encode each type of object on a separate channel in the image

- Channel index carries object description (type, size,...)
- Excitations on the channel carry objects location



Original Layout



Encoded Layout

# CGAN Approach

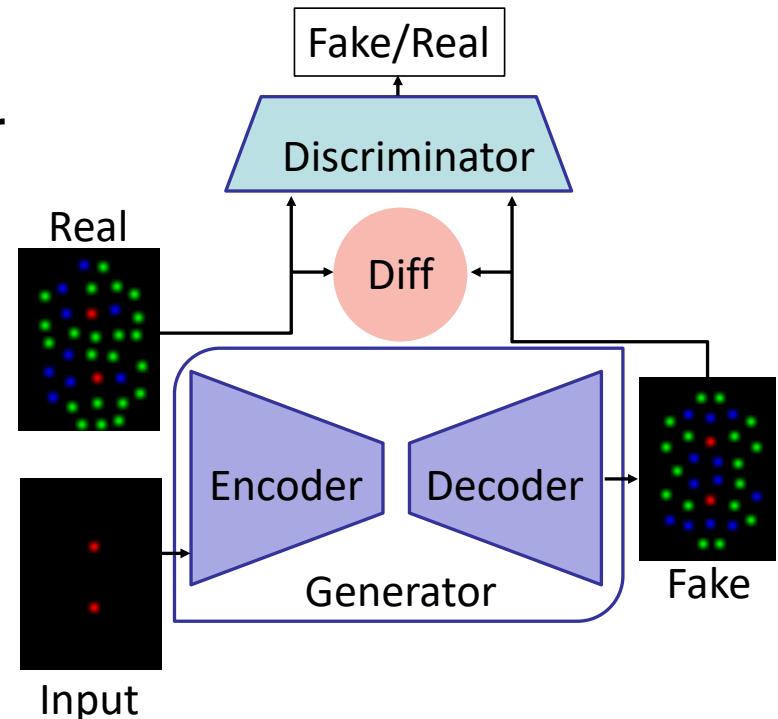
## Generator:

- Trained to produce images in  $D_s$  based on input from  $D_T$
- Tries to fool the Discriminator

## Discriminator:

- Trained to detect ‘fakes’ generated by the Generator

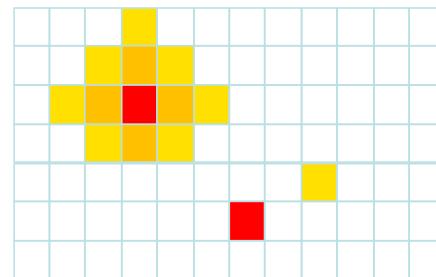
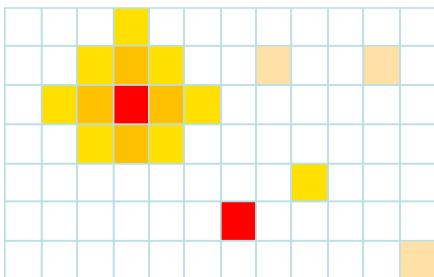
The two networks are jointly trained until convergence



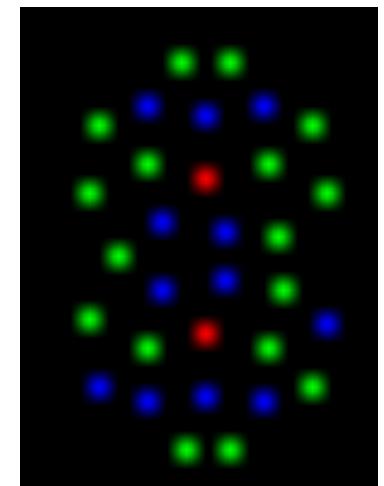
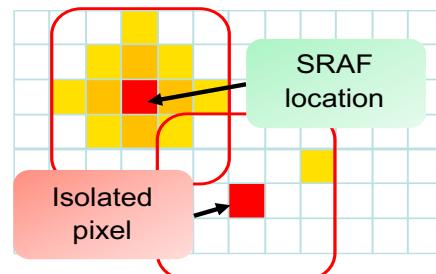
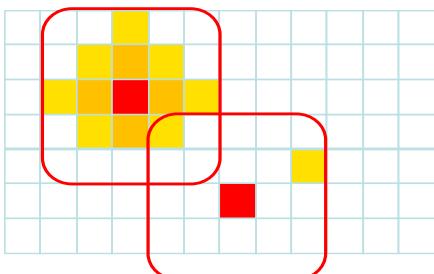
# Results Decoding

Decoding the generated layout images in two steps

- Thresholding
- Excitation detection

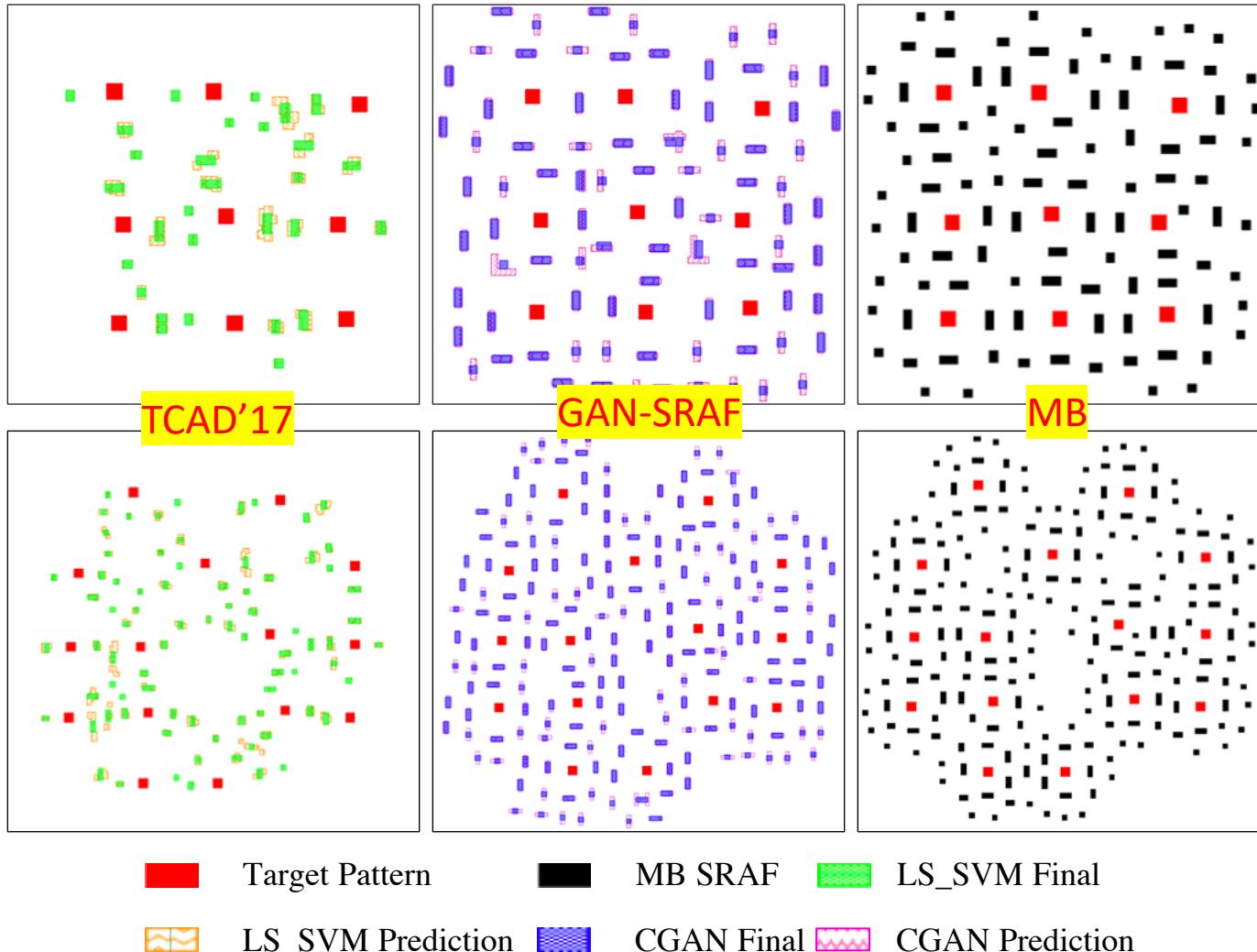


**Decoding scheme is fast → GPU accelerated**



# Sample Results

TCAD'17: [Xu+, ISPD'16, TCAD'17], SVM-based  
MB: Model-Based Approach - Calibre

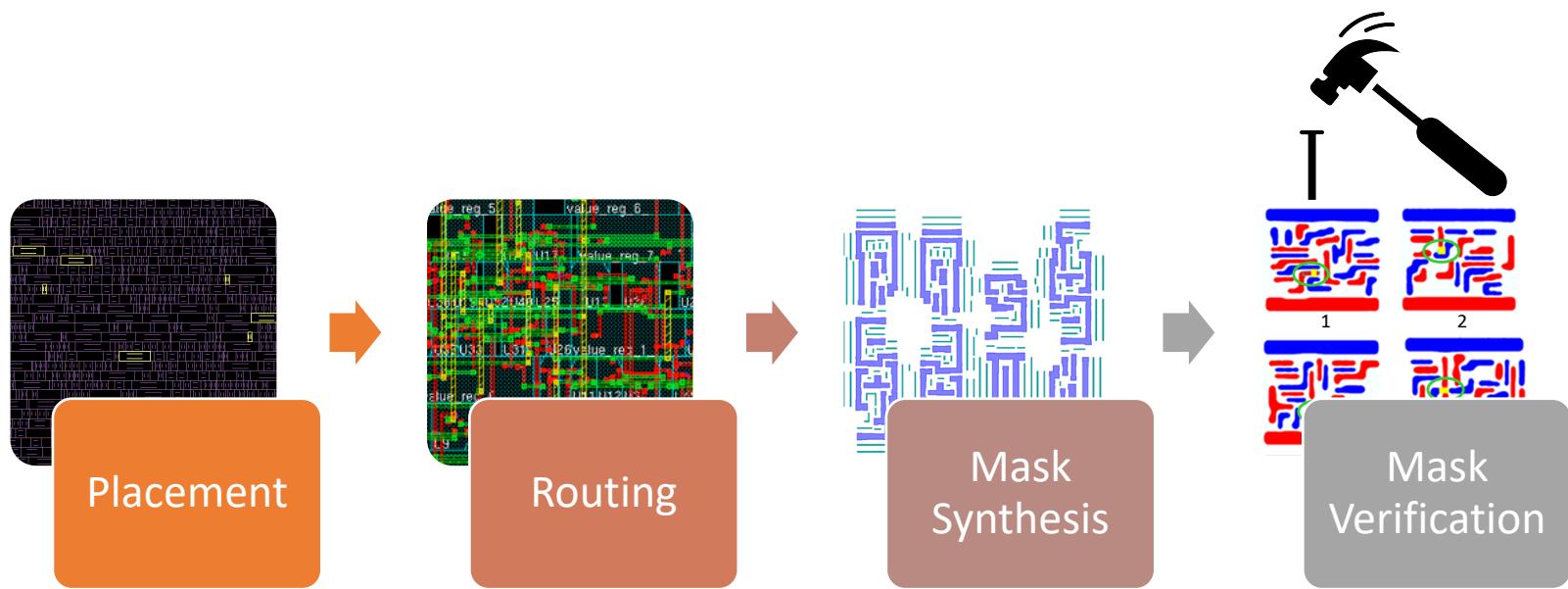


# Comparison Summary

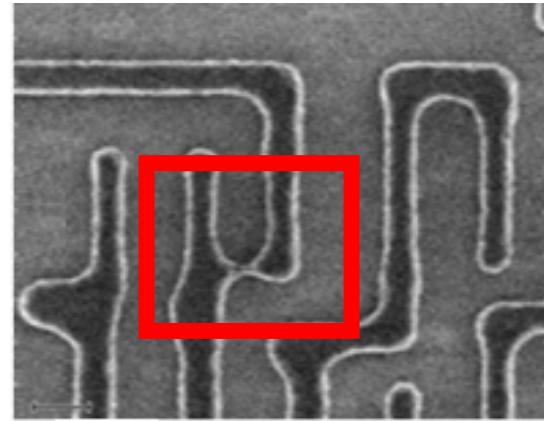
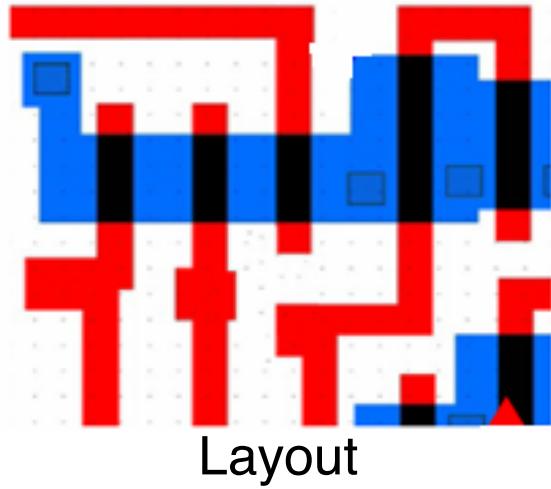
	No SRAF	MB	TCAD'17	CGAN
PV Band ( $\mu\text{m}^2$ )	0.00335	0.002845	0.00301	0.00291
EPE (nm)	3.9287	0.5270	0.5066	0.541
Run time (s)	-	6910	700	48

- The proposed CGAN based approach can achieve comparable results with TCAD'17 and MB with **14.6X** and **144X** reduction in runtime

# Mask Verification



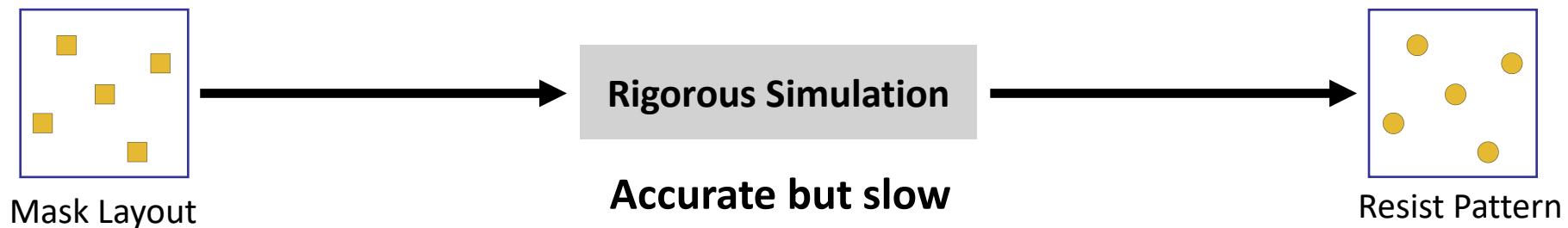
# Bottleneck in Semiconductor and IC Manufacturing: Lithography



- Lithographic modeling and hotspot detection
  - What you see (at design) is NOT what you get (at fab)
  - Hotspot → poor performance and yield
- Litho-simulations are extremely CPU intensive
  - Need much faster algorithms to guide IC design, and pinpoint possible mask/wafer inspection spots

# Challenges in Lithography Modeling

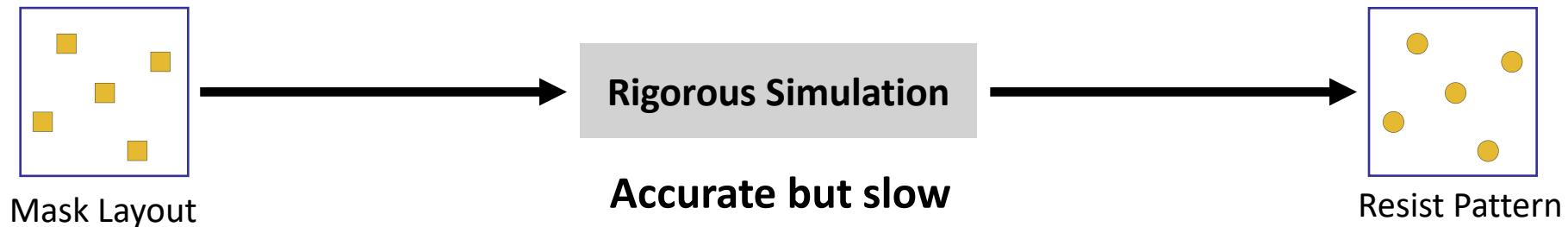
Rigorous simulation: physics-based simulation, e.g., Synopsys S-Litho



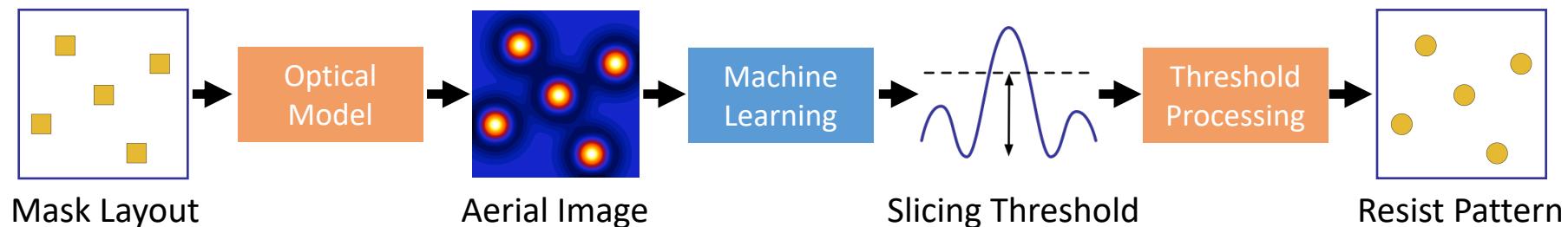
- Simulating  $2 \mu\text{m} \times 2 \mu\text{m}$  using Synopsys S-Litho  $\Rightarrow \sim 1$  minute
- A  $2 \text{ mm} \times 2 \text{ mm}$  chip contains 1M such clips  $\Rightarrow 1.9$  years!
- Intel Ivy Bridge 4C:  $160 \text{ mm}^2$

# ML for Lithography Modeling

Rigorous simulation: physics-based simulation, e.g., Synopsys S-Litho

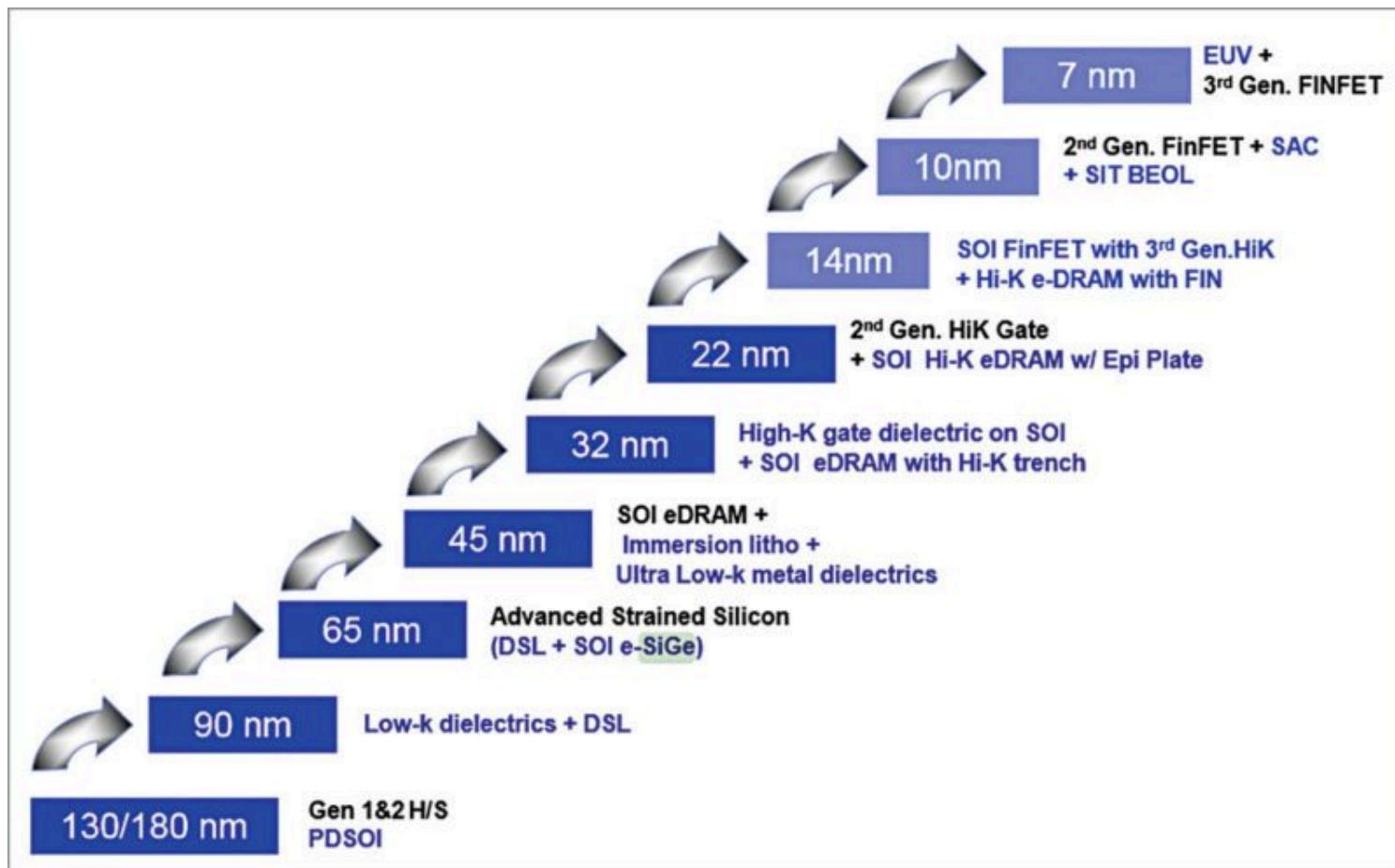


Machine learning for resist modeling [Watanabe+, SPIE'17] [Shim+, SPIE'17]



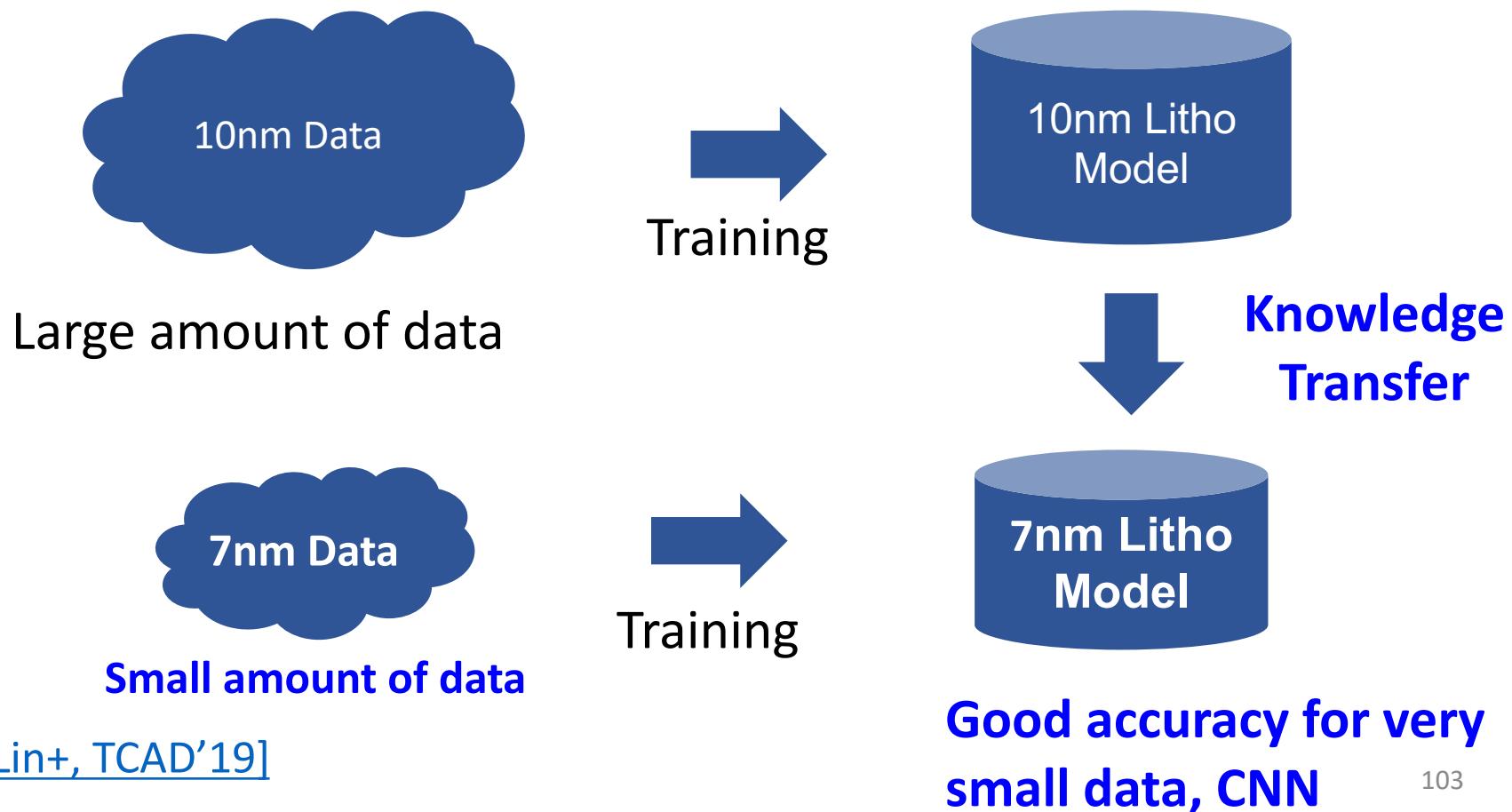
Speeds up the resist modeling stage

# VLSI Technology Nodes



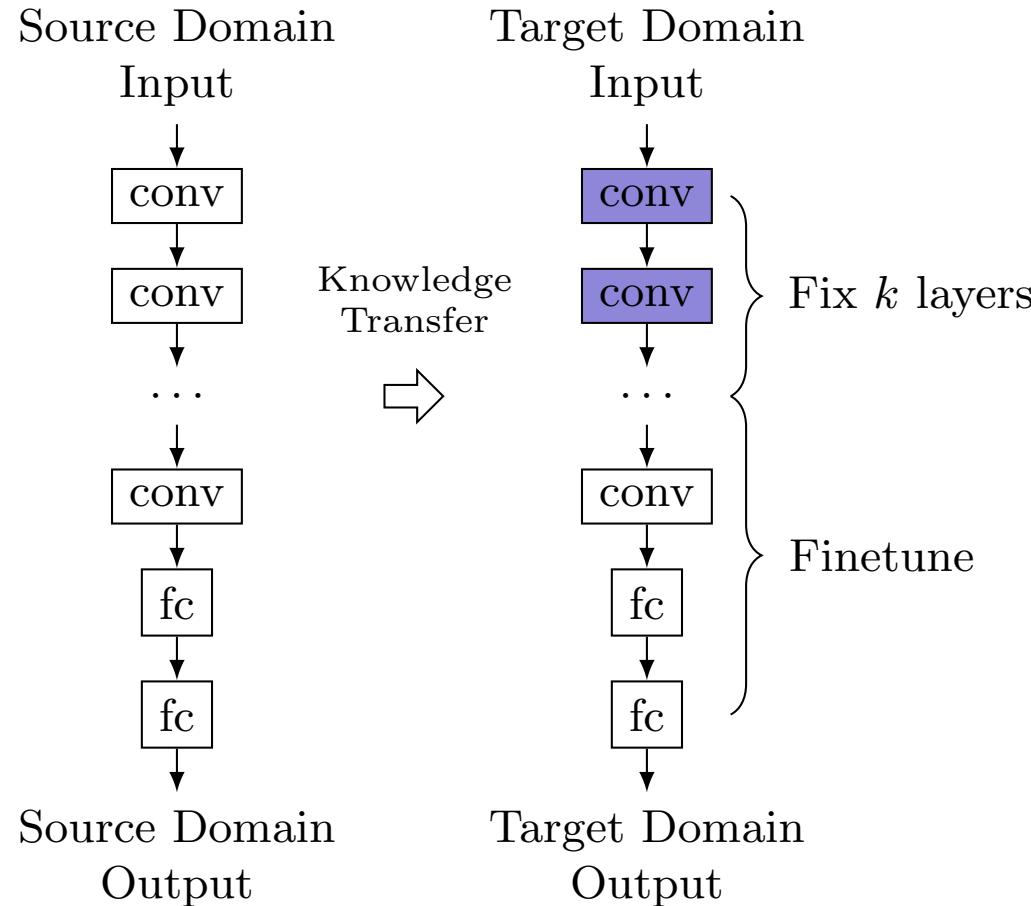
# Transfer Learning for Lithography Modeling

Training with limited new tech. data + older tech.



# Transfer Learning with ResNet

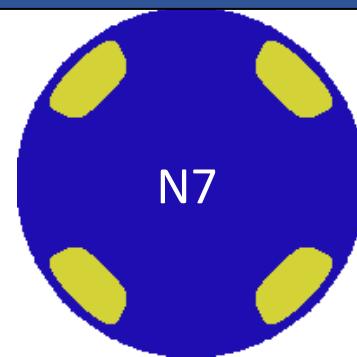
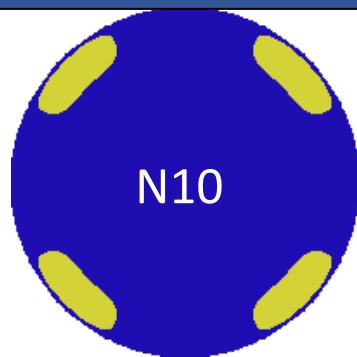
## Transfer and Fix $\text{TF}_k$ Scheme



# Technology Transition from N10 to N7

Contact Layer Design Rules [Liebmann, SPIE'15]		
	N10	N7
Patterning	L E L E	L E L E L E

	N10	N7 <sub>a</sub>	N7 <sub>b</sub>
Design Rule	A	B	B
Optical Source	A	B	B
Resist Material	A	A	B



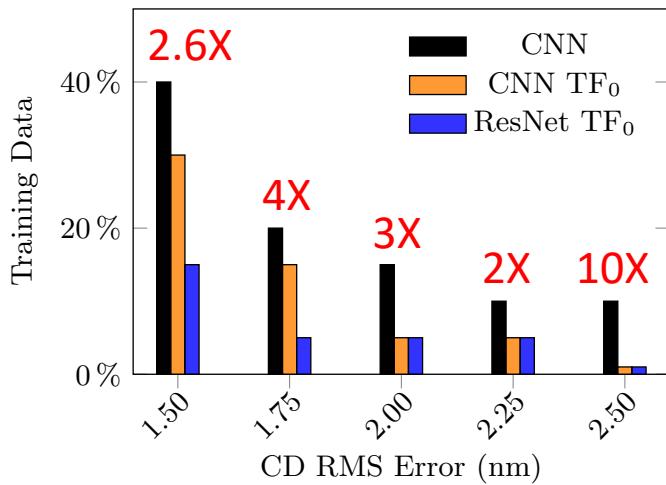
Resist A

Resist B

Different dissolution slopes 105

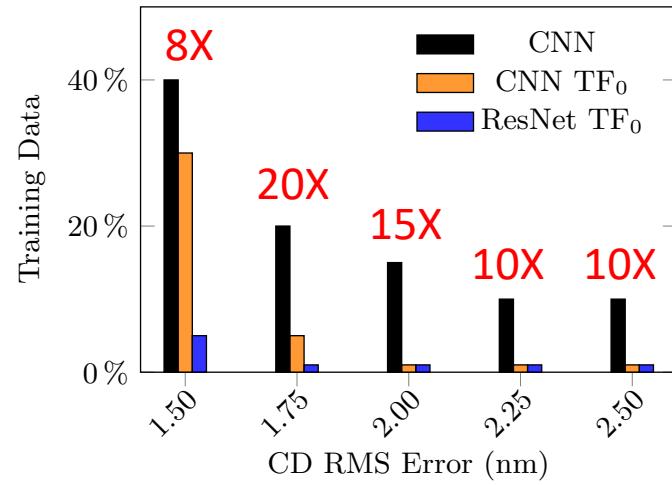
# Data Reduction from Knowledge Transfer

From N10 to N7<sub>b</sub>



2~10X reduction of  
training data

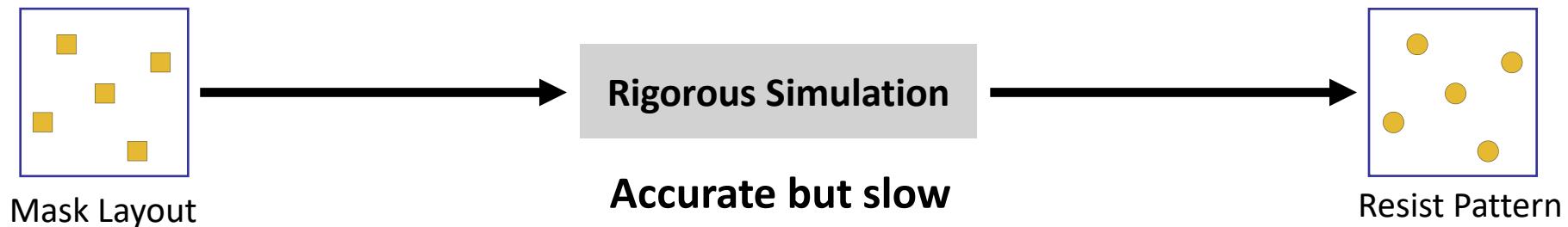
From N7<sub>a</sub> to N7<sub>b</sub>



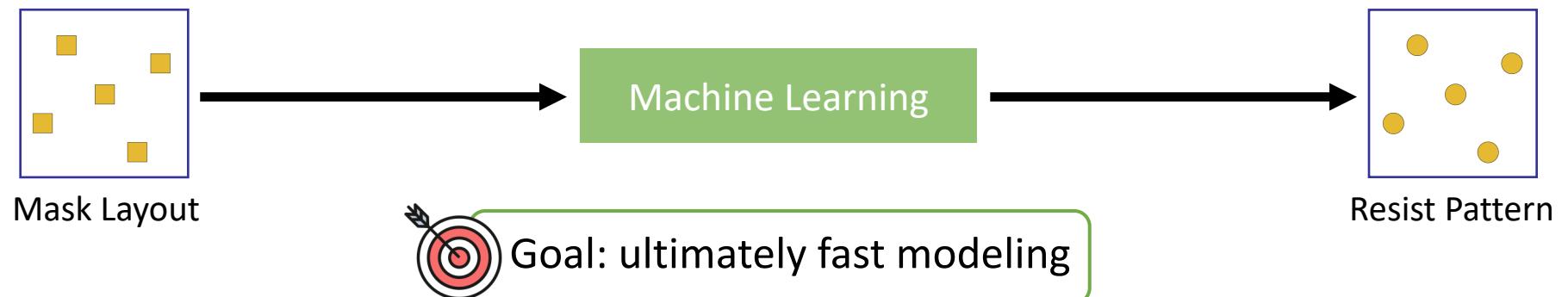
8~20X reduction of  
training data

# End-to-End Lithography Modeling

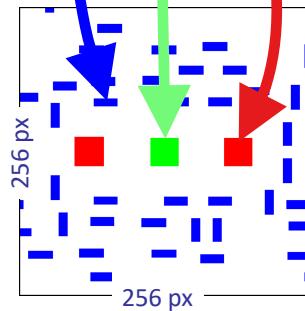
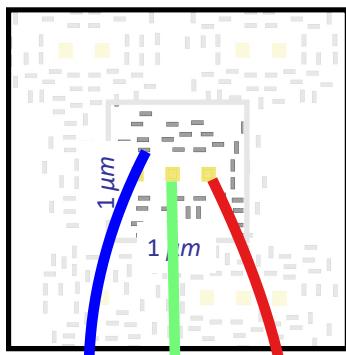
Rigorous simulation: physics-based simulation, e.g., Synopsys S-Litho



Machine learning for end-to-end lithography modeling



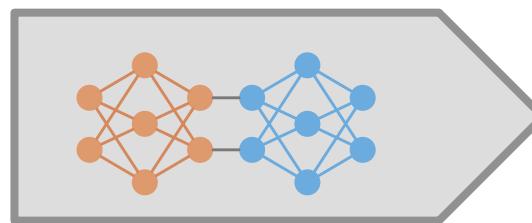
# Image Translation for Lithography Modeling



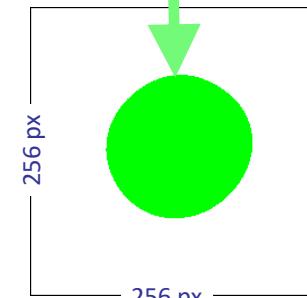
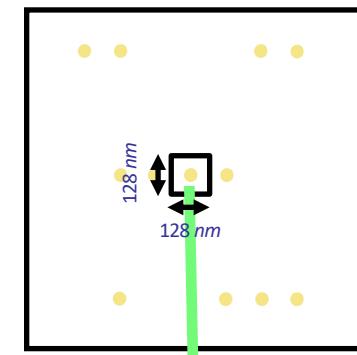
Different elements encoded  
on different image channels



Expensive Litho Simulation

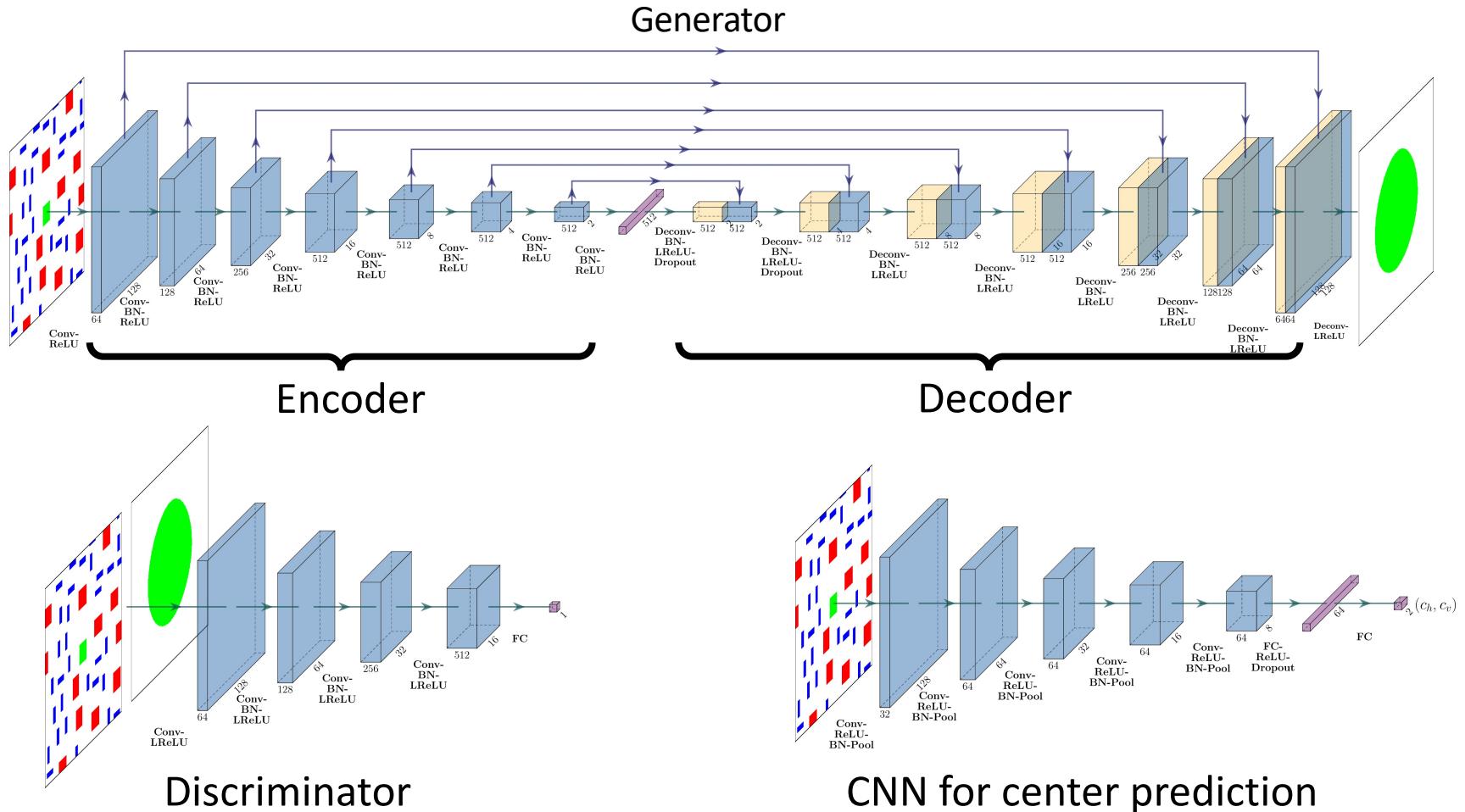


Fast Image Translation

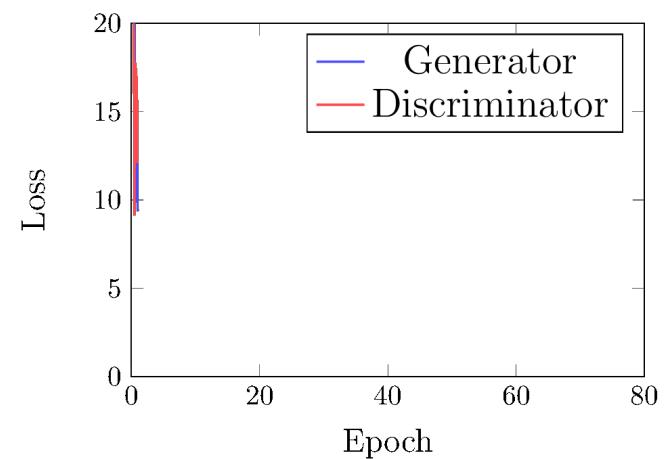
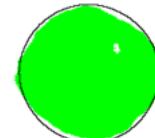
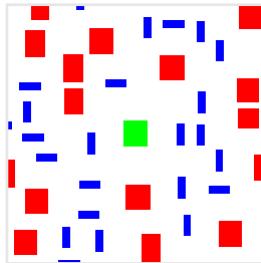
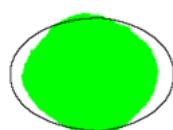
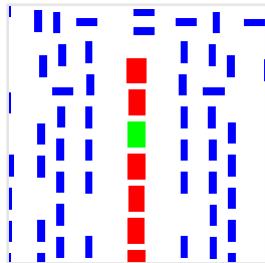
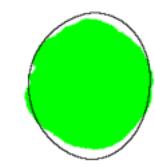
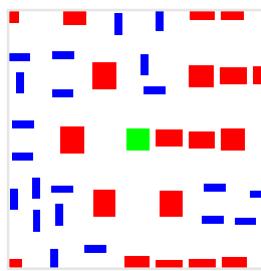
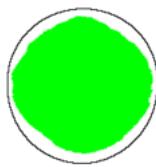
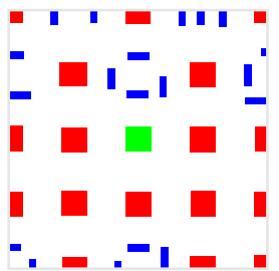


Resist pattern zoomed in for  
high-resolution/accuracy

# LithoGAN Architecture



# LithoGAN Visualization



Model advancement progress

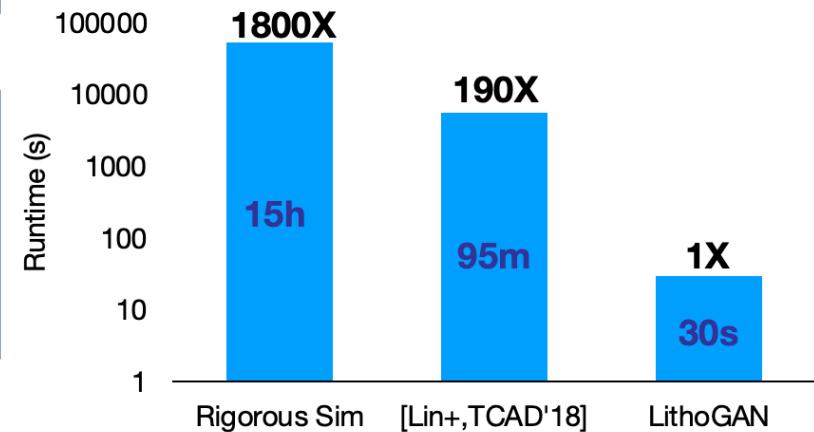
# Experimental Results

## Setup

- Python w/ TensorFlow
- 3.3GHz Intel i9 CPU & Nvidia TITAN Xp GPU

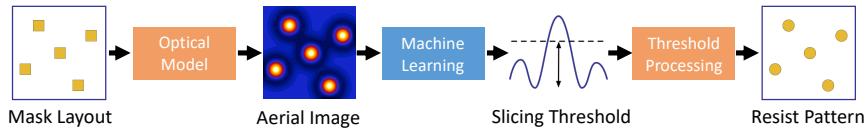
## Datasets

- Different types of contact arrays [\[Lin+, TCAD'18\]](#)
  - 982 mask clips at 10nm node (N10)
  - 979 mask clips at 7nm node (N7)
- 75-25 rule for train/test split



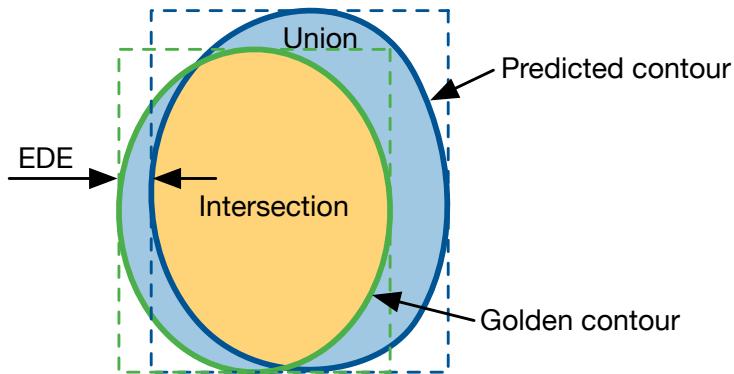
## Methods

- Rigorous sim using S-Litho: golden resist patterns
- [\[Lin+, TCAD'18\]](#): Optical sim using Calibre + threshold prediction using CNN + post processing



**Compelling runtime speedup for early technology exploration**

# Experimental Results



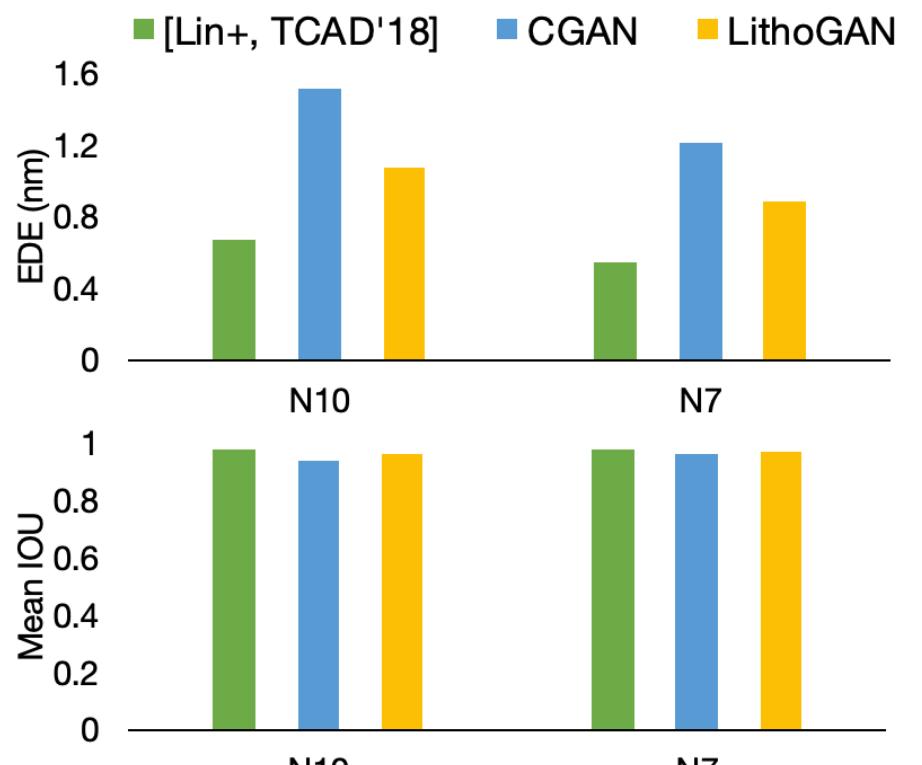
## Accuracy measures

### Edge Displacement Error (EDE)

- Distance between the golden edge and the predicted one of the bounding boxes
- The **smaller**, the **better**
- Captures bounding box mismatch

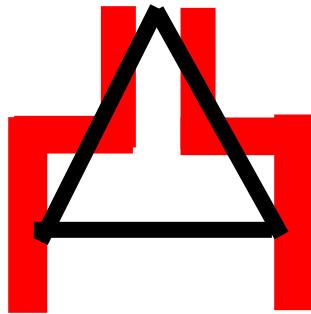
### IOU = Intersection/Union

- The **larger**, the **better**
- Captures contour mismatch



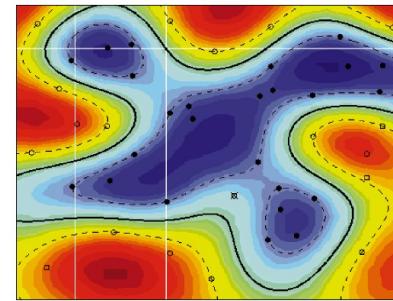
Competent accuracy for lithography usage  
(in consultation with industry)

# Lithography Hotspot Detection



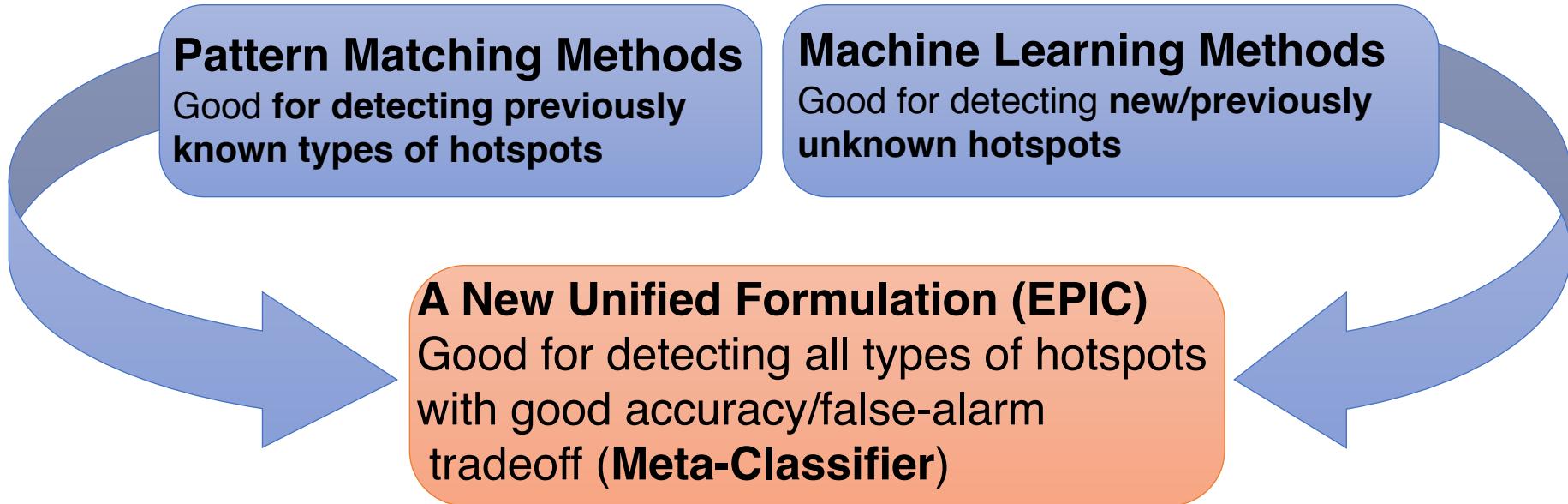
## Pattern/Graph Matching

- Pros/cons
  - Accurate and fast for known patterns
  - But too many possible patterns to enumerate
  - Sensitive to changing manufacturing conditions
- Pros/cons
  - Good to detect unknown or unseen hotspots
  - Trade-off accuracy and false alarms
  - Accuracy may not be good for “seen” patterns



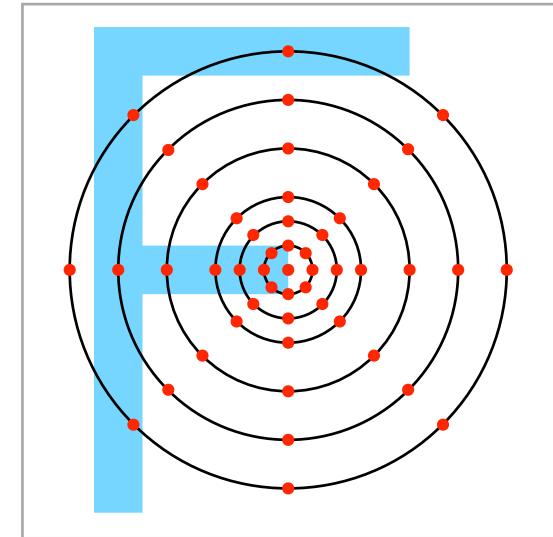
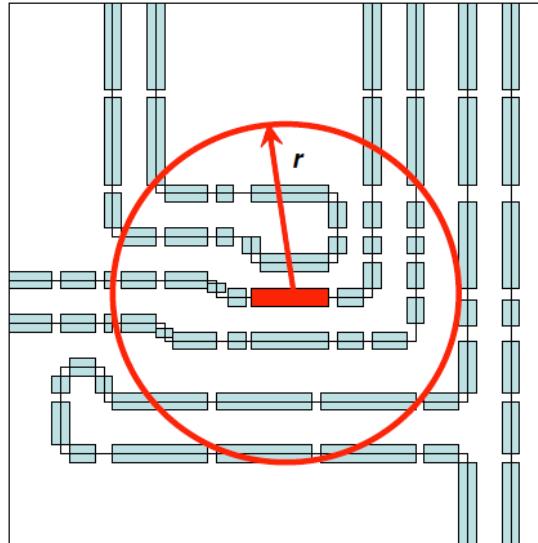
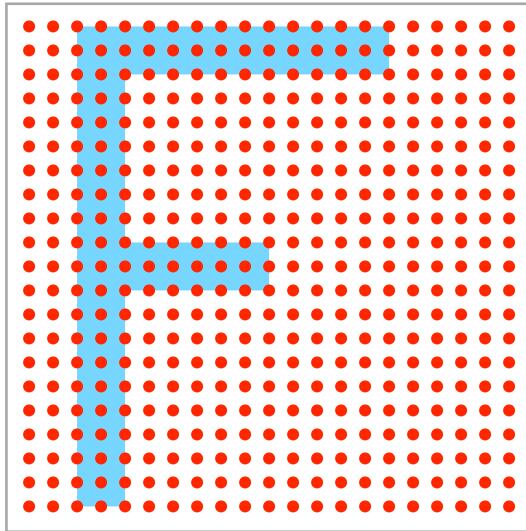
## Data Mining/ML

# PM & ML for Hotspot Detection

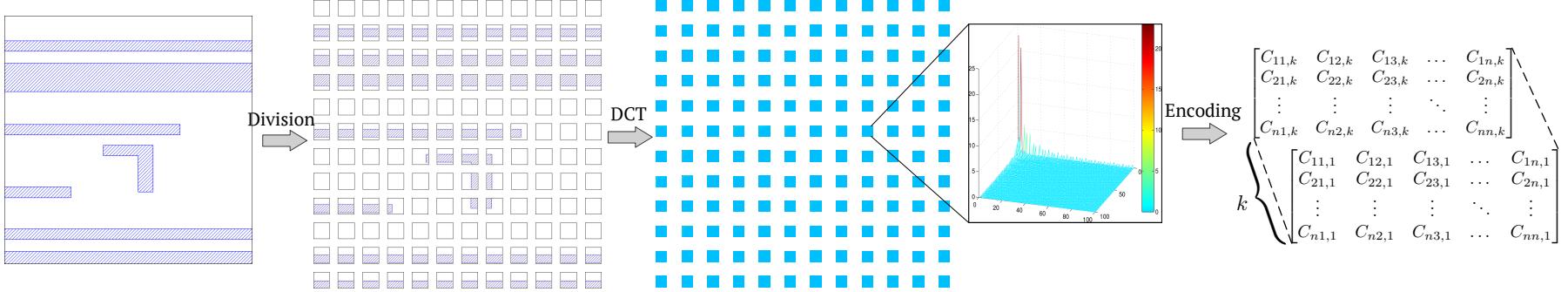


- Meta-classification combines the strength of different hotspot detection techniques [Ding+, ASPDAC'12]
- Balance accuracy and false-alarm

# Application-Specific ML



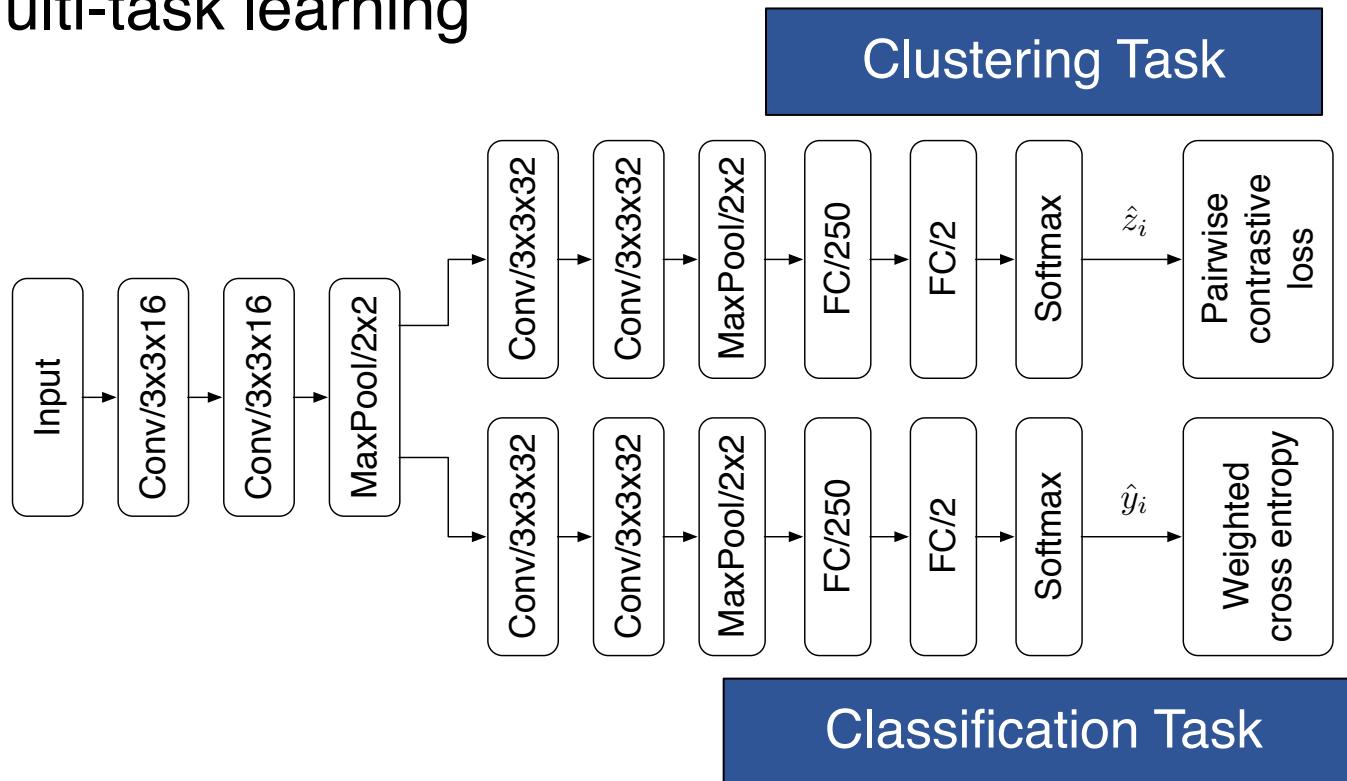
Different ways of feature extractions/representations



Deep learning: CNN, ... [[Yang+, TCAD'19](#)]

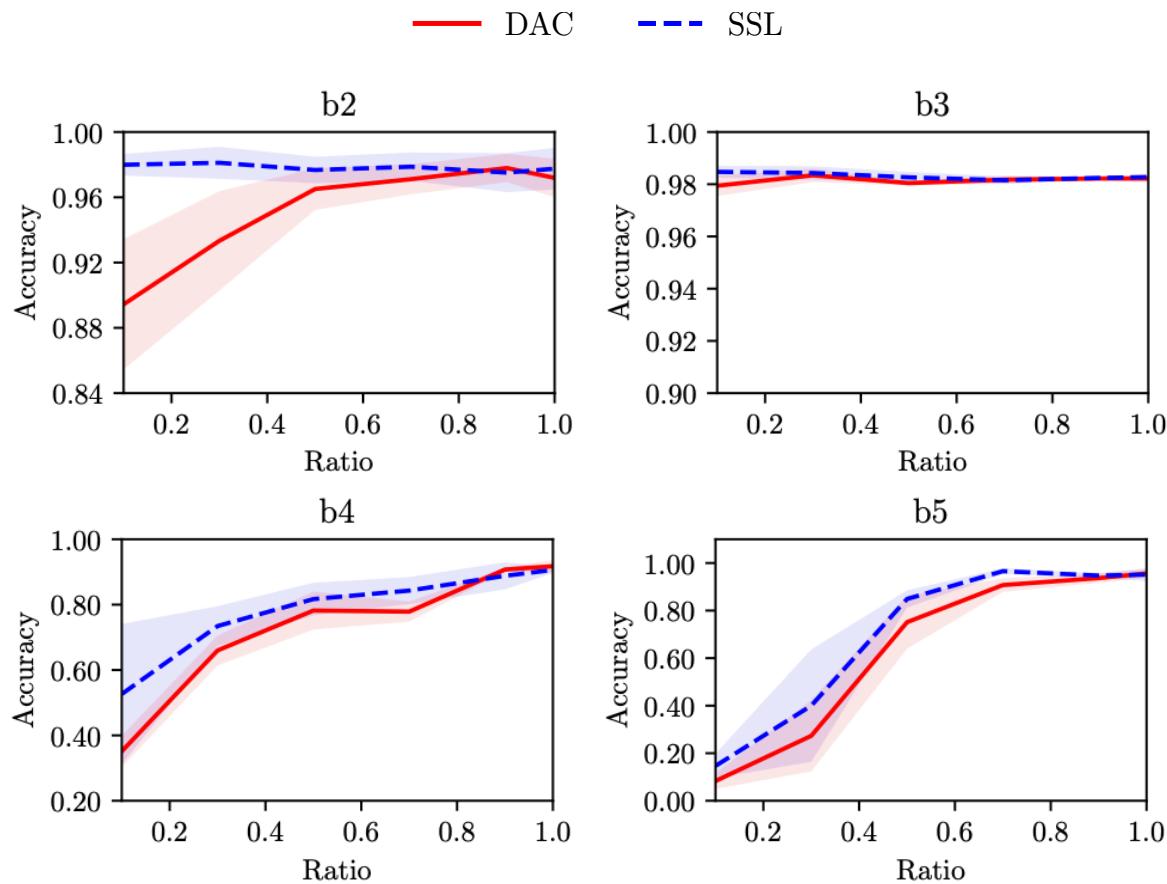
# Recent Progress – Lack of Data

- Self-paced semi-supervised learning
  - [\[Chen+, ASPDAC'19\]](#)
  - Leverage unlabeled data
  - Multi-task learning



# Preliminary Results [Chen+, ASPDAC'19]

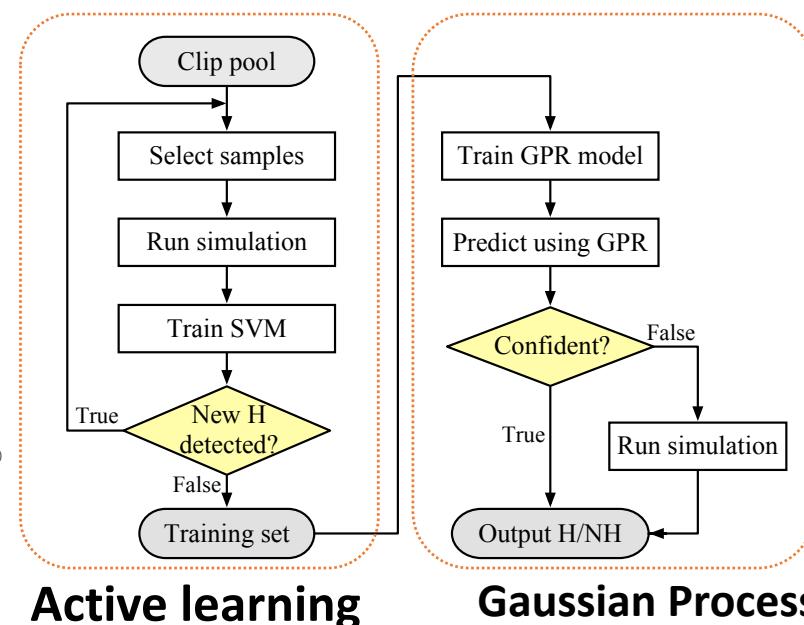
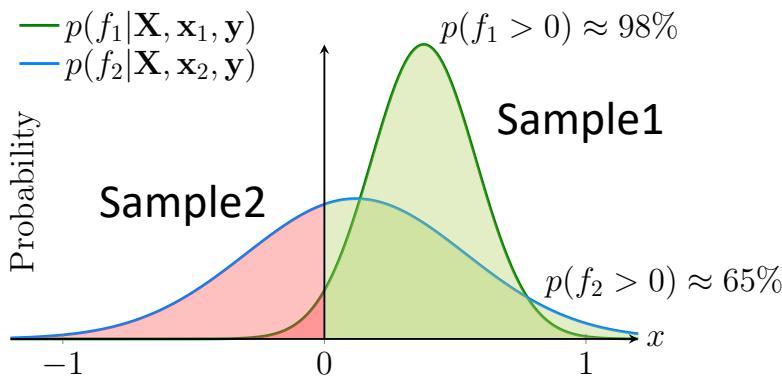
Better accuracy with small amount of training data



# Recent Progress: Model Confidence

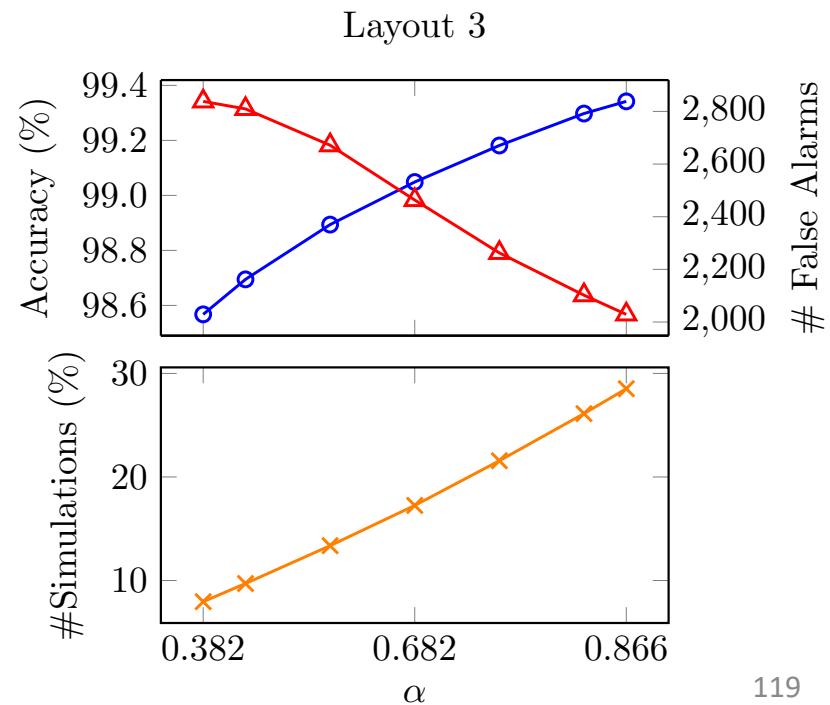
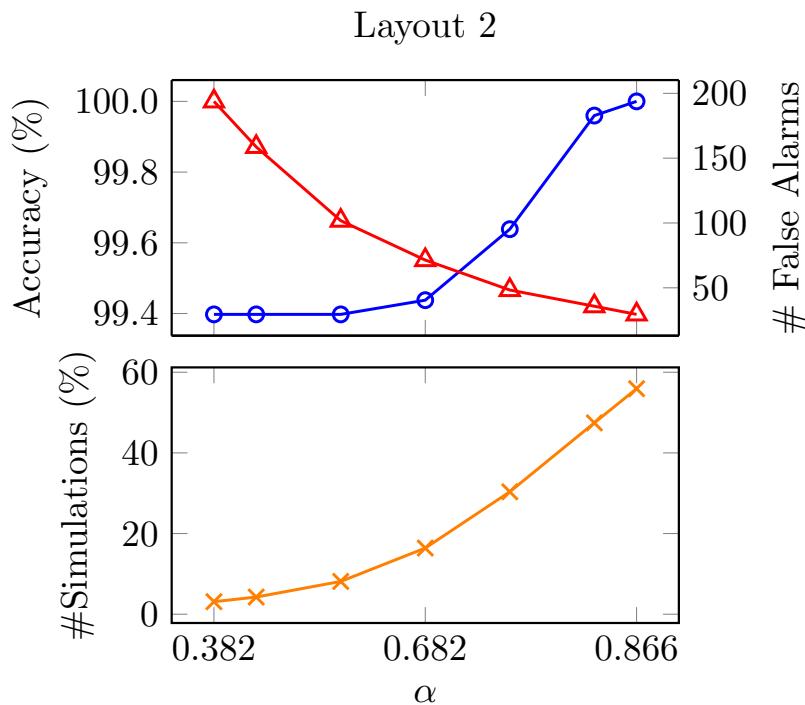
Examine confidence of model predictions

- [Ye+, DATE'19]
- Gaussian Process provides confidence level
- Active learning: build accurate GP model with little data
- Use GP model: simulate unconfident samples

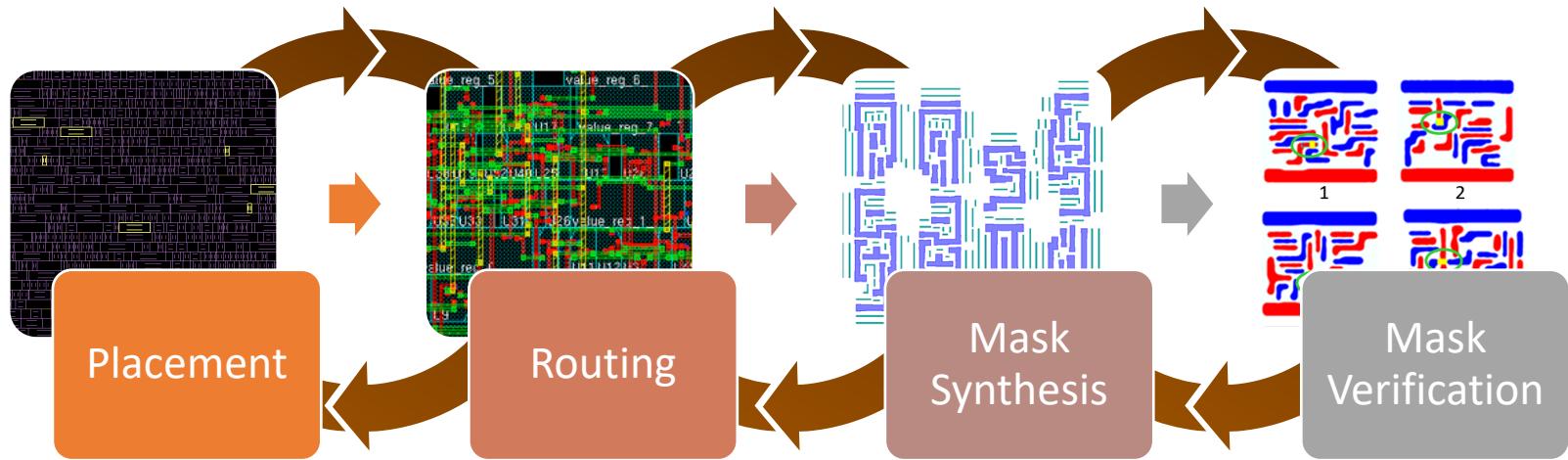


# Preliminary Results [Ye+, DATE'19]

- Larger  $\alpha$  implies a large confidence interval
  - $[\mu - \alpha\sigma, \mu + \alpha\sigma]$
- Trade-off: quality and #simulations required

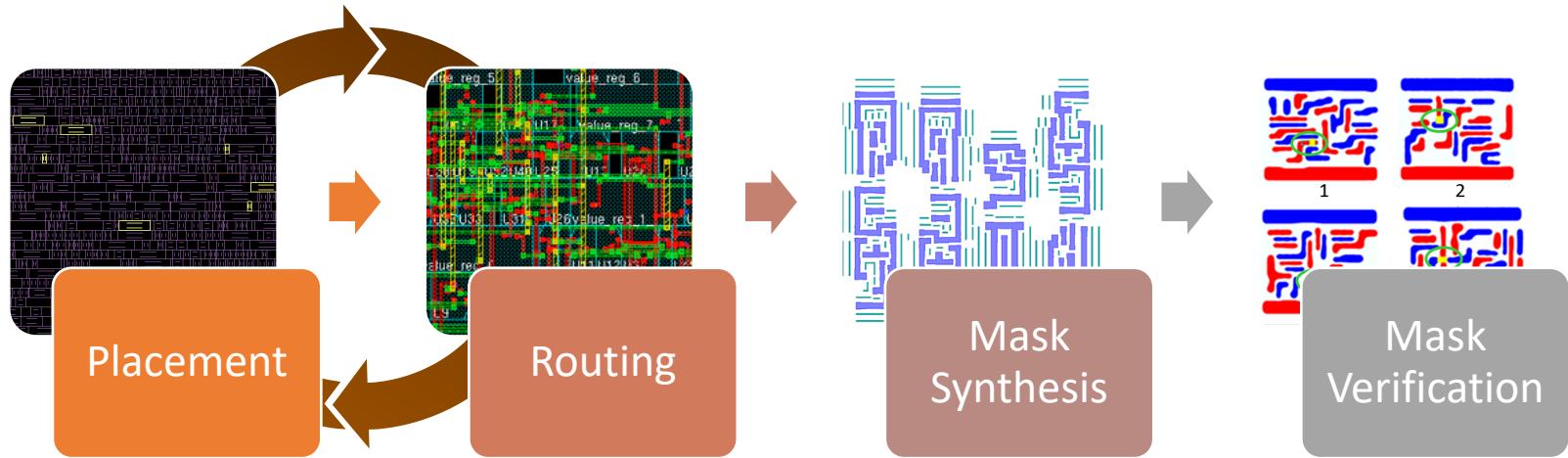


# How Machine Learning Can Help



Bridges to connect each step

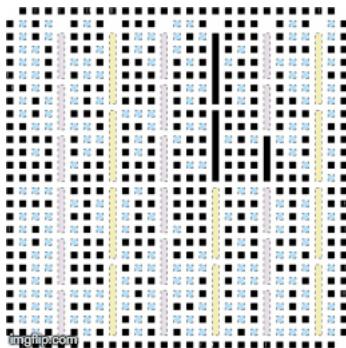
# Bridge Placement and Routing



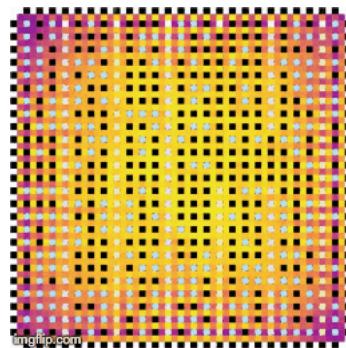
# Predicting Routing Congestion

Given placement, predict

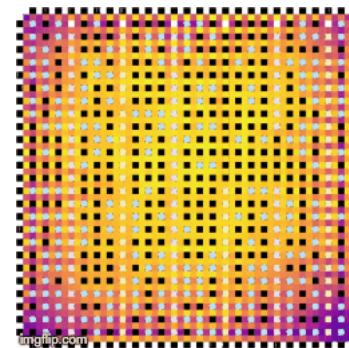
- Routing utilization map [\[Yu+, DAC'19\]](#) for FPGA
- DRC hotspots [\[Chan+, ISPD'17\]](#) [\[Xie+, ICCAD'18\]](#) for ASIC



Input FPGA Placement



Output Routing Util



Ground Truth

[https://ycunxi.github.io/cunxiyu/dac19\\_demo.html](https://ycunxi.github.io/cunxiyu/dac19_demo.html)

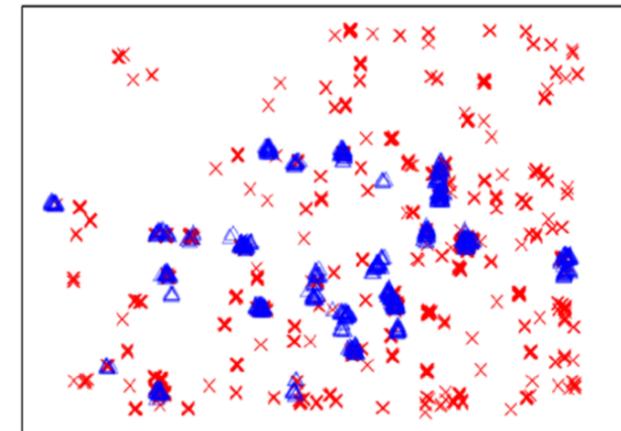
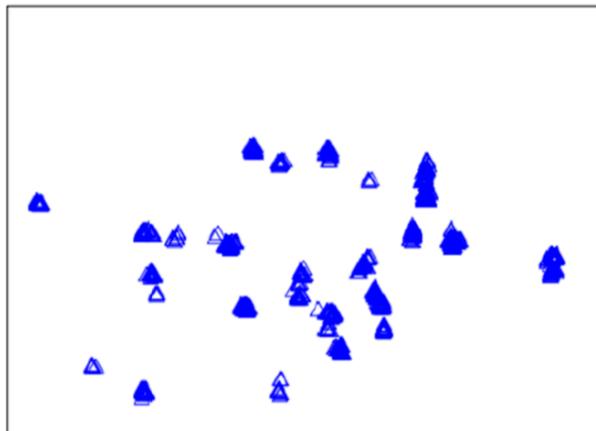
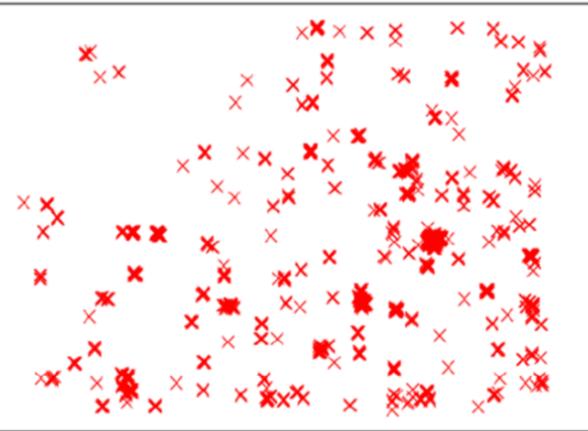
# Predicting Routing Congestion

Given placement, predict

- Routing utilization map [\[Yu+, DAC'19\]](#) for FPGA
- DRC hotspots [\[Chan+, ISPD'17\]](#) [\[Xie+, ICCAD'18\]](#) for ASIC

✗ GR Overflows

△ Actual DRVs



[\[Chan+, ISPD'17\]](#)

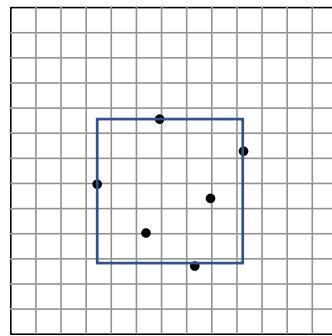
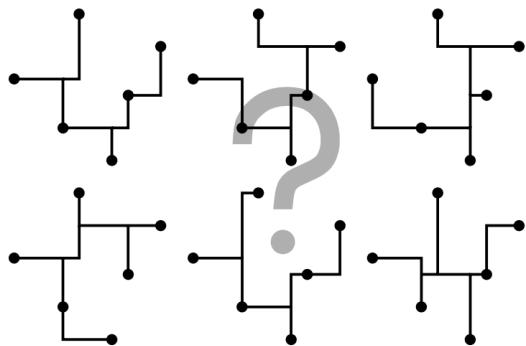
# Challenges in Predicting Congestion

## Feature representation

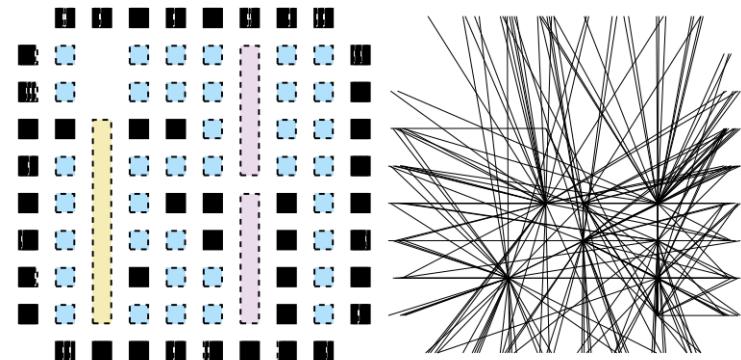
- How to encode interconnect information
- Scalability of features

## Model selection

- SVM, ANN, FCN, GAN, etc.



Different possibility of routing trees [\[Spindler+, DATE'07\]](#)  
Evenly distribute routing demands (RUDY map)



Connectivity images  
[\[Yu+, DAC'19\]](#)

# Integrate Models into Placement

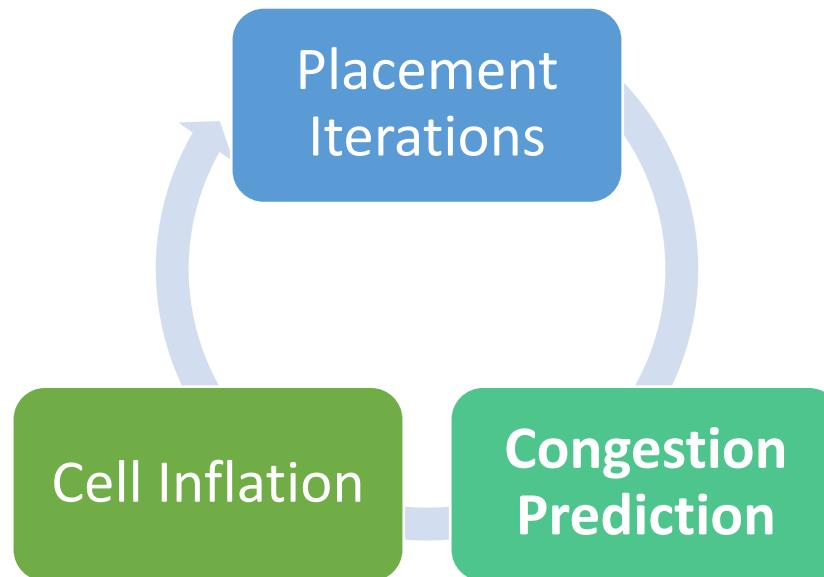
- Up to 76.8% DRC reduction
- Minor WL and timing impacts

[\[Chan+, ISPD'17\]](#)

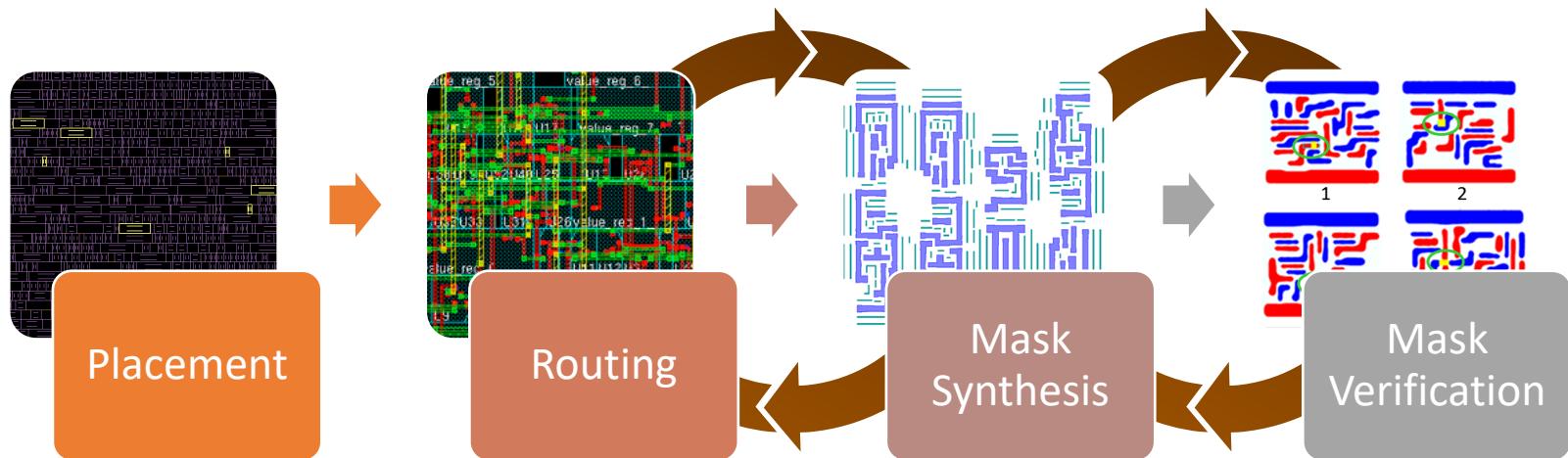
	#DRCs			Wirelength			TNS (ns)		
eg1	8478	1964	-76.83%	1742804	1747685	0.3%	-153.43	-158.4	3.2%
eg2	1502	927	-38.28%	1750698	1753047	0.1%	-168.23	-163.5	-2.8%
eg3	2017	1819	-9.82%	1772889	1773701	0.0%	-215.75	-213.6	-1.0%
eg4	2026	1780	-12.14%	1735185	1735227	0.0%	-151.36	-149.6	-1.2%
eg5	4252	4255	0.07%	1831492	1836060	0.2%	-264.34	-275.6	4.3%
eg6	3440	3891	13.11%	1790059	1794184	0.2%	-195.65	-203.5	4.0%
	avg		-20.6%	avg		0.2%	avg		1.1%
	max		13.1%	max		0.3%	max		4.3%
	min		<b>-76.8%</b>	min		0.0%	min		-2.8%

# Integrate Models into Placement

- Recent study from [UTDA](#)
- On 2016 ISPD FPGA Placement contest benchmarks
- Up to 7% reduction in routed wirelength

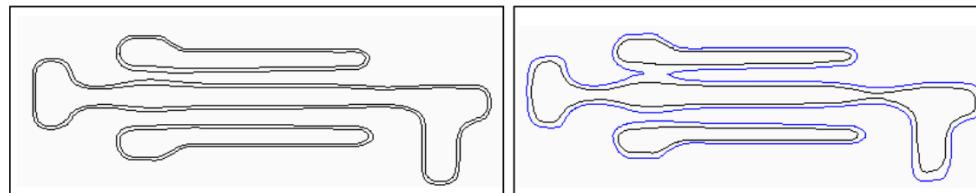


# Bridge Design and Manufacturing

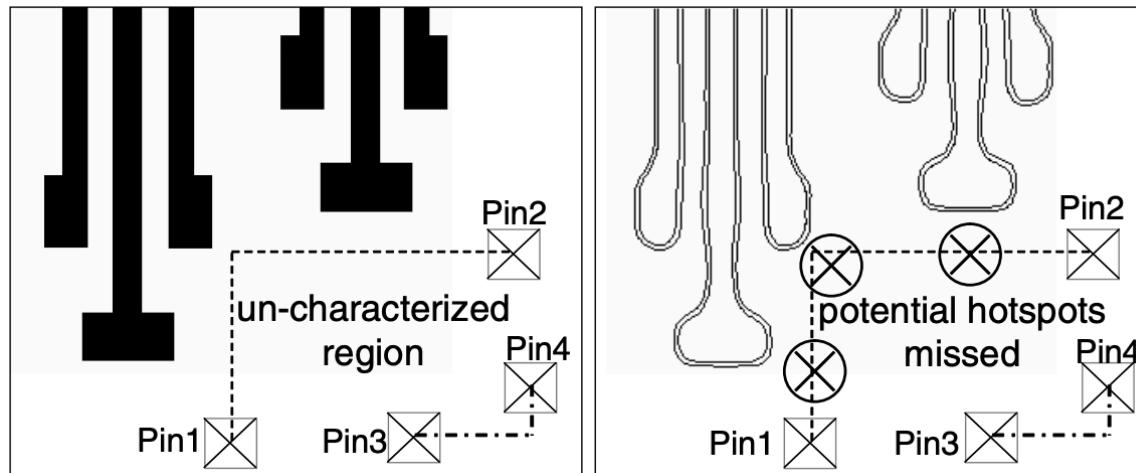


# Lithography-Friendly Detailed Router: AENEID

- Motivation: avoid RET dependent layout printability



- Challenges: the lithography hotspot detection dilemma in the detailed routing stage

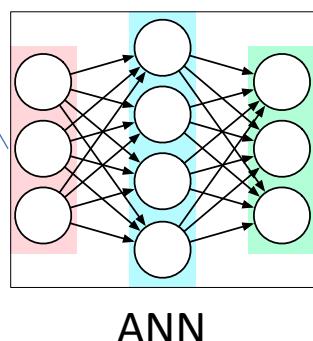


[Ding+, DAC'11]

# Lithography-Friendly Detailed Router: AENEID

- Objective: minimize total wirelength
- Subject to: keep lithography cost on each routing grid within a threshold

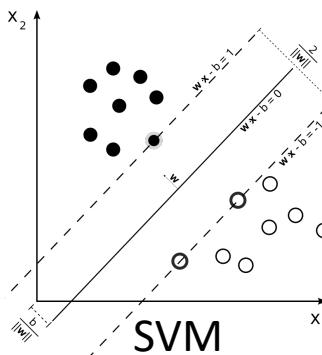
$$\begin{aligned} \min_P \quad & \sum_{e \in P} 1, \\ \text{s.t.} \quad & \underline{litho}(e) \leq L, \quad \forall e \in P \end{aligned}$$



Lagrangian  
relaxation



$$\begin{aligned} \max_\lambda \min_P \quad & \sum_{e \in P} 1 + \lambda_e (\underline{litho}(e) - L), \\ \text{s.t.} \quad & \lambda_e \geq 0 \end{aligned}$$



50% reduction  
in hotspots

# Conclusion

- Machine learning brings
  - New modeling opportunities
  - New optimization techniques
  - New hardware acceleration, e.g., GPU acceleration
  - New software platforms, e.g., Tensorflow, PyTorch
- Hammers and bridges for conventional EDA flow
  - Reformulate the problems, e.g., neural network training, image-to-image translation
  - Accurate and efficient information feedback from late stages to early stages

# Open Problems

- Connectivity feature representation
  - How to encode hypergraph as input to models
  - Or develop models that are friendly to ultra-large graphs
- Optimization-friendly ML models and ML-friendly optimization techniques
  - Target at integrating ML models into optimization
  - Need to consider fidelity, smoothness, accuracy, convergence rate
- Generalization guarantee
  - How far can ML models generalize
  - How to know whether a model is applicable to new data

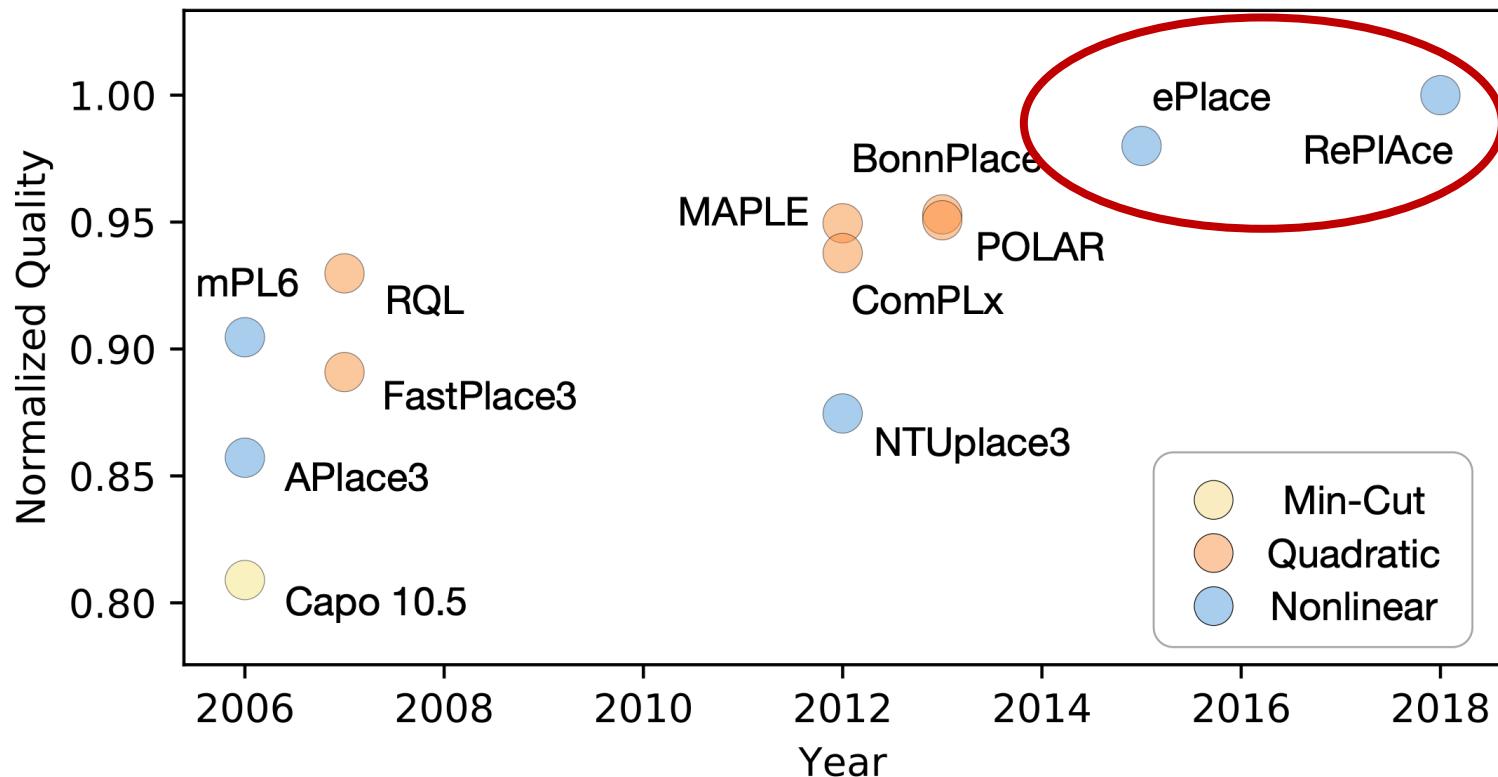
# Future Directions

- Routability & Timing-driven DREAMPlace with deep learning toolkits and GPU acceleration
  - Integrate ML models for routability and timing prediction
- Reinforcement learning for routing strategies
  - Rip-up and re-route policy
  - Tree topology generation
- End-to-end mask synthesis and verification
  - Use LithoGAN to guide SRAF and OPC
  - No need to generate golden SRAF and OPC solutions
- Open discussions...

Q&A

*Thanks*

# Recent Development of Placement



\*Data collected from RePIAce [TCAD'18, Cheng+] and <http://vlsi-cuda.ucsd.edu/~ljw/ePlace/> on ISPD 2005 benchmarks

# Future Directions

